

CONTROL DATA®
94200
CORE MEMORY

GENERAL DESCRIPTION APPLICATION SPECIFICATIONS THEORY OF OPERATION MAINTENANCE DIAGRAMS PARTS DATA

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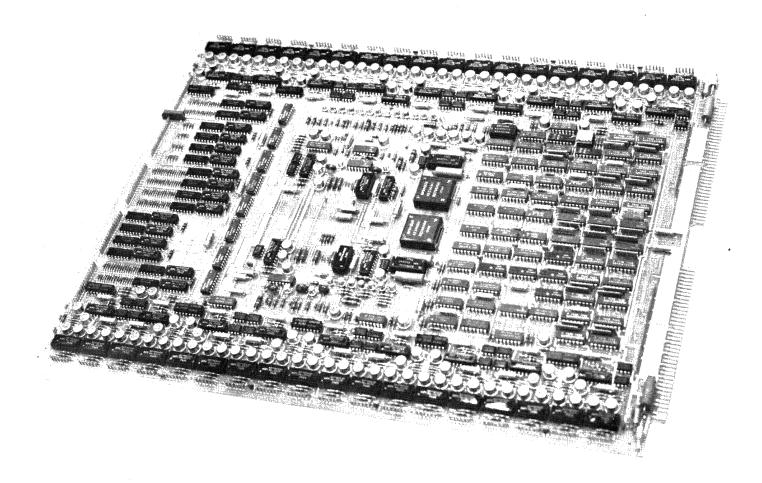
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CONTENTS

1.	GENERAL DESCRIPTION	1-1	Data Buffer	3-5
			Current Regulator	3-5
Intr	oduction	1-1	Current Source	3-5
Fun	ctional Description	1-1	Bridge Switch	3-5
	sical Description	1-1	X Read Switches and X Write Drivers, Y Read Drivers and Y Write Switches	3-5
			X Read Driver, X Write Switch,	
2.	APPLICATION SPECIFICATIONS	2-1	Y Write Driver, Y Read Switch	3-6
	.,		Inhibit	3-6
Pow	er Requirements	2-1	Sink Discharge	3-6
	ling and Environmental Requirements	2-1	Core Array	3-6
	ensions	2-1	Sense Amplifier and Data Register	3-8
			One-Bit Data Path	3-8
inte	rface Description	2-1		
	Logic Levels	2-1	4. MAINTENANCE	4-1
	Definitions	2-1		
	Input Signals	2-1	Introduction	4-1
	Output Signals	2-3	Recommended Test Equipment	4-1
	Options	2-4	Memory Tests	4-1
	Connector	2-4	All Ones	4-1
	Termination Requirements	2-4	All Zeros	4-1
	Bidirectional Data Lines	2-4	Worst Pattern and Worst Pattern	
		- -	Complement	4-1
	Timing Diagrams	2-5	Errors	4-1
	MILLODI OF ORDER A TA		Control Errors Address Errors	4-1 4-1
3.	THEORY OF OPERATION	3-1	Data Errors	4-1 4-2
			Data Effors	4-2
Intro	oduction	3-1	5. LOGIC AND COMPONENT	
Mod	ule Select	3-1	LOCATION DIAGRAMS	5-1
Add	ress Register	3-1	EGGIIION DIIIGIMIND	0 -
Tim	ing and Byte Register	3-1	Memory Electronics Logic Diagrams	5-1
	Control	3-1	Memory Electronics Component	-
	Byte Transfers, 16Kx36-Bit	0 -	Locations	5-54
	Configuration	3-5	Core Array Logic Diagrams	5-55
	Full-Word Transfers, 16Kx18-Bit	0 0	Core Array Component Locations	5-69
	Configuration	3-5	J	
	Byte Transfer, 32Kx18-Bit	0 0	6. PARTS LIST	6-1
	Configuration	3-5		
	Full-Word Transfer, 32Kx18-Bit			
	Configuration	3-5		
		A DDEAL	DIVEC	
		APPEN	DIXES	
Α.	ALPHABETICAL LISTING OF		B. INTERFACE CONNECTOR CHART	
	MEMORY MODULE MNEMONICS			
		FIGUI	RES	
2-1	Module Dimensions	2-2		
2-2	Connection of Modules for		3-2 Memory Cycle Timing,	
	External Current Control	2-4	Read Portion	3-3
2-3	Current Regulator Circuit	2-5	3-3 Memory Cycle Timing,	
2-4	94200 Line Terminations	2-6	Write Portion	3-4
2-5	Read Restore Timing	2-7	3-4 Core Drive Circuits	3-7
2-6	Read Modify Write Timing	2-7	3-5 X and Y Line Selection Example	3-8
2-7	Clear Write Timing(Word)	2-8	3-6 Bit 2 Data Path	3-9
2-8	Byte Write Timing	2-8	4-1 Control Errors	4-2
3-1	Module Block Diagram	3-2	4-2 Address Errors	4-3
			4-3 Data Errors	4-5
		TAB	LES	
3-1	Address and Drive		4-1 Relationship of Address Bits,	
-	Current Relationship	3-6	Circuits, and Logic Diagram	4-4

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THE 94200 CORE MEMORY MODULE

INTRODUCTION

The CONTROL DATA® 94200 Core Memory Module is a coincident current, magnetic core memory intended for use by original equipment manufacturers.

FUNCTIONAL DESCRIPTION

The 94200 memory module as shipped has a capacity of 16,384 36-bit words. However, the configuration can be changed to 32,768 18-bit words by external wiring changes. Minimum core cycle time is 850 nanoseconds. Up to eight modules may be used in one system.

The 94200 memory module has two basic operating modes called full cycle and split cycle. The module performs three operations in the full cycle mode. These operations are read restore, clear write, and byte control. During a read restore operation, data words are read out of the memory and restored back into memory without modification. A clear write operation writes data words into memory replacing any information in the memory. Nine bits of data can also read out or write into memory. The remaining bytes in the location recirculate during a byte write operation.

In the split cycle mode, the memory does a readmodify-write operation. This means that data is read from memory during the read portion of a cycle, and new data is written into memory during the write portion of a cycle. The write portion of the cycle does not occur until an external signal starts it.

The system with which the 94200 memory module is used must supply data, adddresses, and control signals.

PHYSICAL DESCRIPTION

The 94200 memory module consists of two 17-3/4 inch by 13-7/8 inch (45 by 35.2 centimeters) fiberglass printed circuit (PC) cards held together by screws and spacers. The module is 1 inch (2.54 centimeters) thick. The core memory occupies the area between the PC cards, and semiconductor and passive components fasten to the outside of the PC cards. Connectors molded into the PC cards provide circuit continuity between the cards. An 80-pin connector provides data, address, and control signals and power to the module. Maximum weight of the module is 6 pounds.

The logic is TTL in dual in-line packages. Voltages required are +5 volts, +15 volts, and -15 volts. Nominal power consumption is 120 watts operating and 35 watts standby. Forced-air cooling is required.

		,	

POWER REQUIREMENTS

Voltages:

Standby current:

Operating current:

+15 volts

0.12 ampere

0.75 ampere

+5 volts

4.5 amperes

6.4 amperes

(5.1 amperes)†

(7.0 amperes)†

-15 volts

0.55 ampere

6.5 amperes

Voltage regulation

±2 percent

Voltage margins

± 5 percent of nominal

COOLING AND ENVIRONMENTAL REQUIREMENTS

Cooling:

Forced air at a minimum of 40 cubic feet/minute

Operating temperature range:

0° C to 55° C

Nonoperating temperature range:

-40° C to 80° C

Operating humidity:

10 percent to 90 percent without condensation

DIMENSIONS

Figure 2-1 illustrates the module dimensions.

INTERFACE DESCRIPTION

LOGIC LEVELS

Logic 1 (high) in/out of memory:

+2.4 vdc to +5.5 vdc

Logic 0 (low) into memory:

0 vdc to 0.8 vdc

Logic 0 (low) out of memory:

0 vdc to 0.5 vdc

DEFINITIONS

Access Time:

The time between the appearance of the cycle initiate signal at the input terminals of the memory and the data signals being available at the output terminals of the memory. Maximum access time is 350 nanoseconds.

Byte:

A group of 9 data bits.

Cycle Time:

The time between memory request signals.

Full Cycle Clear Write:

The clear-write operation clears data at a specified address and writes new data present on the data in lines into the address.

Full Cycle Read-Restore:

The read-restore operation reads data from a specified address, puts the data on the data out lines, and restores the data into the same address.

Full Cycle Time:

The maximum time required to do a clear-write or read-restore into memory. Minimum full cycle time is 850 nanoseconds.

Read-Modify-Write:

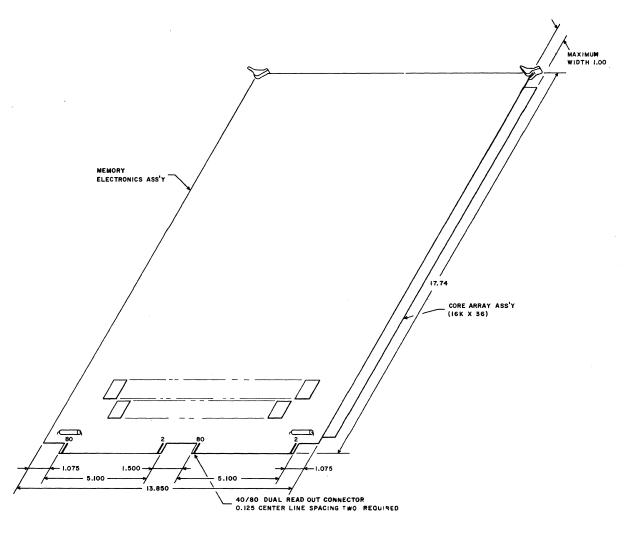
The read-modify-write operation provides modify time after the read portion of the memory cycle completes. The read portion of the memory cycle reads data from a specified address and puts the data on the data out lines. The module then remains quiescent until a write initiate input signal starts the write portion of the memory cycle. New data or the data read from memory is written into the specified address depending on the byte control inputs. Minimum split cycle time is 900 nanoseconds.

INPUT SIGNALS

The leading edge of the cycle initiate signal is defined as being \mathbf{t}_0 in the following input signal description. All timing measurements are made at the 1.5-volt level of the signal transition.

The load driving requirements indicated below are standard TTL loads and do not include termination load.

[†]Includes terminating resistor.



NOTES:
1. DIGITAL STACK MODULE MOUNTS ON 1.125 CENTERS.
2. ALL DIMENSIONS IN INCHES.

Figure 2-1. Module Dimensions

Address Lines (AD00 through AD13):

These lines select one of 16,384 36-bit word locations in memory. The leading edge of the address signal must be stable for a minimum of 100 nanoseconds after the leading edge of the $\overline{\text{CI}}$ signal. There are 14 address lines. Each address line drives one load.

Byte Control ($\overline{B0}$ through $\overline{B3}$):

These lines make possible transfers of 9-bit bytes of data. One or more of these lines being low causes corresponding bytes of data to write into memory upon receiving the cycle initiate (CI) signal. If one or more of these lines is high, 9-bit bytes of data read out of memory upon receiving the CI signal. If full word transfers are desired, these inputs should be left open and the word write (WW) input used. The byte control signals each drive one load. Refer to the byte timing description in the options subsection.

Cycle Initiate (\overline{CI}) :

This signal going low initiates a memory cycle. The leading edge of this signal is defined as t_0 . The signal must remain low for 100 nanoseconds and may remain low to a maximum of t_0 to 750 nanoseconds. The cycle initiate signal drives one load.

Data In (DI00 through DI35):

These lines transmit data into memory. Data must be stable to t_0 plus 150 nanoseconds during clear write cycles. During split cycles, data must be stable at the leading edge of write initiate ($\overline{\rm WI}$) and remain for 150 nanoseconds. Each data in line drives one load when the memory is wired for 36-bit words and 16,384 locations. If the memory is wired for 18-bit words and 32,768 locations, each data in line drives two loads.

Data Save (DS):

This line must be high for the memory to operate. Data save should be low during power up and power down to retain data. A memory cycle will not start if the data save signal goes low before $\overline{\text{CI}}$. If data save goes low during a memory cycle, that cycle completes, and the next cycle does not occur. The data save signal drives three loads.

Module Select (AD14 through AD16):

These inputs provide addressing which allows a system to reference up to eight memory modules. Each module has a manual switch in a dual in-line package. This switch is set to decode an address assigned to the module. Each line drives one load. In single module applications, the switch must be closed and inputs AD14, AD15, and AD16 left open.

Reset:

This signal being negative for 100 nanoseconds resets the memory logic if it is not cycling. This signal is only used if an illegal signal condition has caused the memory logic to hang up. Reset drives three loads.

Word Write (WW):

This signal allows full word data transfers. A read restore operation occurs when word write is high. If word write is low, a clear write operation occurs. If data transfer in 9-bit bytes is desired, the word write input should be left open and the byte control inputs used. Word write drives one load.

Write Initiate (WI):

This signal initiates the write portion of a read modify write operation. Write initiate may go negative at t_0 plus 450 nanoseconds or later, and remain for a minimum of 100 nanoseconds and maximum of 400 nanoseconds. The read portion of the cycle is complete at t_0 plus 450 nanoseconds. The write portion of memory requires 450 nanoseconds to complete. A read-modify-write operation requires a minimum of 900 nanoseconds when write initiate occurs at 450 nanoseconds. Write initiate drives one load.

OUTPUT SIGNALS

The leading edge of the cycle initiate signal (an input signal) is defined as being t_0 in the output signal descriptions that follow. All timing measurements are made at the 1.5 volts level of the signal transition.

Data Available (DA):

This signal going low indicates that data from memory is available when any one byte is in a read restore or read modify write cycle. This signal occurs at t_0 plus 350 nanoseconds and remains until t_0 plus 450 nanoseconds.

Data Out (D000 Through D035):

Data read from memory is available at the data out pins of the interface connector 350 nanoseconds after t_0 and remains until t_0 plus 800 nanoseconds for full cycle operation. For a read-modify-write, data is available 350 nanoseconds after t_0 and remains until approximately 30 nanoseconds after write initiate. There are 36 data out pins.

End of Cycle (EC):

This going low signal indicates the memory cycle is complete. This signal occurs at to plus 800 nanoseconds and remains until to plus 880 nanoseconds.

End of Read (\overline{ER}) :

This signal going low indicates the read portion of the memory cycle is complete. This signal occurs at t_0 plus 450 nanoseconds and remains until t_0 plus 500 nanoseconds.

Memory Busy (MB):

This signal being low indicates that a memory cycle is occurring. This signal occurs at t_0 plus 90 nanoseconds and remains until t_0 plus 800 nanoseconds.

OPTIONS

Byte Control Timing (BCT):

Grounding or leaving this input open allows adjustment of the timing of the byte control signals for read modify write operations. If J46-77 is grounded, the byte write control signal must occur at to and remain stable for 100 nanoseconds. If J46-77 is open, the byte control signal must occur at write initiate time in the write portion of the cycle and remain stable for 100 nanoseconds. Refer to the byte control description in the input signals subsection.

Clear Data Out (CDO):

This input allows an external signal to clear the data out lines. The signal should occur between t_0 plus 450 (data out lines active for 100 nanoseconds) and t_0 plus 800 nanoseconds. If this input is open, the data out signals operate as described in the output signals subsection.

External Current Control (ECC):

An external current regulator can provide bias current for a multimodule system. To operate the modules this way, remove jumper -1 and jumper -2 (shown on logic sheet 22) from each module. Connector pins J46-11 and J46-12 must then supply the bias current. Figure 2-2 shows how to connect the modules. Figure 2-3 shows a circuit for a regulator which can be used as an external current supply.

Late Data Timing (LDT):

Grounding this input allows the data in signals to be delayed. If J46-6 is grounded, data in must be present from t_0 plus 200 nanoseconds to t_0 plus 350 nanoseconds. If J46-6 is open, data in must be present from t_0 to t_0 plus 150 nanoseconds.

16K to 32K Capacity Option:

The memory configuration can be changed to 32,768 18-bit words by the following modifications.

- Grounding input J47-58.
- Providing address bit AD17 which is address
 14. Module select addresses move to
 AD15-16-17. Refer to logic sheet 18.
- Connect the data inputs as indicated on page 5-1 of the logic diagrams. That is, connect J47-21 to J47-29, J47-23 to J47-49, and so forth.

CONNECTOR

The module plugs into dual edgeboard wire wrap connectors of 80 pins each. The pins are on 0.125 inch centers. The CDC part number is VPB01C40B00A1. A vendor part number is Amphenol 67878-7.

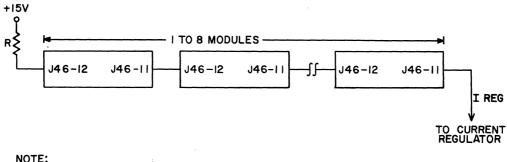
TERMINATION REQUIREMENTS

The inputs to the 94200 memory must have the proper termination resistors. Similarly, the inputs to the external equipment must be properly terminated. Refer to figure 2-4. The 94200 memory is available with or without terminators. Modules without terminators can be connected in parallel, and terminated using terminators located on the backpanel.

BIDIRECTIONAL DATA LINES

Tying the interface connector inputs and outputs together allows the use of one data input/output line per bit. To do this, the output drivers must be able to drive two termination networks (refer to figure 2-4). The 94200 output drivers can drive two termination networks.

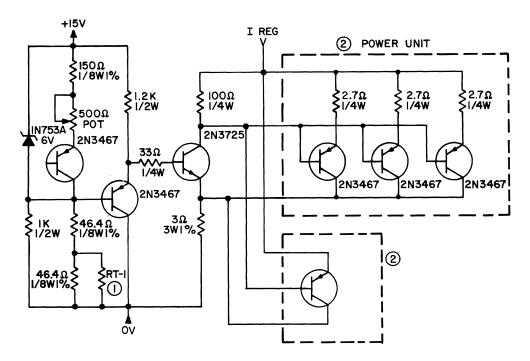
Operation with bidirectional data lines in read modify write mode can cause reflections to occur on the data lines. This happens if the 94200 output drive and the external input drive are on simultaneously (beginning of write initiate). When the memory driver turns off,



NOTE:

FOR 1 TO 2 MODULES R MUST BE 24.0Ω , 6 WATTS. FOR 3 TO 4 MODULES R MUST BE 18.0Ω , 5 WATTS. FOR 5 TO 6 MODULES R MUST BE 12.0Ω , 4 WATTS. FOR 7 TO 8 MODULES R MUST BE 6.0Ω , 3 WATTS.

Figure 2-2. Connection of Modules for External Current Control



NOTES:

- () RT-1 IS A THERMISTOR WHICH IS 100Ω AT 25°C. POSSIBLE THERMISTOR VENDORS ARE NATIONAL LEAD INC. 2D204 OR RODAN 2BD100.
- (2) THE POWER UNIT CAN CONSIST OF A NUMBER OF TRANSISTORS OR ONE POWER TRANSISTOR. THE POWER REQUIRED IS 2.5 WATTS MAXIMUM.

Figure 2-3. Current Regulator Circuit

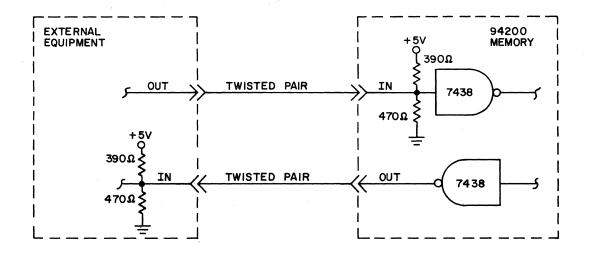
a positive reflection occurs which could cause the memory to malfunction. The amplitude and duration of the reflection depend on the length of the data line.

There are two ways to eliminate the reflections. One way is to apply a negative pulse to the clear data out input 50 nanoseconds before write initiate. This clears the memory drivers before new data appears on the lines. Another way to eliminate the

reflections is to connect the end of read output signal to the clear data out input. This causes data to be on the line from t_0 plus 350 nanoseconds to t_0 plus 500 nanoseconds.

TIMING DIAGRAMS

Timing diagrams for read restore, read-modifywrite, clear write, and byte write operations are at the end of this section.



Notes:

- 1. The 94200-00 does not have input termination resistors.
- 2. The 94200-01 has input termination resistors.
- 3. The twisted pair lines should be a maximum of 10 feet long.
- 4. Control Data can supply plug-in terminator resistors.
- 5. The 7438 drivers can sink 48 ma.

Figure 2-4. 94200 Line Terminations

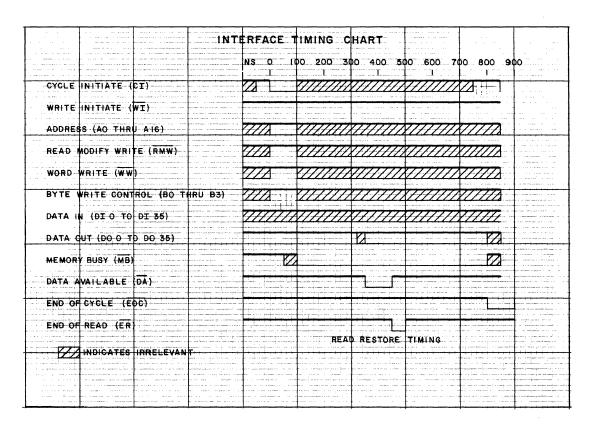


Figure 2-5. Read Restore Timing

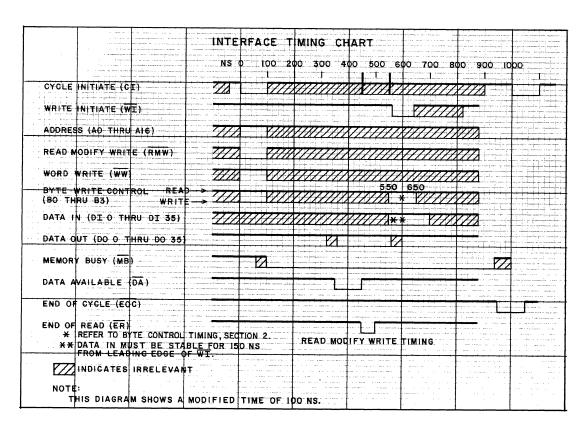


Figure 2-6. Read Modify Write Timing

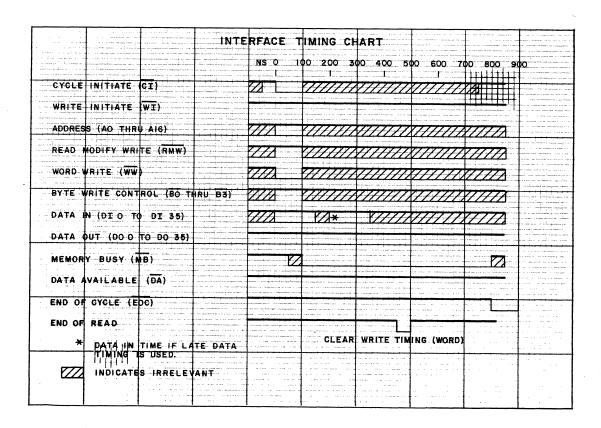


Figure 2-7. Clear Write Timing (Word)

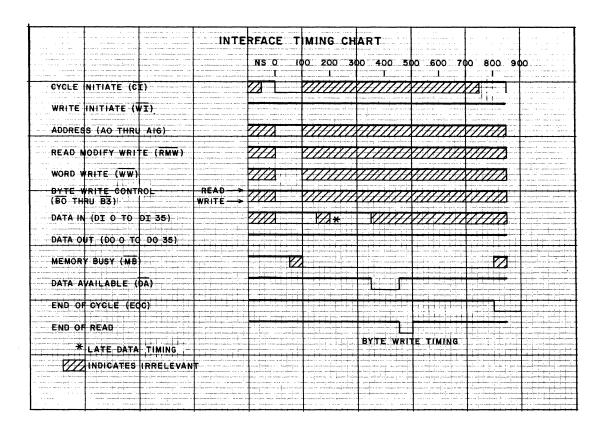


Figure 2-8. Byte Write Timing

INTRODUCTION

The 94200 memory module is a 3-D, 3-wire, random access core memory module with a common sense/inhibit line. The module contains timing, control, inhibit, and core drive circuits as well as data and address registers. Figure 3-1 shows a block diagram of the module.

MODULE SELECT

Module select decodes an address from the external equipment which specifies one module in a system that contains more than one module. A manual switch in a dual in-line package on each module must be set to decode the module address. In a single module application, the switch must be set closed and address inputs AD14, AD15, and AD16 left open. Logic page 5-21 shows the module select circuit.

ADDRESS REGISTER

The external equipment supplies information that determines at which location within the module an operation will take place. The address register stores this information and distributes it to the module select, core driver, byte control, and timing circuits. Address registers are shown on logic pages 5-18 through 5-20. The 74S157 chips compose the address register. When the hold input signal is low, the register gate is open. When hold goes high, the register latches.

TIMING AND BYTE REGISTER

The external equipment supplies control information that determines which operation the module performs. The cycle initiate input signal starts a read sequencer circuit. This circuit generates a sequence of signals that times the read portion of the memory cycle. When the read sequencer stops, a write sequencer starts to generate timing signals for the write portion of the memory cycle for a full cycle operation. During split cycle operations, the read sequencer completes the read portion of memory cycle and waits for a write initiate input signal to start the write sequencer. Both the read and write portion of a memory cycle occur during full and split cycle operations.

The timing diagrams (figures 3-2 and 3-3) show the read and write sequencer signals for one memory cycle. Other signals derive from the read and write sequencer signals through logical AND and OR functions. These signals cause the current source, sink discharge, core drive, and inhibit drive circuits to function at the proper times during a memory cycle. An explanation of the timing control logic on page 5-3 follows.

Output 8 of the gate at location Z106 and the delay line form a clock circuit. A factory-installed jumper from one of the delay line taps to input 13 of the gate completes the feedback loop. The clock period is 30 nanoseconds on and 30 nanoseconds off.

During a full cycle operation, inputs $\overline{\text{WI}}$ (write initiate) and $\overline{\text{MRMW}}$ (read modify write) are high. Input clear only goes low during power up or if the +15 volt and -15 volt power supplies malfunction. Input $\overline{\text{DS}}$ (data save) is high except at power up and power down. Inputs QT-12 and QT-24 are low at the start of a memory cycle while inputs $\overline{\text{QT-13}}$ and $\overline{\text{HOLD}}$ are high.

Input $\overline{\text{CI}}$ (cycle initiate) going low starts a memory cycle. Input MS (module select) goes high after the module select addressing is stable. Output $\overline{\text{RCLR}}$ then goes low setting the RST flip-flop and RST (Z95-8) output high which enables the read sequencer logic on page 5-4. Output $\overline{\text{RCLR}}$ going low causes output 6 of the gate at location Z106 to go high. The clock begins to oscillate and drives the sequencer logic.

The RST flip-flop being set causes pin 2 of Z106 to go low. This holds inputs 9, 10, and 12 of the gate at location Z106 high enabling the clock (CPM) to operate. $\overline{\text{HOLD}}$ then goes low driving input 9 of the gate at location Z96 low for the duration of the memory cycle. This prevents any change at the $\overline{\text{CI}}$ input from affecting the cycle.

At the end of the read portion of the cycle, input QT-12 goes high causing output 8 of the flip-flop at location Z89 to go low. This resets the flip-flop which generates output RST, and the read sequencer inhibits. Z89-9 going high causes outputs WST-1 and WST-2 to go high and output \overline{ER} (end of read) to go low. WST-2 going high enables the write sequencer logic. At the end of the write portion of the cycle, input QT24 goes high and Z89-6 goes low resetting WST-1 and WST-2. This stops the clock. QT-24 resets the hold flip-flop allowing another CI input signal to start a new memory cycle.

During a split cycle operation, input MRMW is low. This means that output 6 of the gate at location Z95 is always high. Consequently, input $\overline{\text{WI}}$ must go low to start the write portion of the memory cycle. Input $\overline{\text{WINH}}$ prevents $\overline{\text{WI}}$ from starting the write portion of the cycle if the read portion has not occurred.

BYTE CONTROL

The byte control logic combines external control signals and internal timing signals to generate data control signals. These signals cause the data buffer, sense amplifier, and data register to function at the proper times during a memory cycle. The byte control logic also determines from external control signals whether full words or 9-bit bytes transfer into or out of memory.

3-1

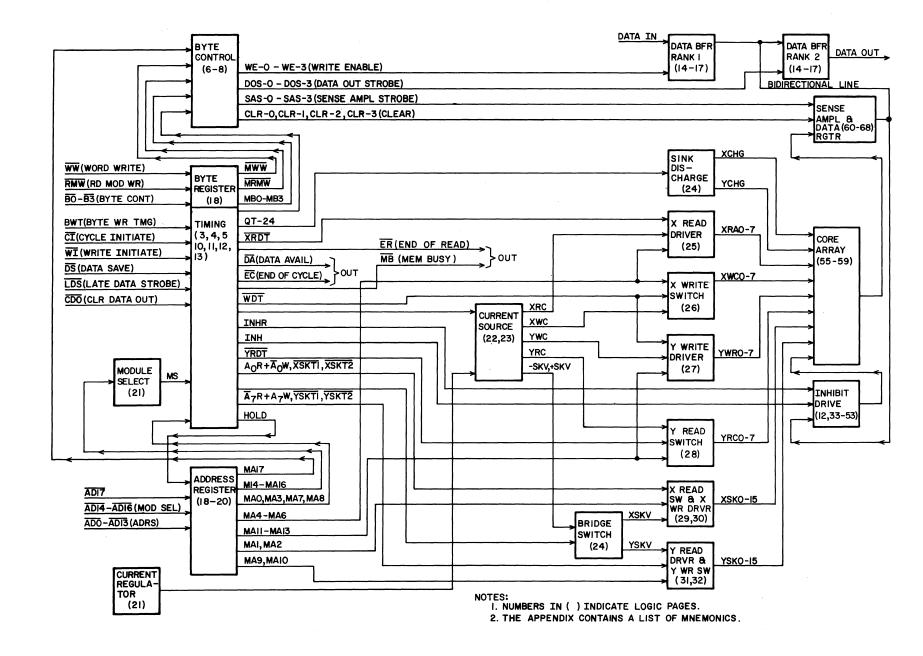


Figure 3-1. Module Block Diagram

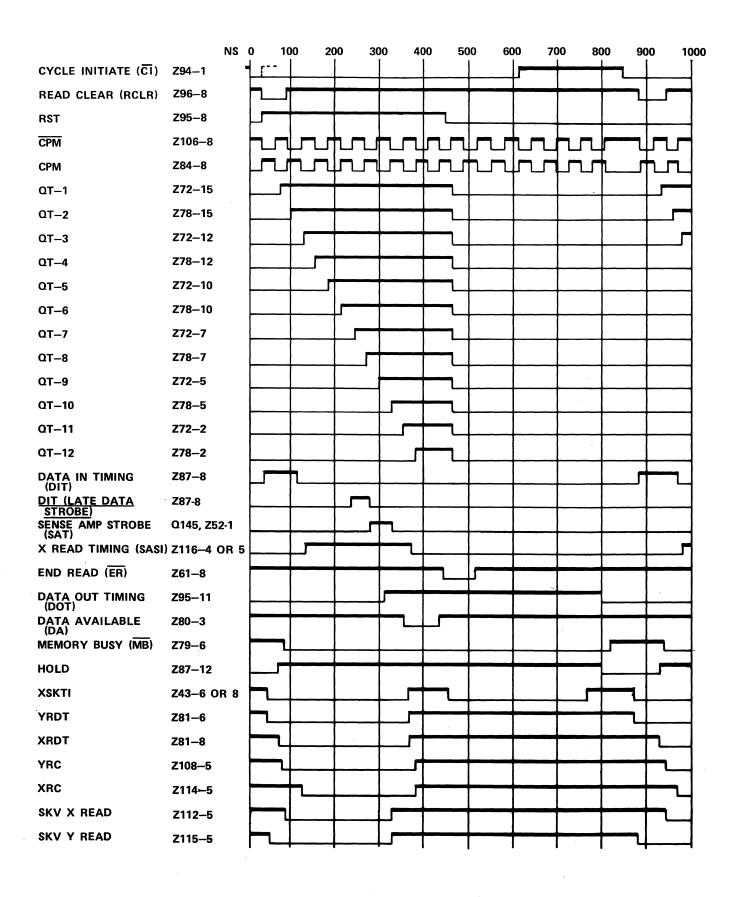


Figure 3-2. Memory Cycle Timing, Read Portion

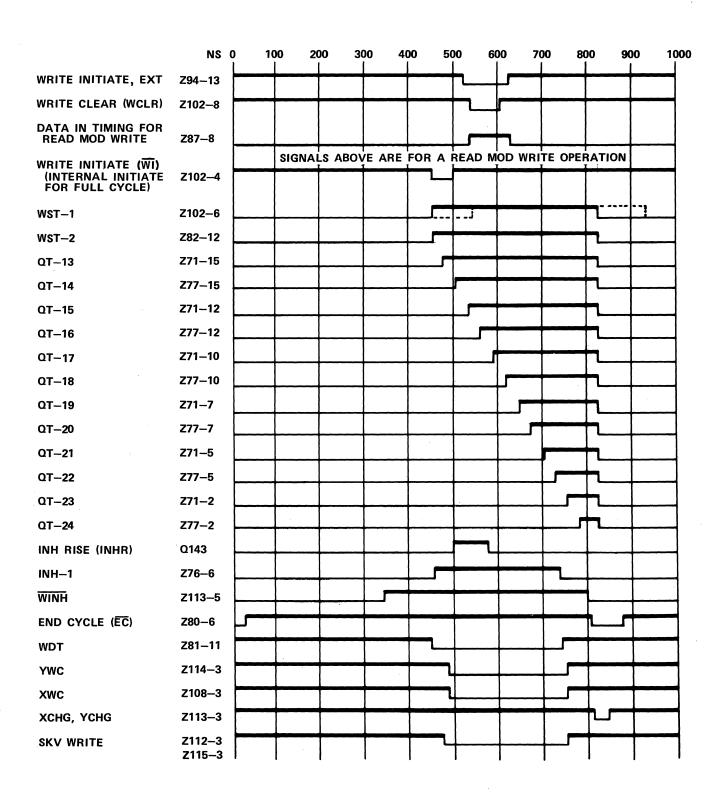


Figure 3-3. Memory Cycle Timing, Write Portion

Descriptions of the byte control logic during various operations follow.

BYTE TRANSFERS, 16K x 36-BIT CONFIGURATION

The memory is divided into four 9-bit bytes, MB-0 through MB-3 (refer to logic page 5-18). The 74S157 chip at location Z75 stores the four bits of byte information. When a byte input is high, the module performs a read-restore operation. A low byte input causes a clear-write function to occur. The byte register latches at 80 nanoseconds after the cycle initiate signal appears and remains latched until 800 nanoseconds into the cycle.

When the module is in the 16K x 36-bit configuration, the A inputs of the 74S157 at location Z47 on logic page 5-6 are selected. For a read-restore operation, MB-0 through MB-3 are high and $\overline{\text{MWW}}$ is high ($\overline{\text{WW}}$ input is open). Outputs WR-0 through WR-3 are then low. This holds the write enable gates (WE-0 through WE-3) off and enables the sense amplifier strobes (SAS-0 through SAS-3). When MB-0 through MB-3 are low (clear-write operation), the WR-0 through WR-3 signals are high. This causes the WE gates to enable and the SAS gates to inhibit.

WR-0 through WR-3 control the data out strobes (DOS, page 5-7). When the WR signals are low (read-restore), the DOS gates enable which samples the output buffers. Data then appears on the output lines.

FULL WORD TRANSFERS, 16K x 36-BIT CONFIGURATION

The word write (WW) input controls all 36 bits in this case. Word write operates the memory in the same manner as the byte control inputs described in the preceding section. When word write is high, a read-restore operation occurs. Word write being low causes a clear-write operation.

BYTE TRANSFERS, 32K x 18-BIT CONFIGURATION

The B0 and B2 inputs control byte transfers in this configuration. The B1 and B3 inputs should be open, and the 16K/32K input should be grounded. Pin 1 of the 74S157 on logic page 5-6 being high enables the B inputs of the 74S147. When a clearwrite operation is initiated, MB-0 is high. MA17 being high causes WR-0 to go high. MA17 is then low causing WR-1 to be low (read-restore). Byte 1 (B2 input) which controls WR-2 and WR-3 operates in the same manner.

FULL WORD TRANSFERS, 32K x 18-BIT CONFIGURATION

Word write control (\overline{WW}) operates in the same way as the byte control inputs except that \overline{MWW} controls the full word. The byte control inputs should be open.

The memory module always operates on a 36-bit word with address 17 determining what half of the word is to be operated (controlled) on.

DATA BUFFER

The data buffer receives data from the external equipment and transmits data to the external equipment. Logic pages 5-14 through 5-17 show the data buffer. Data on the input lines gates into memory when the write enable (WE) input goes high. If write enable is low and data out strobe goes high, data transmits from memory to the external equipment

CURRENT REGULATOR

The current regulator provides a regulated bias current for the switch cores in the current source. Thermistor RT-1 causes the regulator to compensate for changes in memory core characteristics with temperature. If temperature increases, the regulator output decreases and vice versa. Logic page 5-21 shows the current regulator circuit.

CURRENT SOURCE

The current source provides current for switching the memory cores. Logic pages 5-22 and 5-23 show the current source. Outputs YRC, +SKV, XWC, XRC, -SKV, and YWC drive the cores through the bridge, read, and write switches. Timing signals cause the appropriate gates at locations Z108 and Z114 to turn on the current source after all of the appropriate core drive switches have turned on.

IREG from the current regulator flows through switch cores T68 and T80 in series. This current biases the switch cores and causes the current source to provide the proper drive current to the memory cores.

BRIDGE SWITCH

The bridge switches steer the direction of current flow in the XSKV and YSKV outputs for read and write operations. Timing signals drive the gates at locations Z112 and Z115. These gates cause a pair of transistors to turn on and effectively connect the outputs to -SKV or +SKV. Q126 effectively connects XSKV to -SKV and Q129 effectively connects YSKV to +SKV during a read operation. During a write operation, Q127 effectively connects XSKV to +SKV and Q140 effectively connects XSKV to -SKV. Logic page 5-24 shows the bridge switch.

X READ SWITCHES AND X WRITE DRIVERS, Y READ DRIVERS AND Y WRITE SWITCHES

These circuits connect the X and Y drive lines to the current source during read and write operations. Timing and address signals cause specified drive lines to activate at the proper time. These circuits are shown on logic pages 5-29, 5-30, 5-31, and 5-32. The circuit on page 5-29 is described below.

The 74145 decodes address and timing information. This causes a specified output to connect to the proper current source polarity at the proper time during read and write operations. Address inputs MA01 and MA02 specify a pair of transistor switches. AoR + AoW specifies one of the pair

of switches. Table 3-1 illustrates the various conditions. Assume the address specifies the uppermost pair of transistors. The uppermost transistor is Q_1 , and the second transistor down is Q_2 (this half of QM-13 package).

TABLE 3-1. ADDRESS AND DRIVE CURRENT RELATIONSHIP

Oper- ation	XSKV	AoR+AoW	Decoder Output Low	Q_1	Q_2	Drive Current Flow
Read	-	Low	1	On	Off	From XSK0 through CR393, through Q_1 , through CR368 to XSKV.
Write	+	High	2	Off	On	From XSKV through CR377, through Q_2 , through CR396 to XSK0.
Read	-	High	2	Off	On	From XSK1 through CR395, through Q_2 , through CR369 to XSKV.
Write	+	Low	1	On	Off	From XSKV through CR376, through Q ₁ , through CR394 to XSK1.

X READ DRIVER, X WRITE SWITCH, Y WRITE DRIVER, Y READ SWITCH

These circuits turn on specified X or Y drive lines during read and write operations. The 74145 decodes the address and causes one of the transistor switches to turn on. This effectively connects the selected drive line to the current source. Logic pages 5-25, 5-26, 5-27, and 5-28 show these circuits.

The diagram in figure 3-4 shows the core drive circuits.

INHIBIT

During a read operation, all one-state cores at the location being referenced switch to a zero state. These cores switch back to the one state during the write (restore) portion of the memory cycle. The inhibit circuit prevents the cores originally in the zero state from also switching to the one state during write portion of memory cycle.

Logic sheets 36 through 53 show the inhibit drive circuits. Refer to bit 3 on page 5-37 during the following discussion unless otherwise noted. The P27-1 input comes from the sense amplifier output. The INHT-4 input derives from address and timing signals. If inputs P27-1 and INHT-4 are high, transistor Q_{11} turns on causing current to flow in outputs P27-5 and P27-6. This inhibits the corresponding core from switching during restoration.

 Q_{10} is turned on during the start of inhibit. This effectively shorts out part of the primary winding of the inhibit drive transformer. The turns ratio of the transformer thus effectively decreases. Consequently, the inhibit drive current builds up to the desired value. When the drive current reaches the desired value, Q_{10} turns off increasing the turns ratio again. The primary of the transformer then delivers a lower current. Because of current step up, the secondary produces the proper inhibit current.

The predrive for inhibit rise circuits on logic pages 5-33, 5-34, and 5-35 drive the transistors that effectively short part of the primary of the drive transformers. The inhibit rise time generator shown on page 5-12 provides a pulse to drive the predrive for inhibit rise circuits. This pulse is adjusted at the factory by selecting R279 in the inhibit rise time generator. Input QT-13 causes the inhibit rise time circuit to generate a pulse with the proper width.

SINK DISCHARGE

The sink discharge circuit is shown on page 5-24. Input QT-24 causes Q130 and Q131 to turn on and effectively tie the core drive lines to 0 volts at the end of a memory cycle. This leaves the stack at 0 volts until another cycle initiates.

CORE ARRAY

The 94200 core array is organized into 36 128 x 128 planes containing 16,384 bits each. Each plane correlates with one bit of the data word. An address drive line is strung through each row of cores in the X direction. Similarly, an address drive line is strung through each row of cores in the Y direction. The address drive lines are continuous from one plane to the next. The memory thus has a total of 128 X and 128 Y drive lines. Activating one X line and one Y line references one word location. Each plane has two sense/inhibit lines. This allows a faster memory cycle. Each sense/inhibit line is strung through one half of the cores (8192) in the plane. The sense/inhibit lines connect to dual sense amplifiers. Dual sense amplifiers and a data register are combined in the same package. There are 36 dual sense amplifierdata register packages.

During a read operation, all cores at the referenced location in the one state switch to the zero state. Pulses are induced into the corresponding sense/inhibit lines when a core switches. The sense

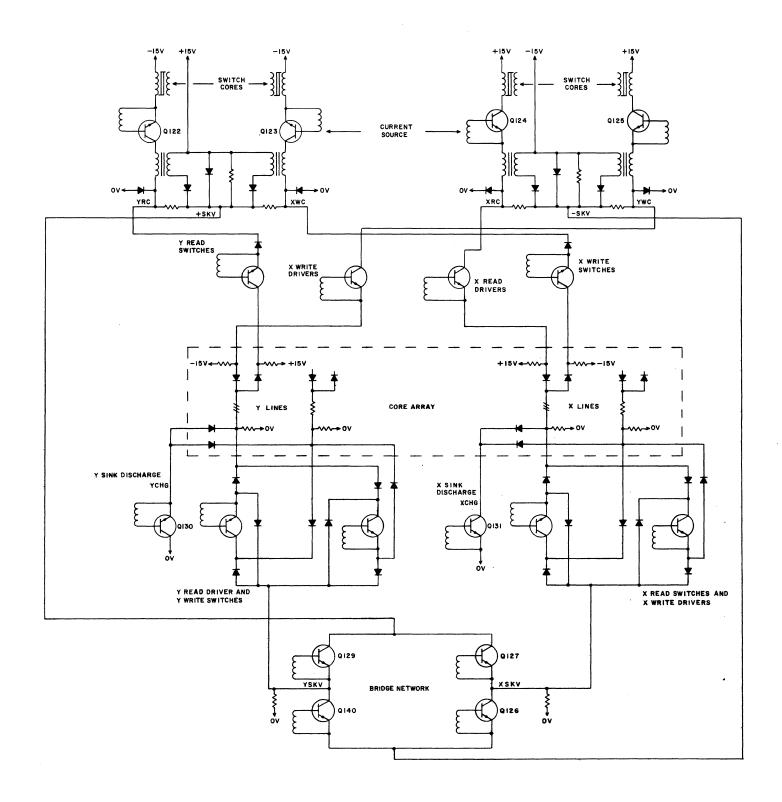


Figure 3-4. Core Drive Circuits

amplifiers receive the induced pulses and store ones in the data register. Cores which were in the zero state at the beginning of the operation do not switch. Therefore, those sense amplifiers store zeros in the data register.

Information stored at the referenced location is destroyed during a read operation. Consequently, the information must be restored into memory. During the write (restore) portion of a memory cycle, the sense/inhibit lines corresponding to zeros in the stored data word are driven. This prevents those cores from switching to a one state. The bits with no inhibit current cause these cores to switch to a one state.

Write operations perform by clearing data out of the referenced location and writing in new data. In this case, the input data word stores the information in the data buffer register. The data buffer register then controls the inhibit drive which determines which cores contain ones or zeros.

Figure 3-5 shows an example of X and Y line selection. Logic pages 5-56 through 5-59 are schematics of the core array.

SENSE AMPLIFIER AND DATA REGISTER

The sense amplifiers read data from the memory cores, and the data register causes data to restore into memory. Thirty-six microcircuits compose the sense amplifiers and data register. Each microcircuit package contains a dual sense amplifier and one bit of the data register. Logic pages 5-60 through 5-68 show the sense amplifiers and data register.

ONE-BIT DATA PATH

Figure 3-6 outlines the data path of bit 2 of the data word. Each half of a memory plane has a sense/inhibit line (SA and SB). The two sense inhibit lines for each plane connect to a dual sense amplifier. Each dual sense amplifier also contains one bit of the data register. During a read operation, the sense/inhibit line corresponding to the half of the memory plane in which the core referenced is located becomes active. If the core referenced had a one stored, the core switches to zero and generates a pulse in the sense/inhibit line. The pulse drives one input of the dual sense amplifier. When a strobe pulse (SAS-0 through SAS-3) samples the strobe gate in the sense amplifier-data register package, a one sets into the data register. Setting a one into the data register causes its output to go low.

If the core referenced had a zero stored, no pulse occurs in the sense/inhibit line, and the output of the data register remains high. Therefore, a zero (GND) appears at the output of the data buffer when the data out strobe signal occurs.

The output of the data register also drives the inhibit circuit. The outputs of the data register which correspond to zero-state cores are high. This partially enables one of the gates at location Z3, figure 3-6. Input INHT-3 or INHT-4 goes high causing current to flow in the sense/inhibit line in the half of the memory plane corresponding to the location referenced. In the read-modify-write mode, data is present at the data input buffer at the start of the write portion of the memory cycle. Write enable samples the data, and the information stores in the data buffer register. Zeros on the data input lines cause the corresponding data register outputs to be high. This enables the gates at location Z3 in figure 3-6. The proper sense/inhibit line then activates in the same manner as during the inhibit portion of a full cycle operation.

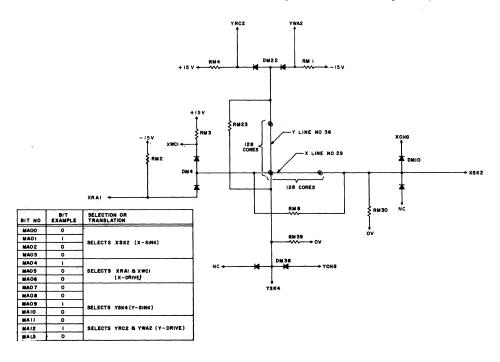


Figure 3-5. X and Y Line Selection Example

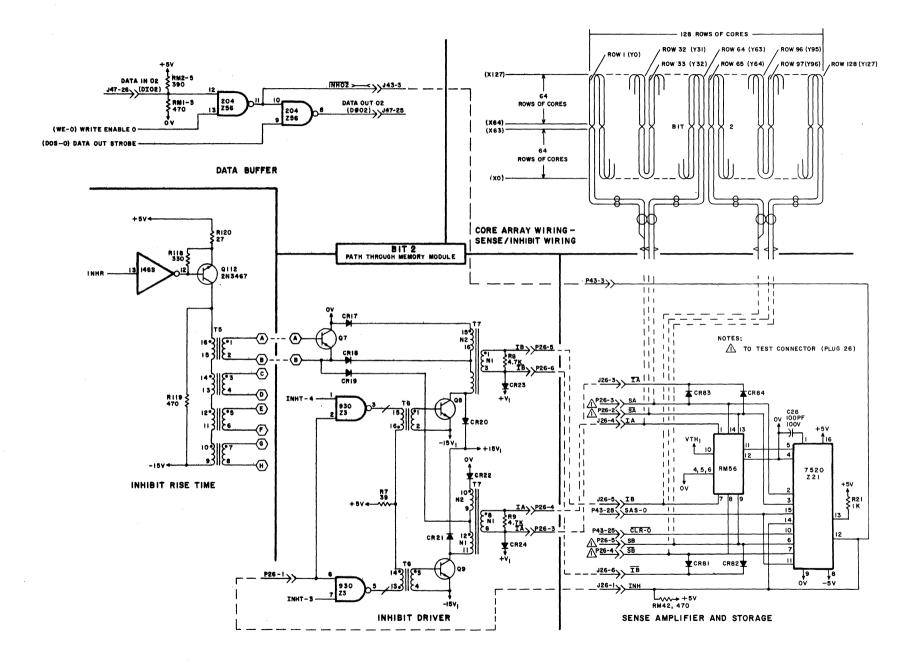


Figure 3-6. Bit 2 Data Path

INTRODUCTION

This section provides memory tests and troubleshooting charts to aid in finding problems. The memory tests usually indicate data, address, or control logic errors in the module. The charts provide possible causes of the trouble.

Before troubleshooting the module, be sure the problem is not external. Check the power supply voltages, and see that the power supply regulates properly. Improper programming causes errors. The accessibility of the interface lines makes this a reasonable place to start troubleshooting. Substituting a spare module isolates problems quickly.

RECOMMENDED TEST EQUIPMENT

Equipment	Manufacturer	Type
Oscilloscope	Tektronix	454 series or equivalent
Current probe	Tektronix	P6021 or equivalent
Voltage probe	Tektronix	10:1 attenuation or equivalent
Digital multimeter	Fairchild	Model 7050 or equivalent
VOM	Triplett	630-NA or equivalent

MEMORY TESTS

The following externally generated test patterns are useful for troubleshooting.

ALL ONES

Sequentially load the memory with logic ones. Next, do a read-restore operation. Ones should unload from the storage location of each address. Any zero on the data out lines is an error. Record the address and bit or bits in error.

ALL ZEROS

Proceed as in the all ones test, but load and unload the memory with zeros.

WORST PATTERN AND WORST PATTERN COMPLEMENT

These patterns cause the worst-case noise conditions on the output lines during read-out. The following logic equations relate addresses to data content for writing the worst patterns into memory:

Worst Pattern =
$$26 \cdot \frac{27}{27} + 26 \cdot 27$$

Worst Pattern = $26 \cdot 27 + 26 \cdot 27$

Read the memory and record any address and bit errors.

ERRORS

Errors discovered while running the test patterns are usually associated with the data, address, or control logic in the memory module.

CONTROL ERRORS

Failure to perform operations or erratic operations usually indicates a control problem. Control problems also cause data and address errors. Faulty signals from the external equipment can cause control malfunctions. Refer to figure 4-1 and the interface timing diagrams (figures 2-4 through 2-7) in section 2 when troubleshooting control errors.

ADDRESS ERRORS

Address errors affect all bits in a data word because decoded address information specifies an X and Y drive line in order to reference memory. Malfunctioning drive line control circuits cause errors at all addresses on the drive line. Failure of the address register, drive switches, or decoders causes address errors.

If the same address errors occur in all modules of a multimodule system, check the address input signals, line connections, and address registers. If all errors are associated with one module, substitute a spare module or swap with a module at a different location. This isolates the problem to one module. Refer to figure 4-2 when troubleshooting address errors.

Table 4-1 is an aid to troubleshooting to circuit and component levels. The table associates the address bits with circuits, components, and logic diagrams. The address bits are grouped to show the relationship to the X and Y memory drive lines. An example address (octal) of 0-4-3-11 is shown. The circuits and components which cause drive

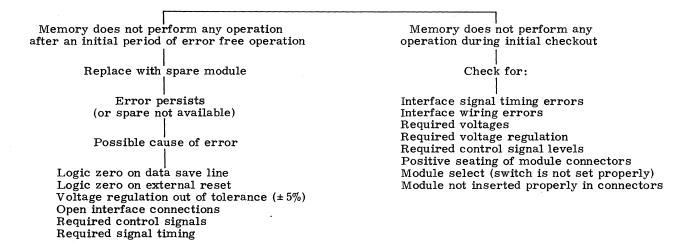
current to flow during a read operation do not necessarily cause current to flow during write operation.

DATA ERRORS

Data errors usually occur in the same bit position of all data words during either a read or write

operation. Check the sense amplifier and related circuits for bit errors during a read operation. Check the inhibit driver and related circuits for bit errors during a write operation. Address 2^{13} divides the bit into two 8K segments for inhibitsense. Refer to figure 4-3 when troubleshooting data errors.

MEMORY ERRORS SYMPTOM



MEMORY PERFORMS AT LEAST ONE OPERATION. BUT NOT:

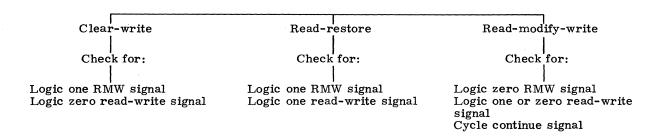


Figure 4-1. Control Errors

ADDRESS ERRORS

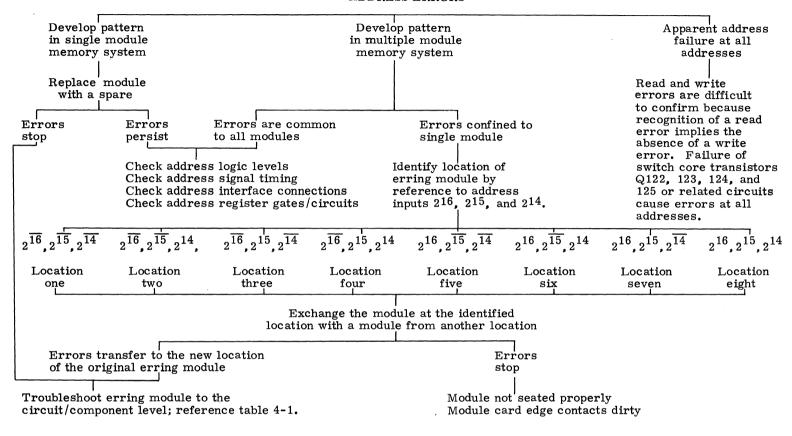


Figure 4-2. Address Errors

TABLE 4-1. RELATIONSHIP OF ADDRESS BITS, CIRCUITS, AND LOGIC DIAGRAMS

Address Bits	2 ¹⁶ 2 ¹⁵ 2 ¹⁴	2 ¹³ 2 ¹² 2 ¹¹	2 ¹⁰ 2 ⁹ 2 ⁸ 2 ⁷	26 25 4	$2^3 \ 2^2 \ 2^1 \ 2^0$
Function Address Octal Address	Module 0 through 7.	Y read switches, logic page 5-28. Y write drivers, logic page 5-27. (diode end of stack) 213 212 211	Y read drivers and Y write switches, logic pages 5-31 and 5-32. (sink end of stack) 210 29 28 27	X read drivers, logic page 5-25. X write switches, logic page 5-26. (diode end of stack) 26 25 24 3	X read switches and X write drivers. Logic pages 29 and 30. (sink end of stack) 2 ³ 2 ² 2 ¹ 2 ⁰ 11
X-Y designation logic page no. in ().		YRC0 (5-28) YWA0 (5-27)	YSK4 (5-31)	XRA3 (5-25) XWC3 (5-26)	XSK11 (5-30)
Possible circuitry for cause of problem		QM3, pin 5-7 CR454 T74 Z123 P4, term 9 QM1, pin 1, 2, 3 T72 Z118 P2, term 1	QM9, pin 1-7 CR306 CR324 CR315 CR327 T81 Z117 P1, term 14	QM5, pin 12-14 T76 Z119 P2, term 12 QM7, pin 8-10 CR462 T78 Z122 P4, term 4	QM15, pin 8-10 and 12-14 CR177 CR412 CR419 CR430 T87 Z121 P3, term 12

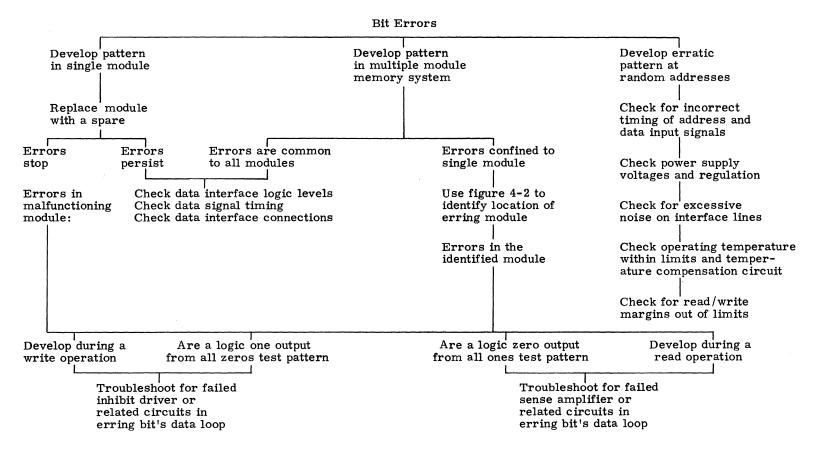
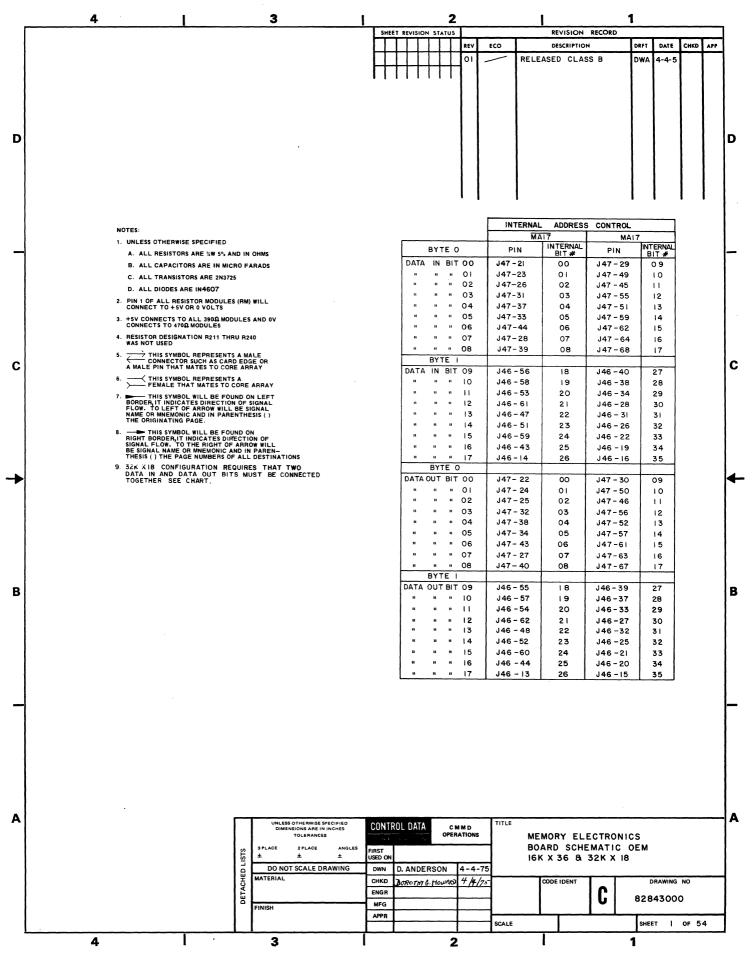
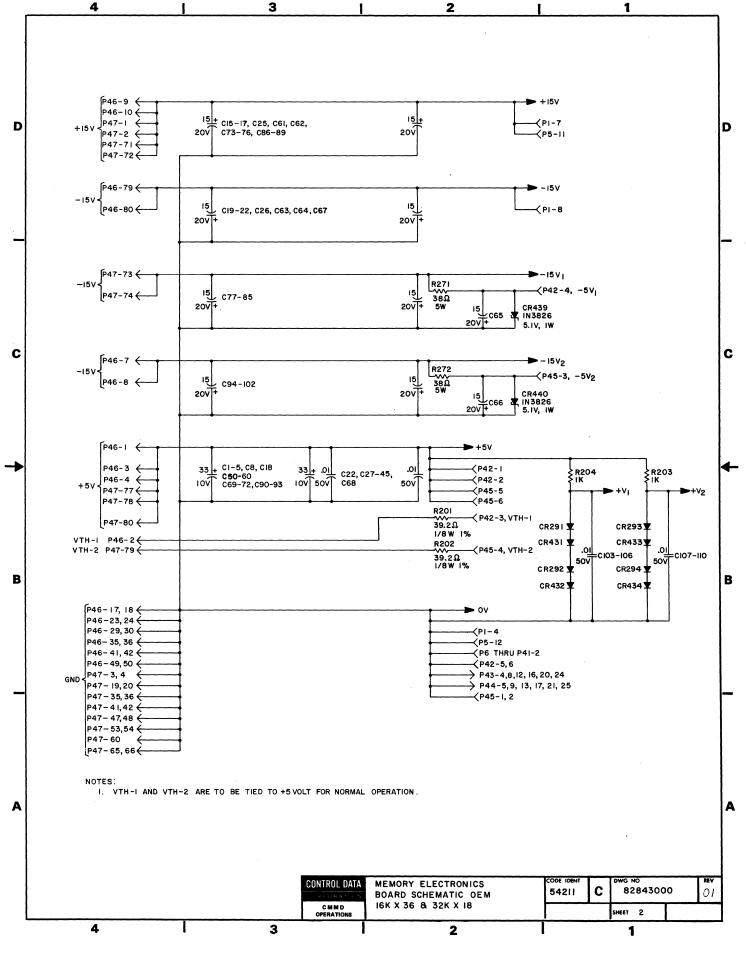
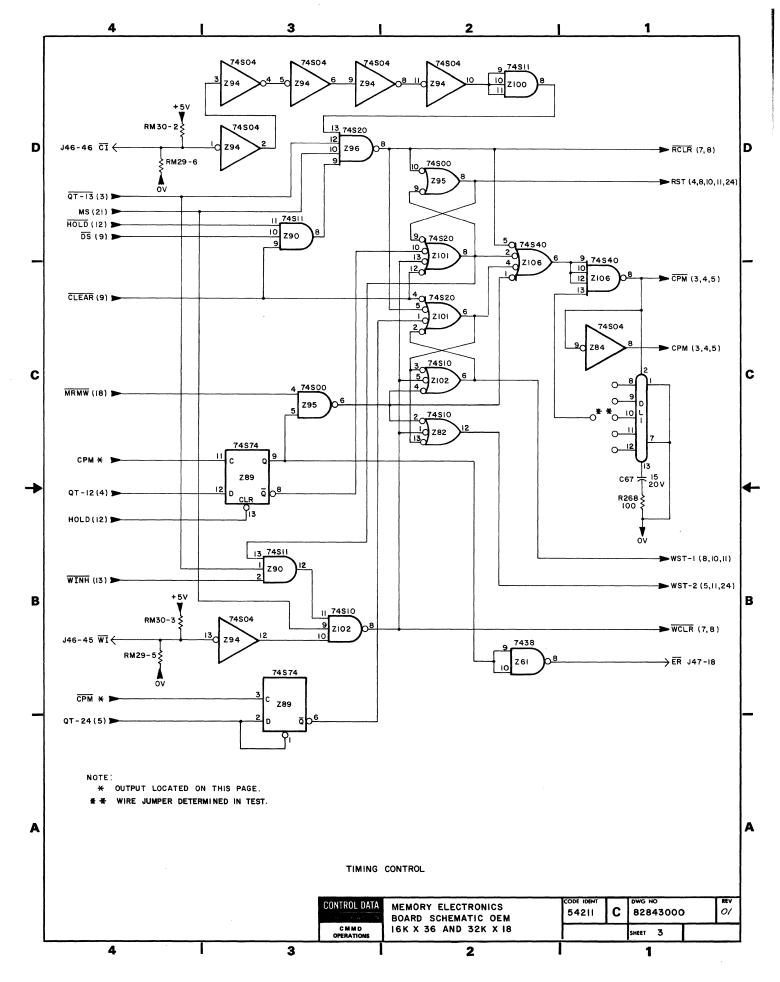


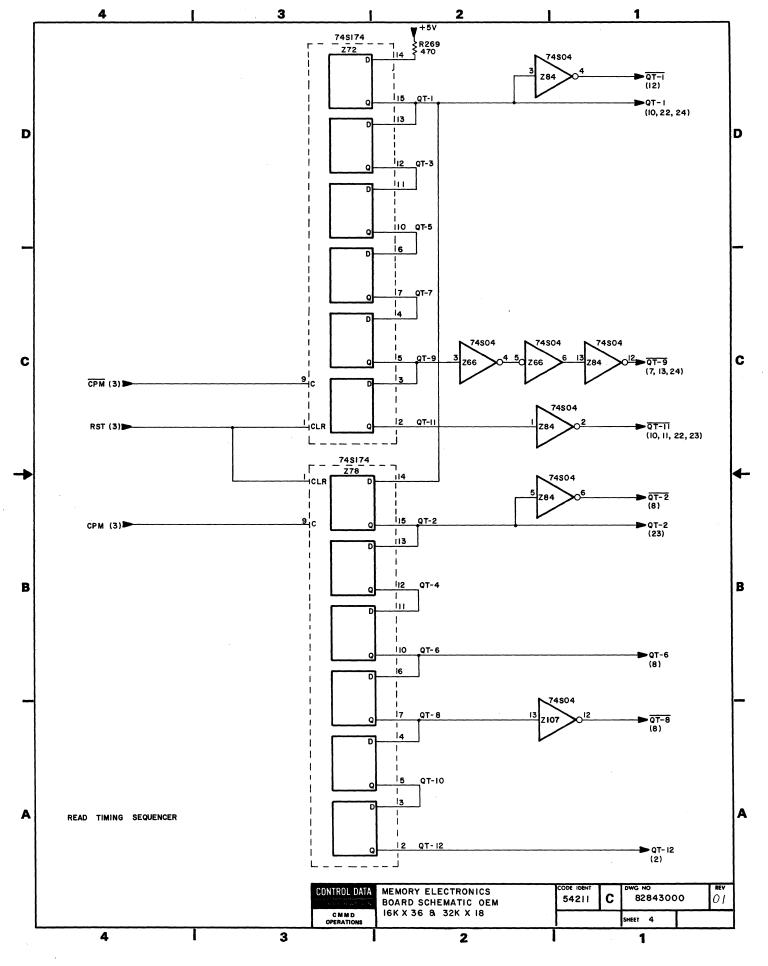
Figure 4-3. Data Errors

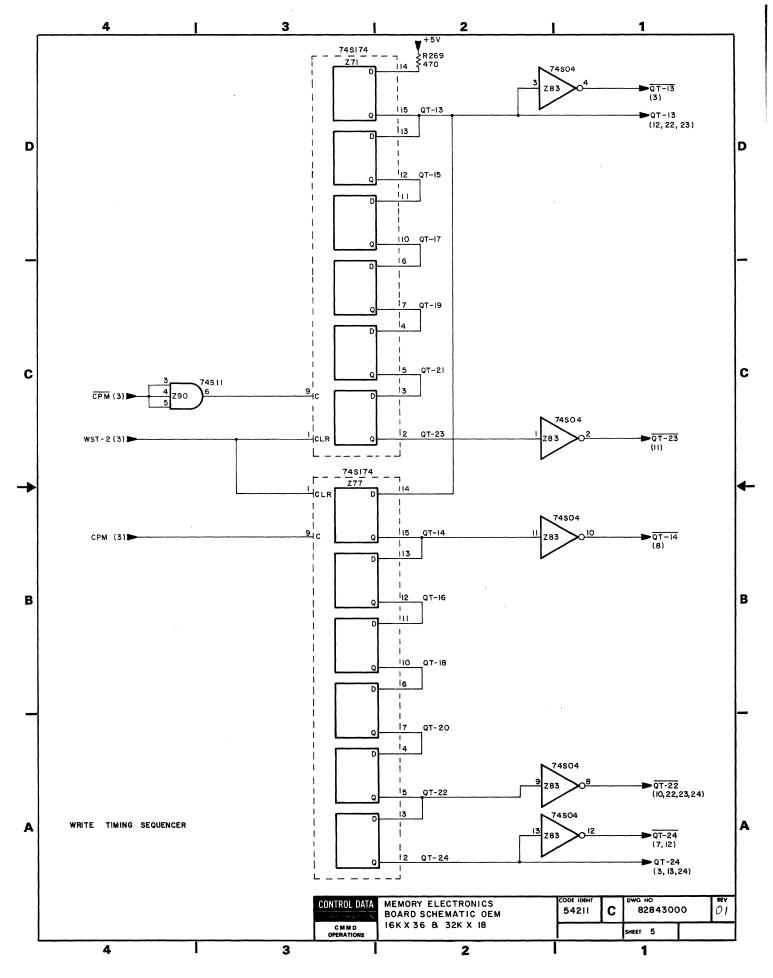
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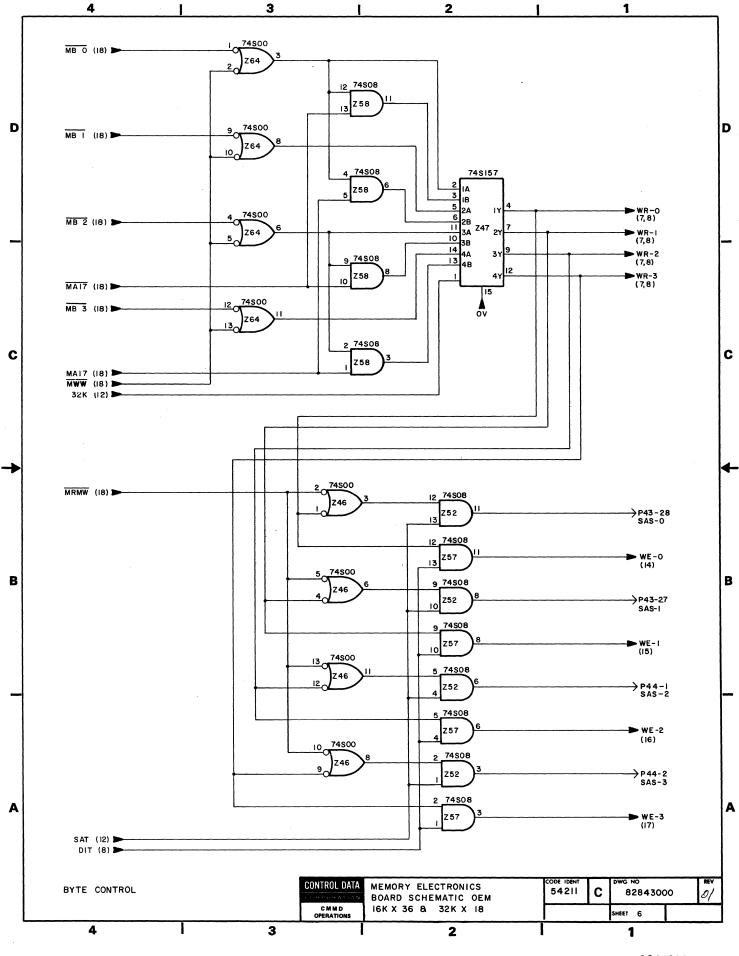


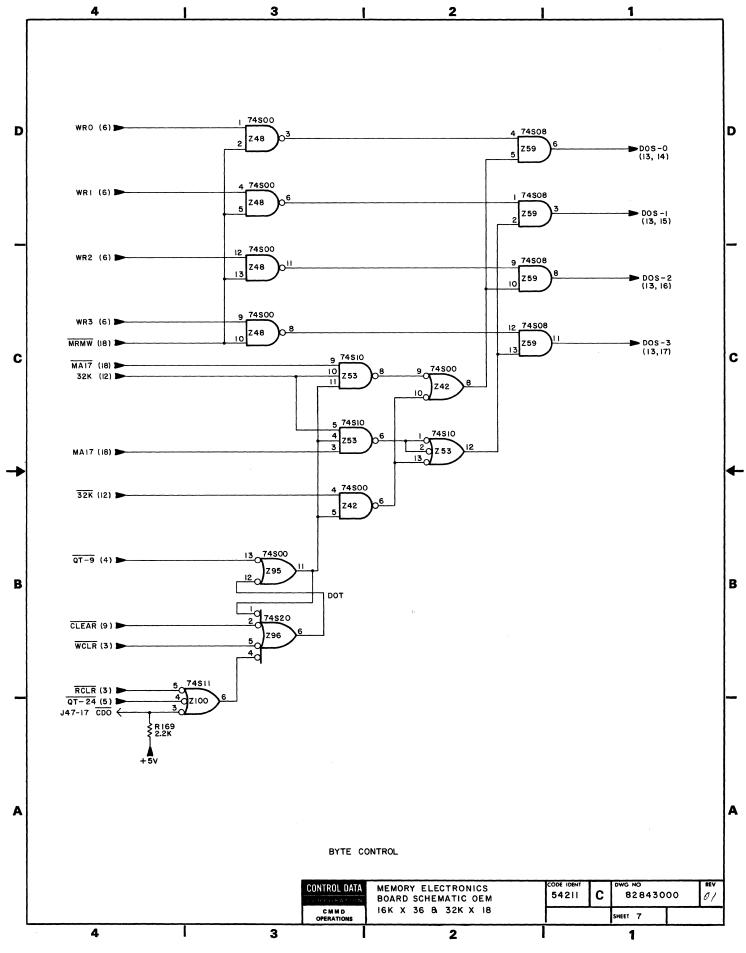


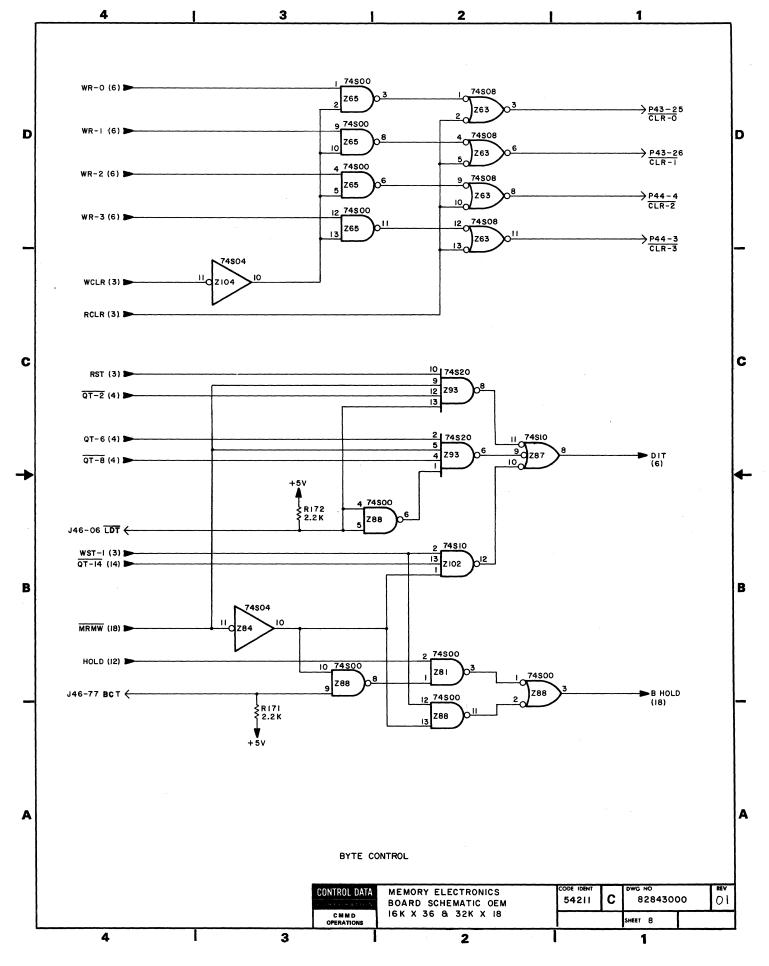


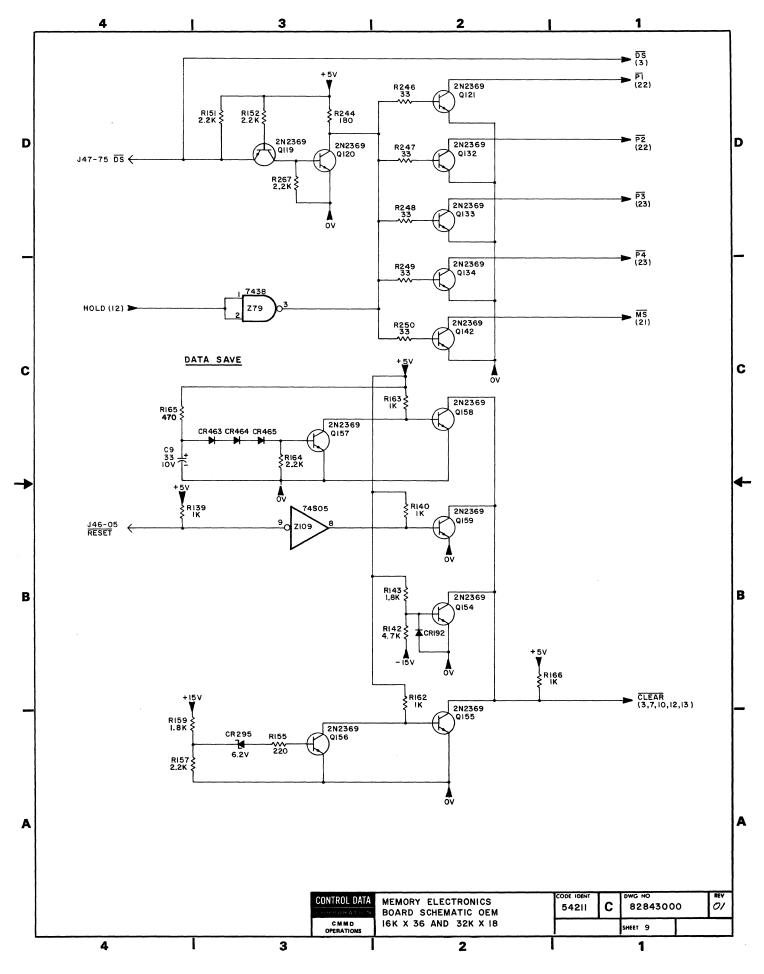


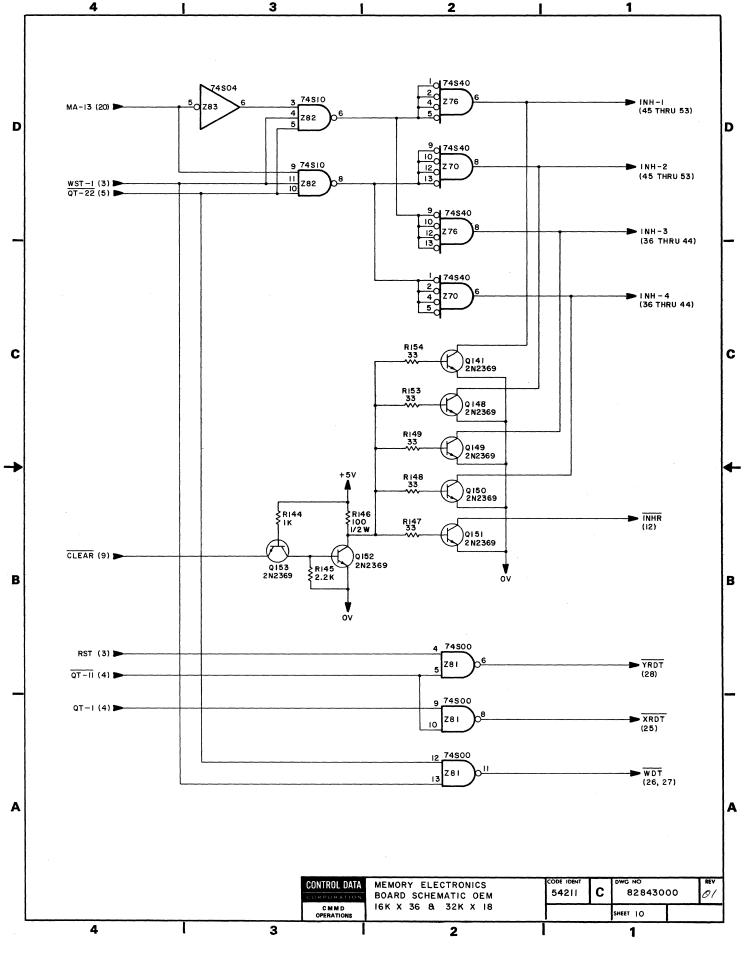


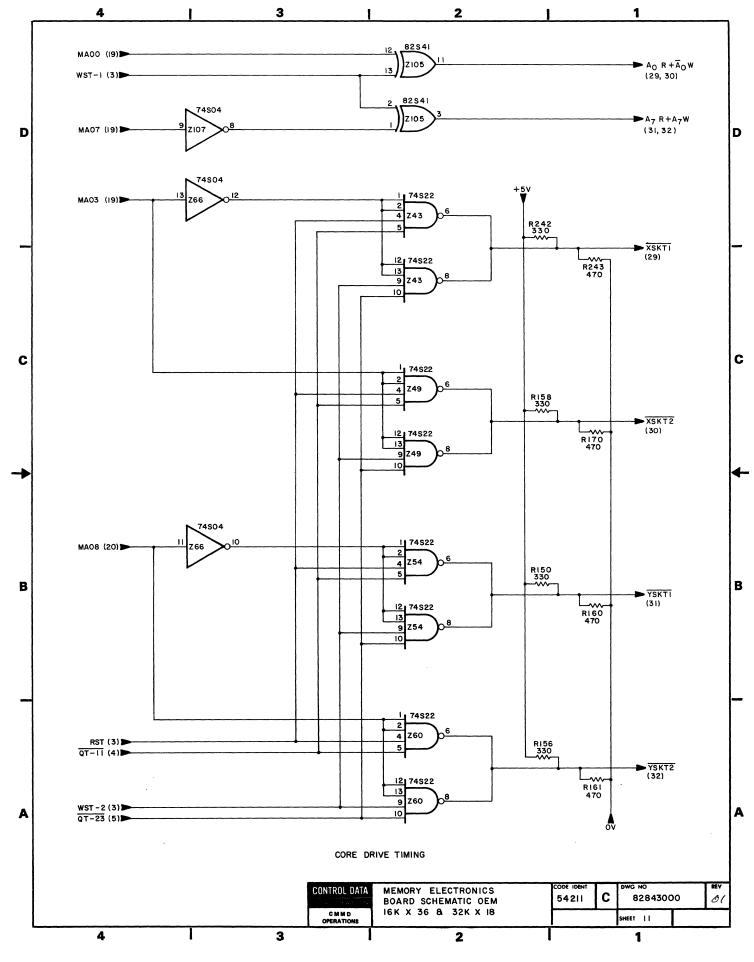


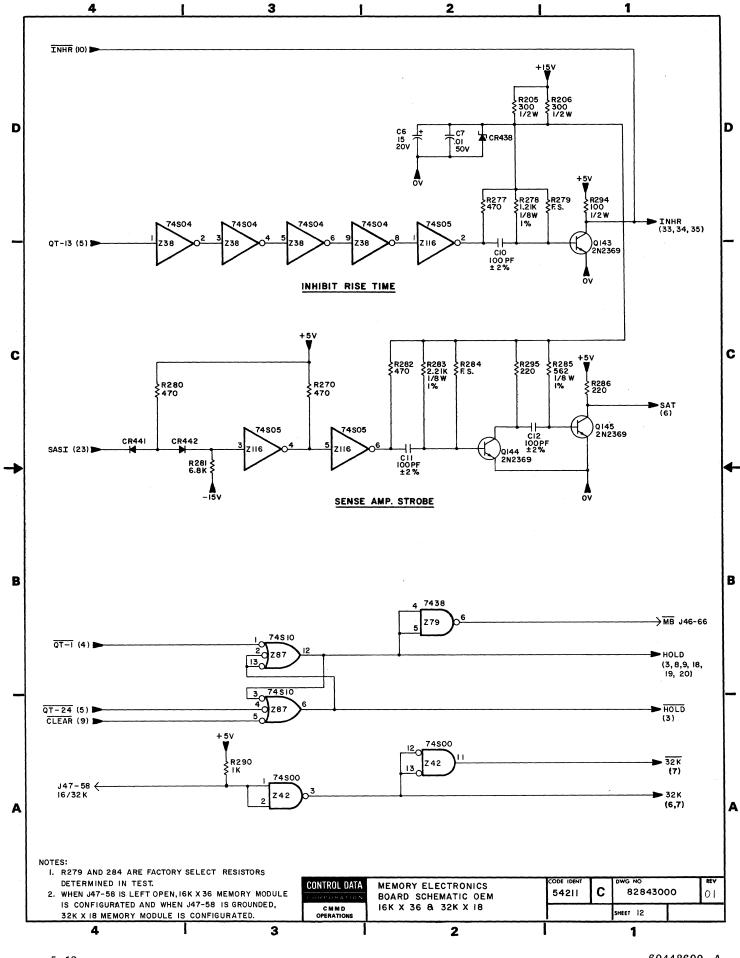


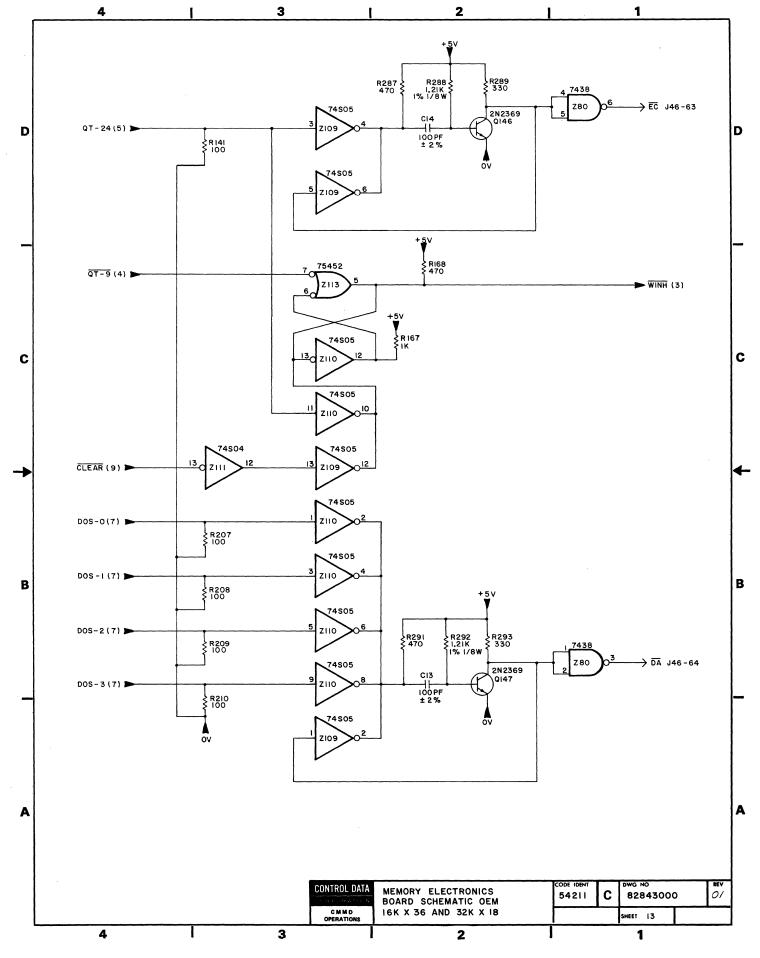


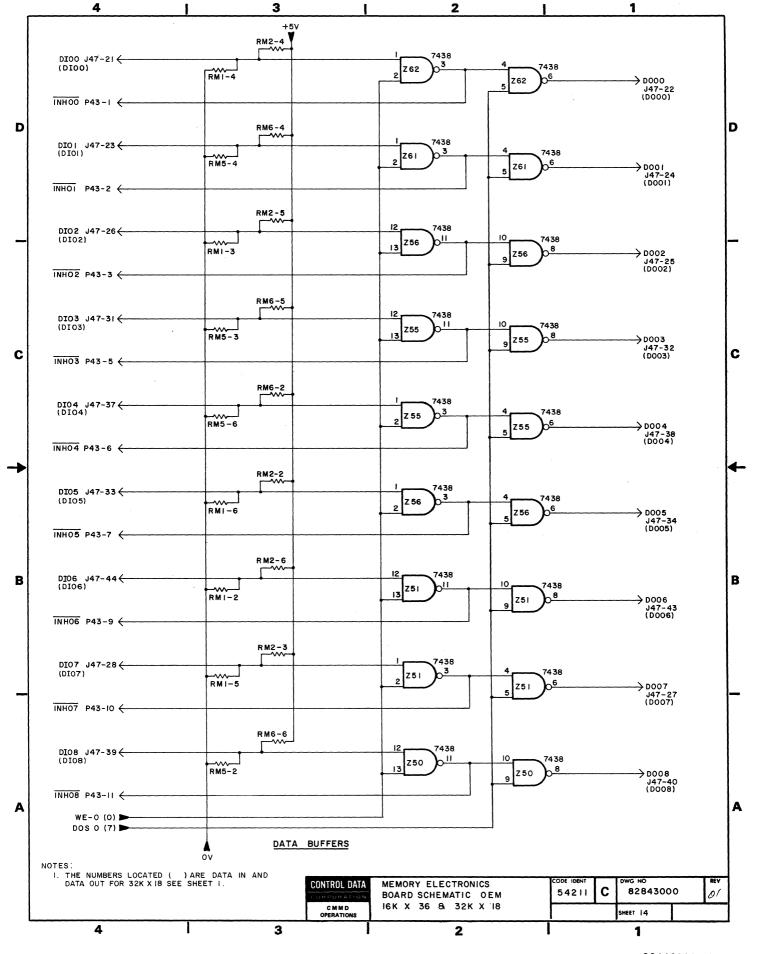


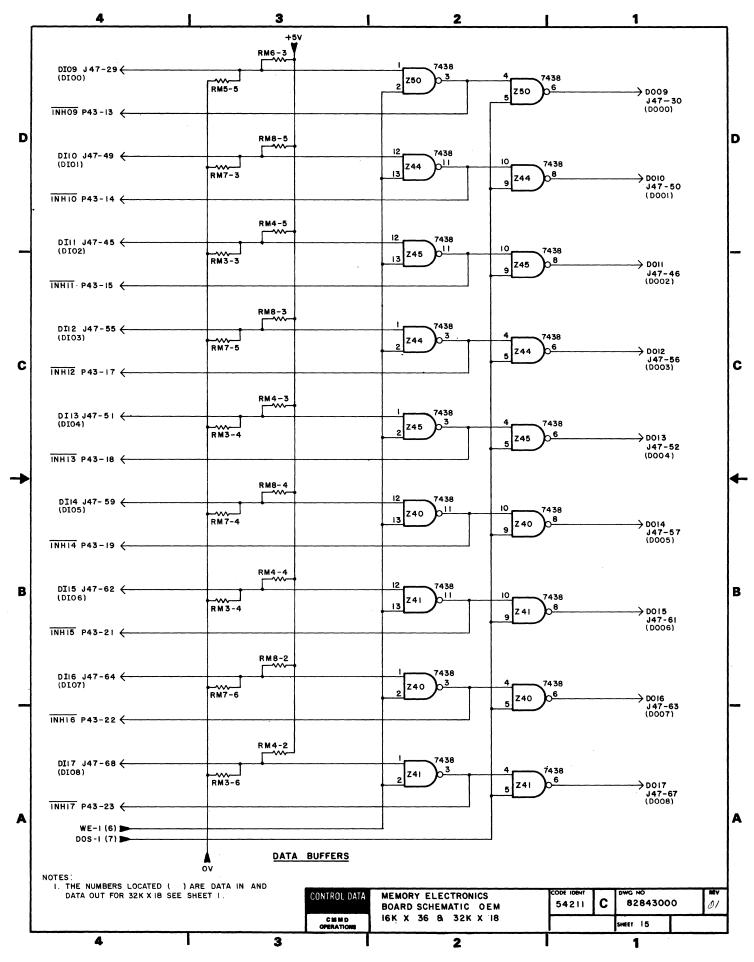


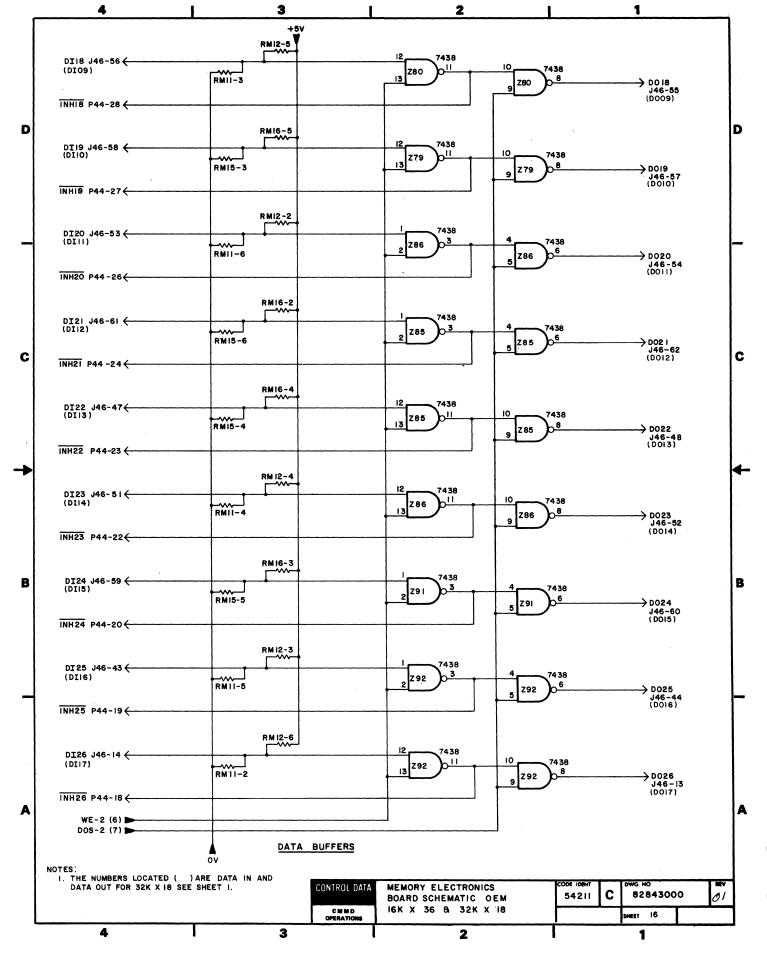


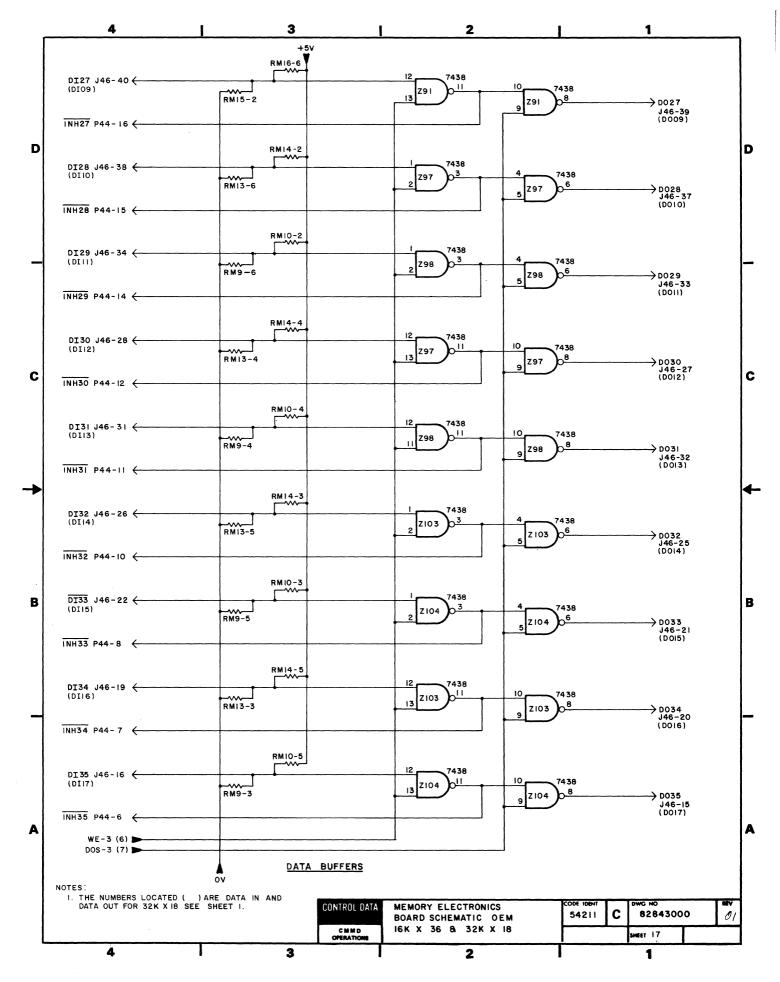


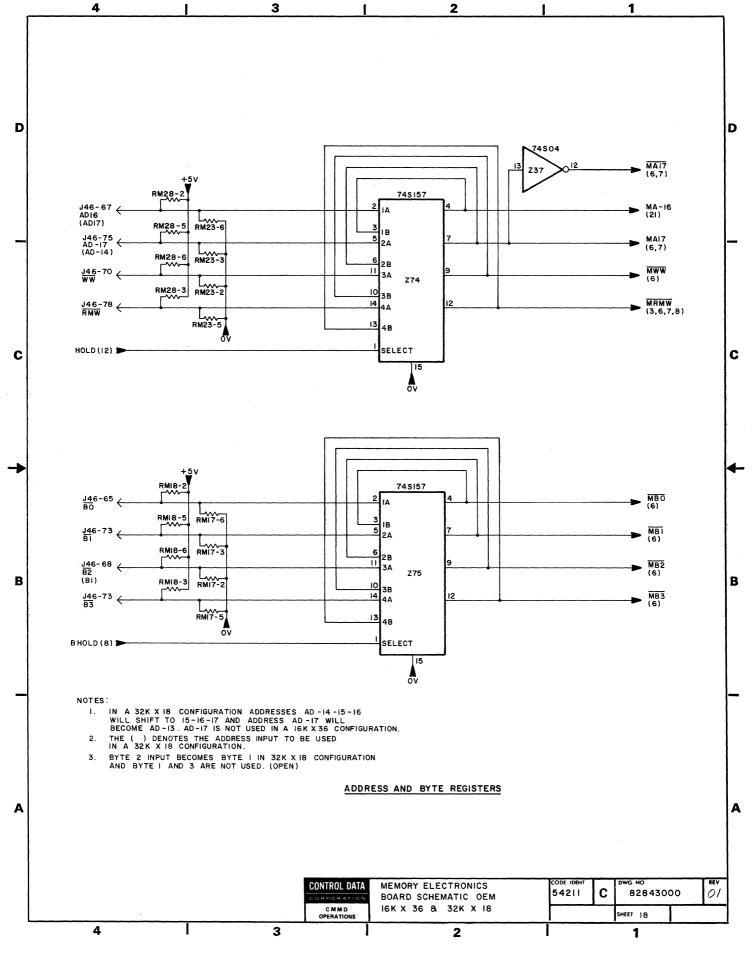


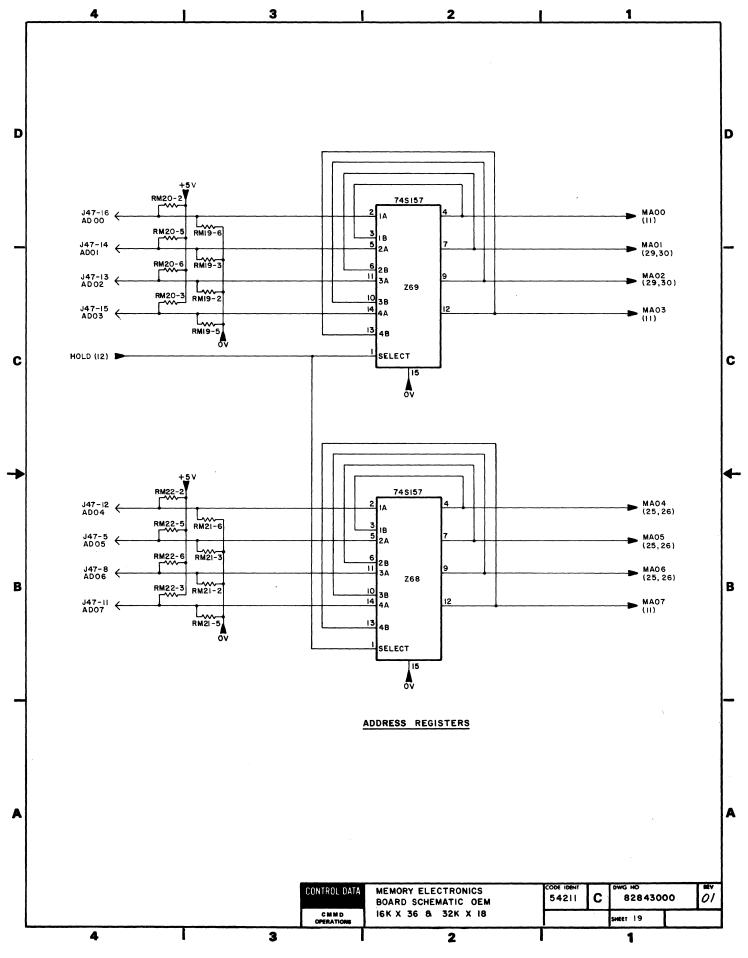


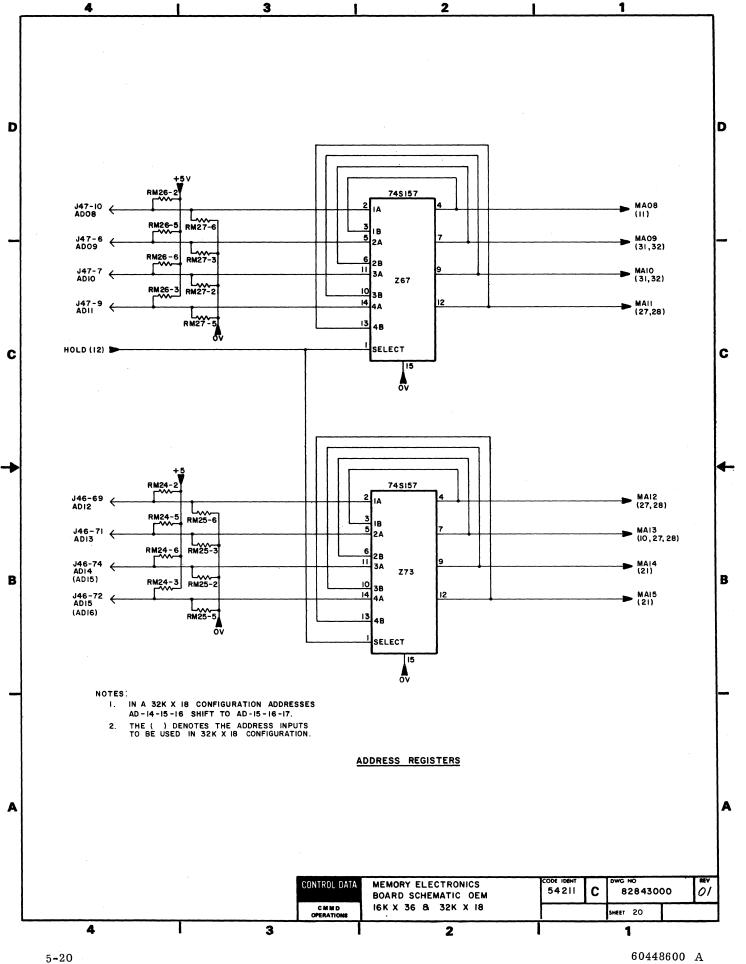


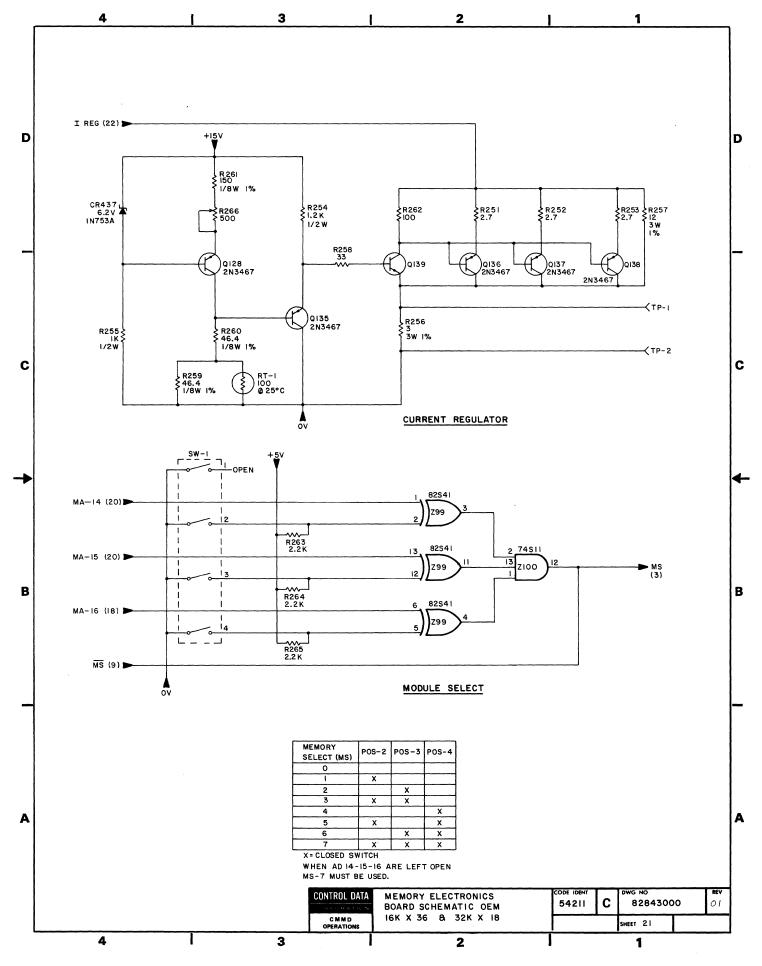


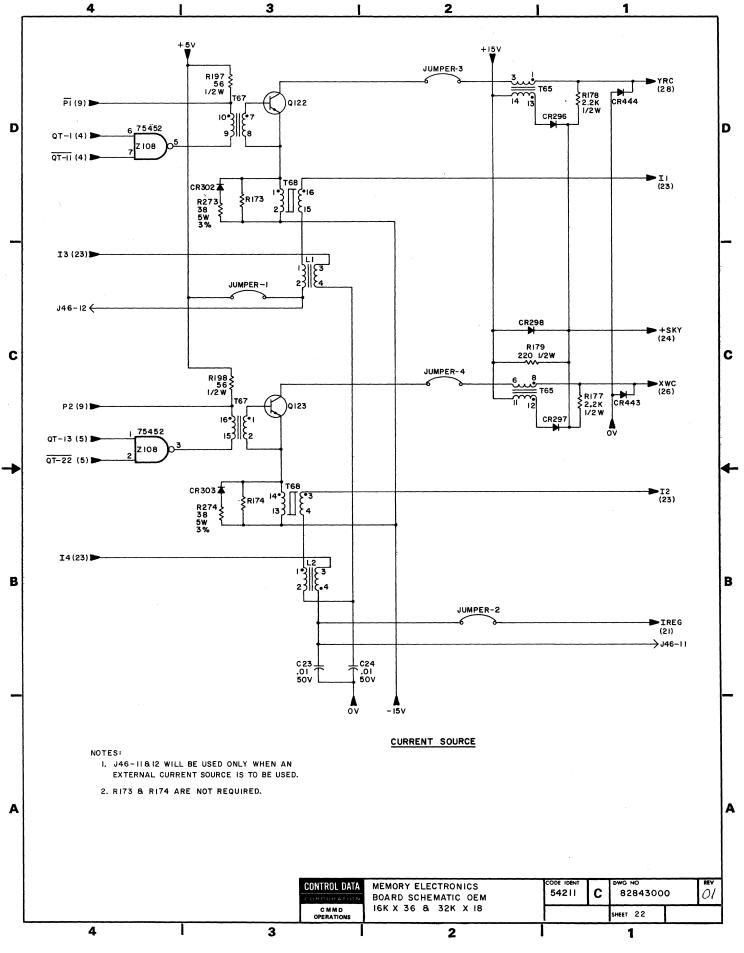


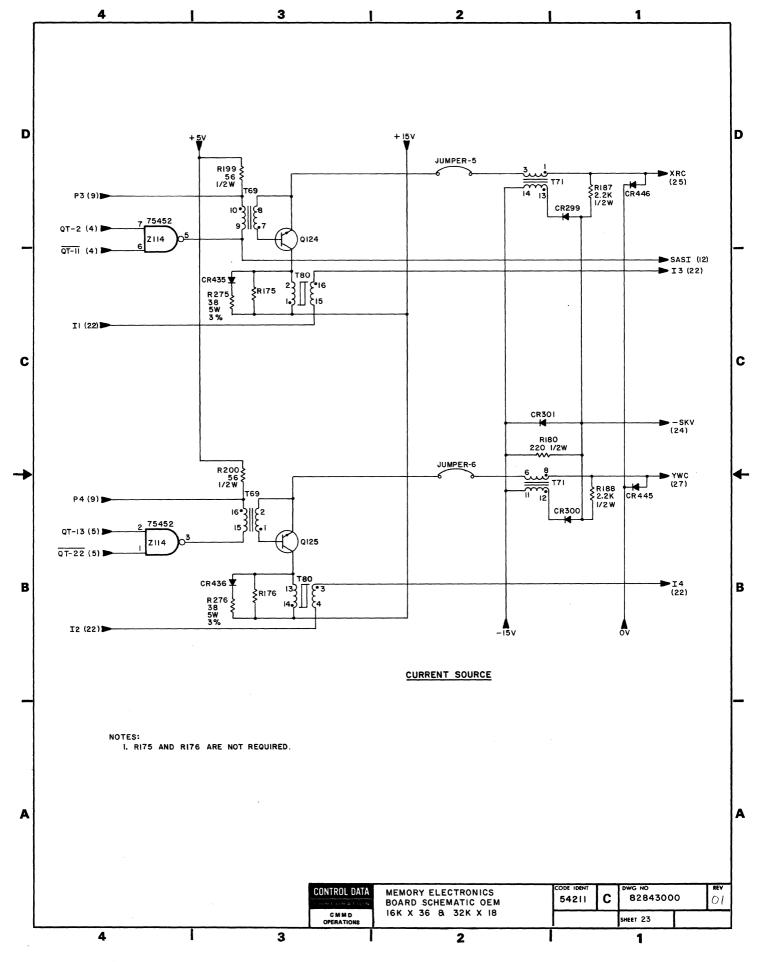


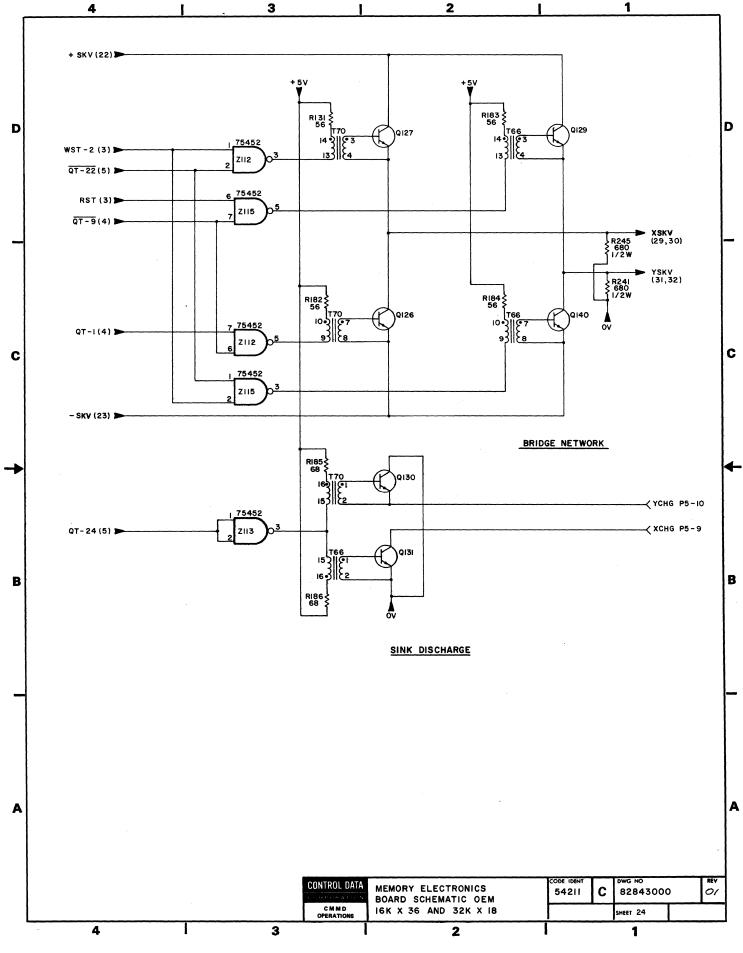


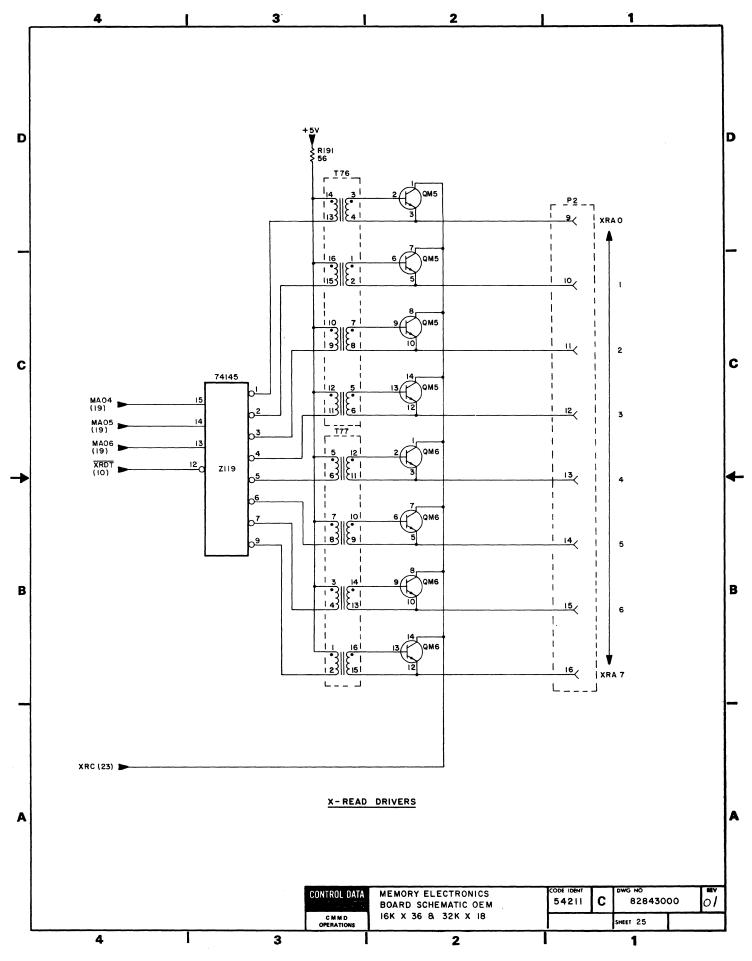


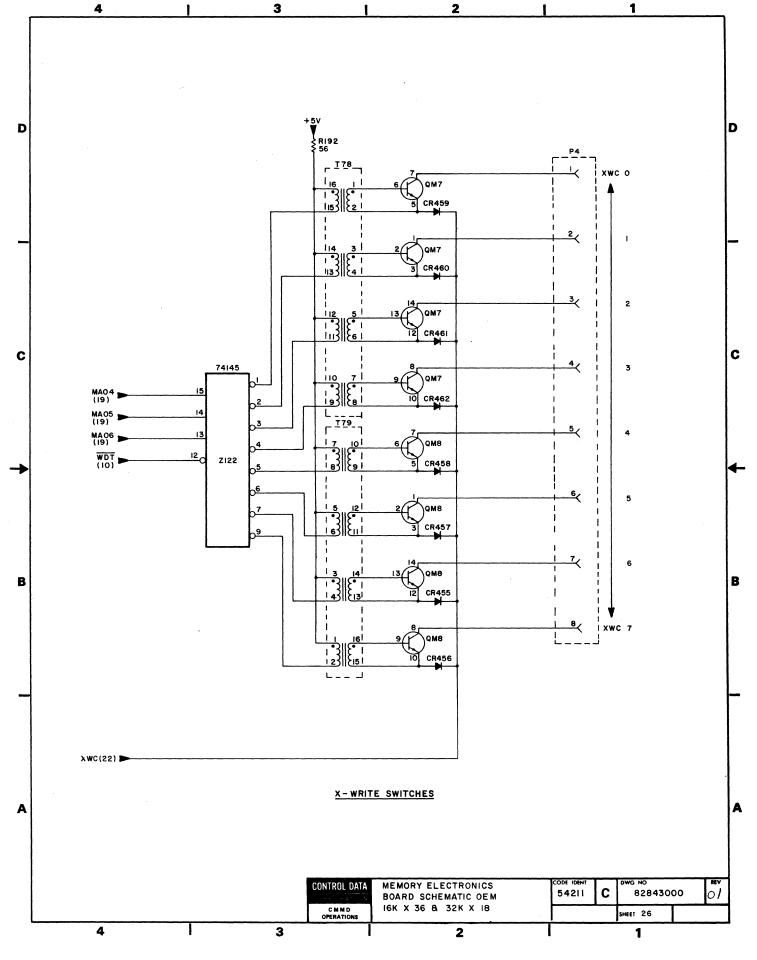


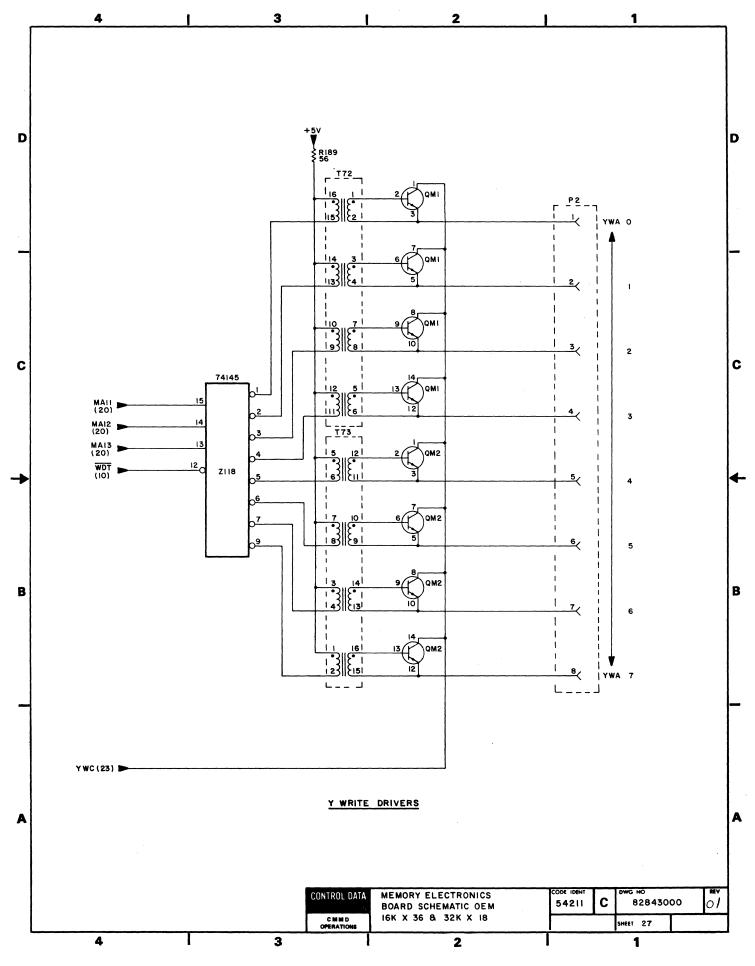


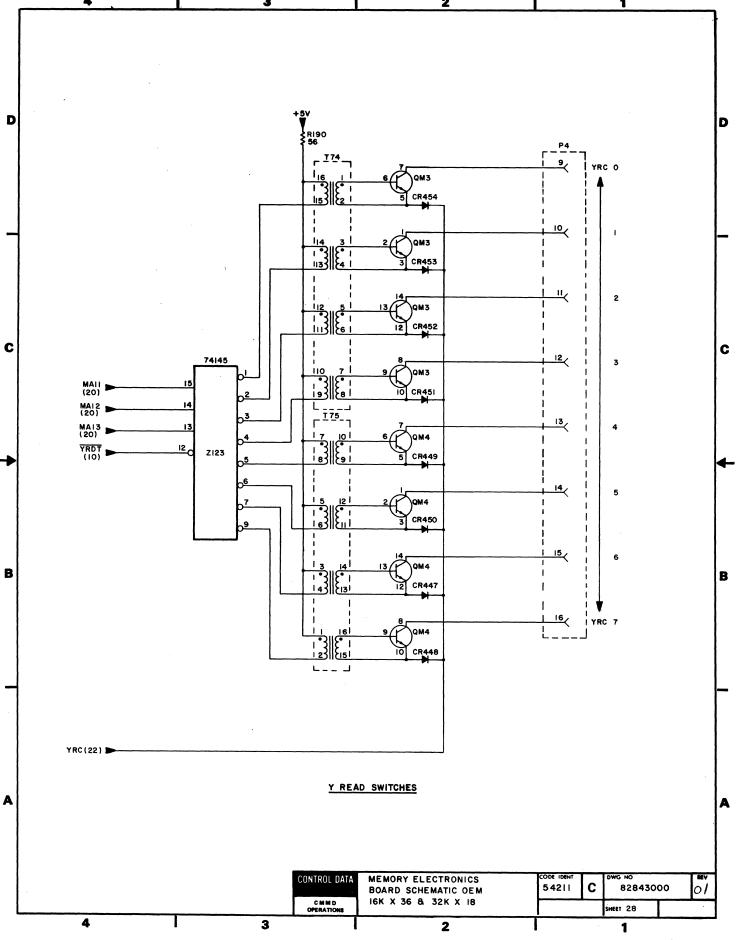


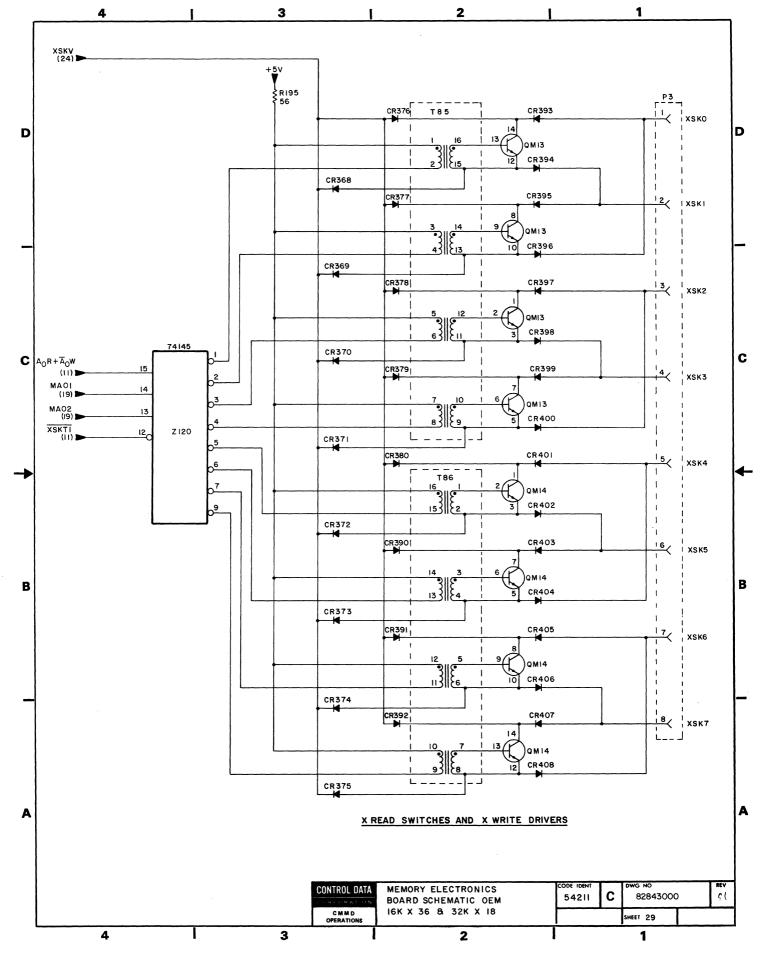


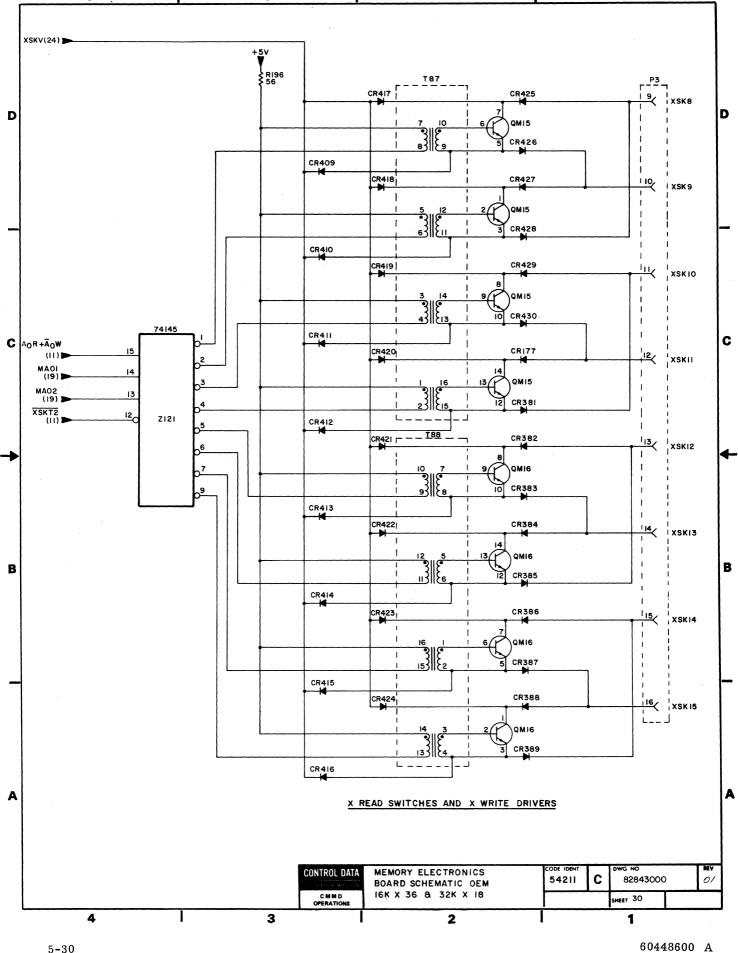


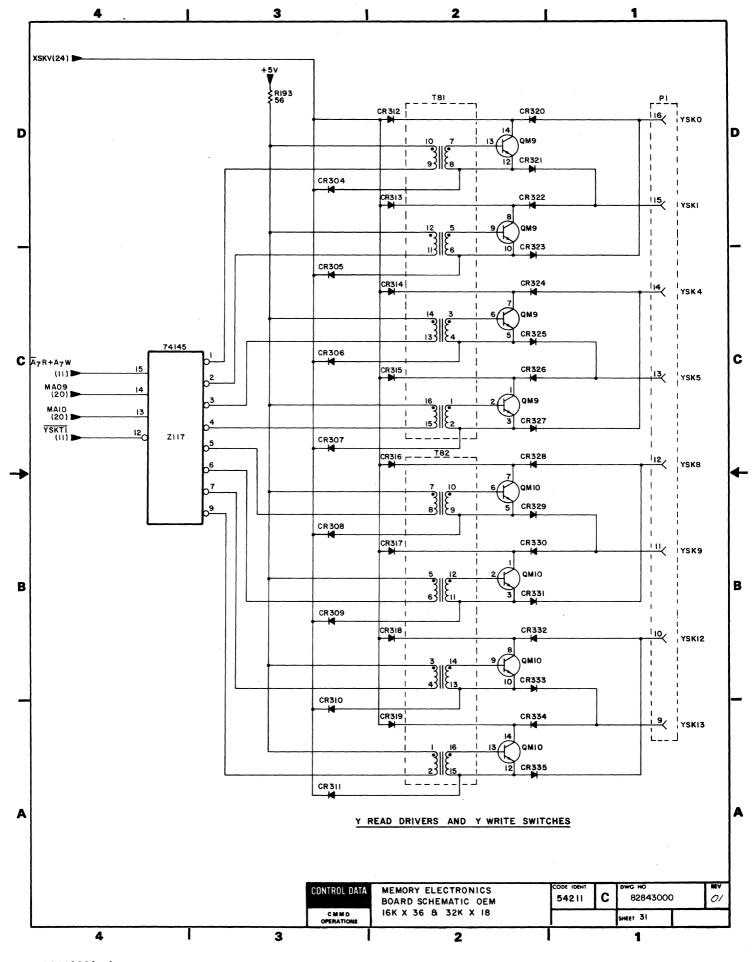


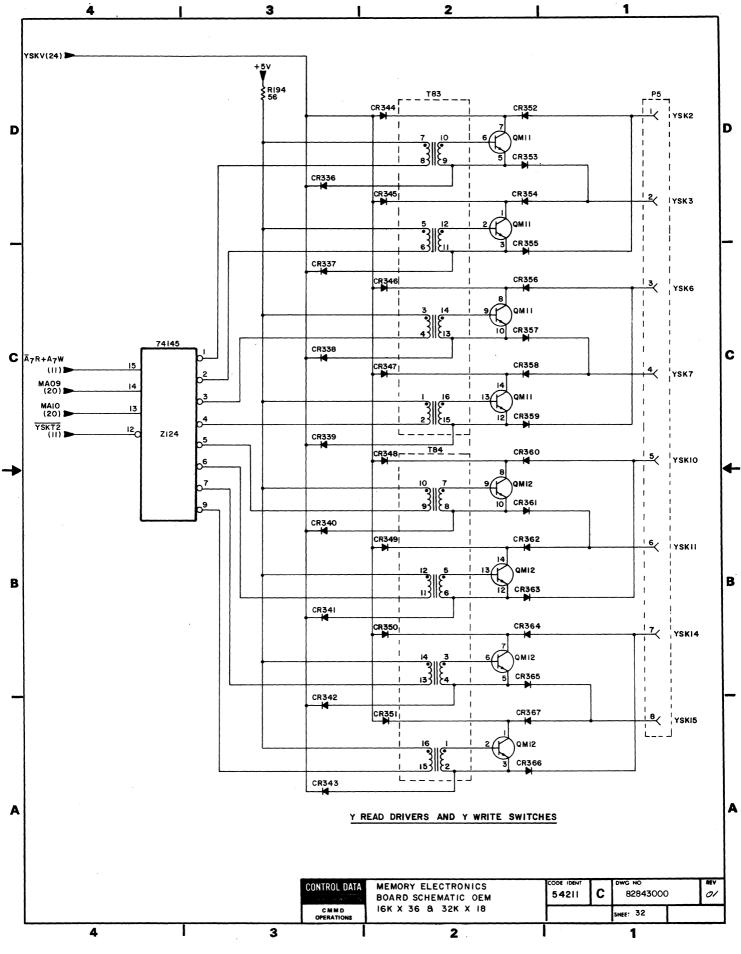


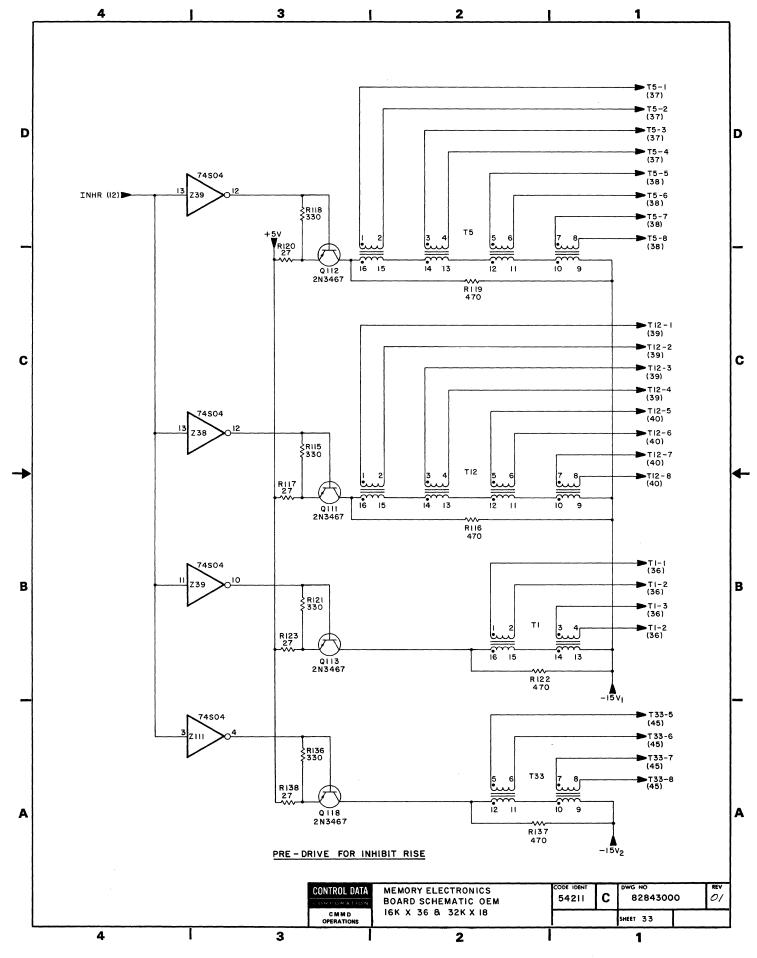


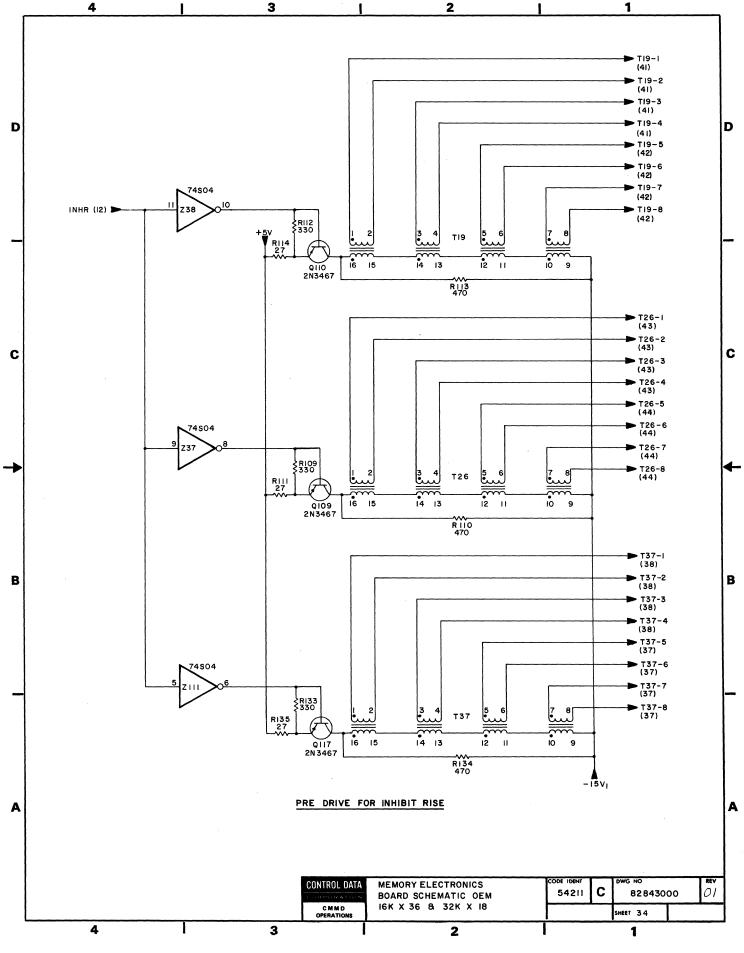


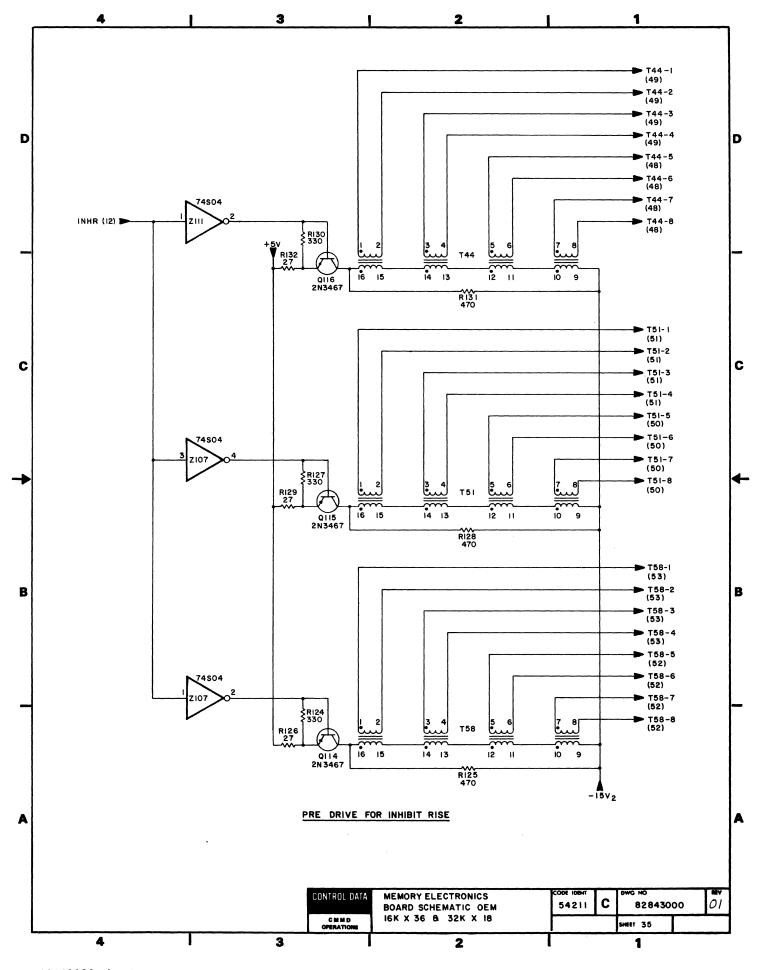


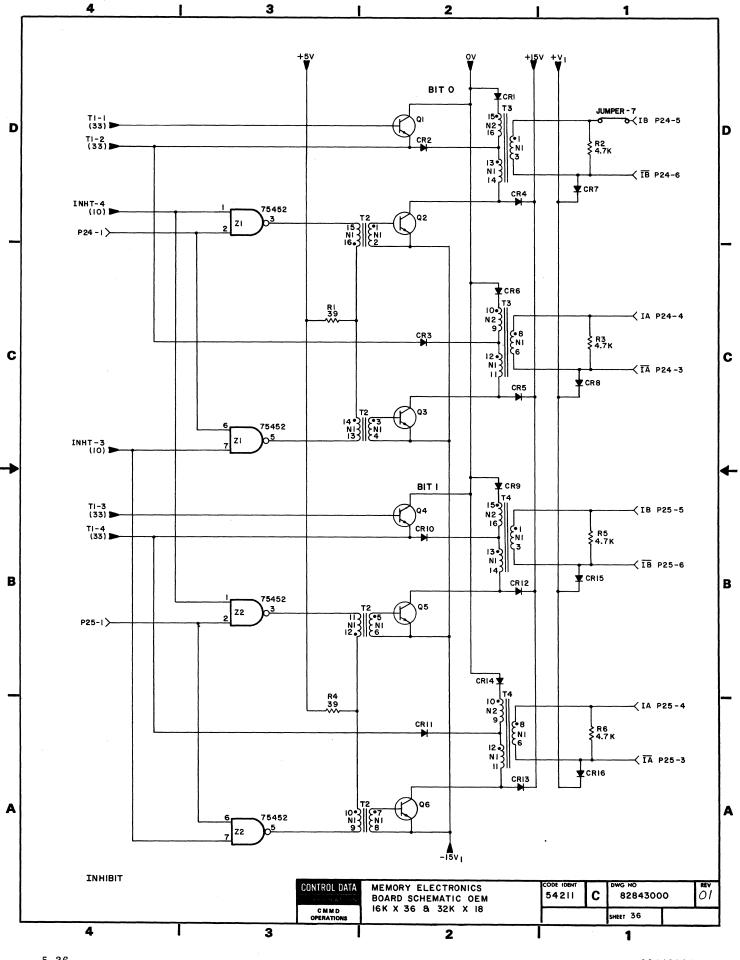


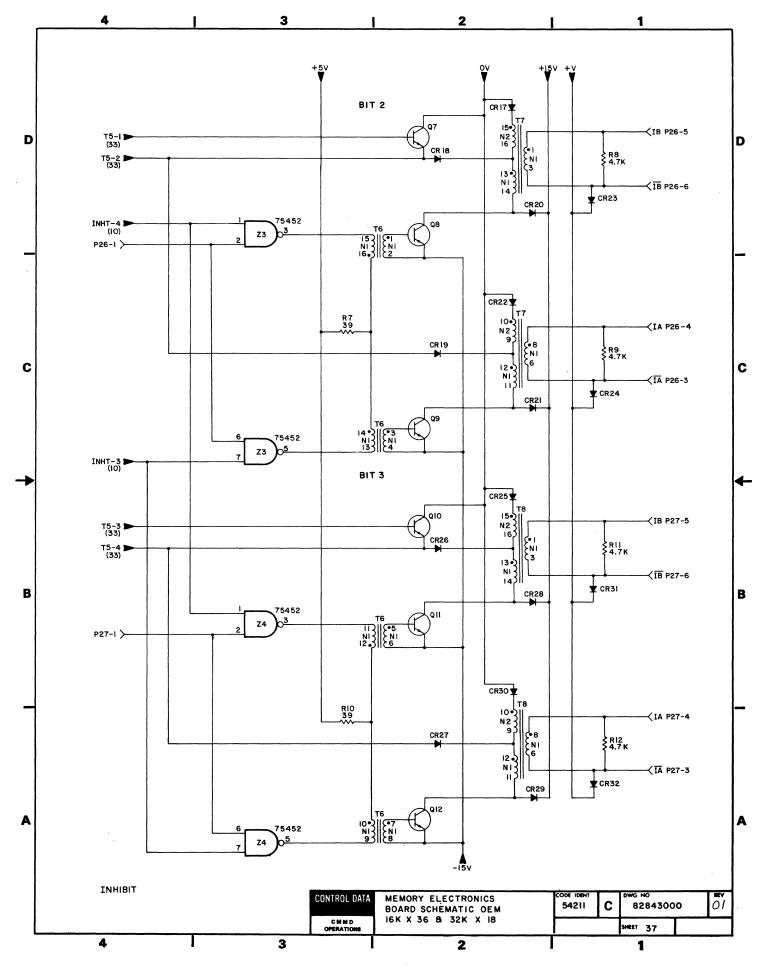


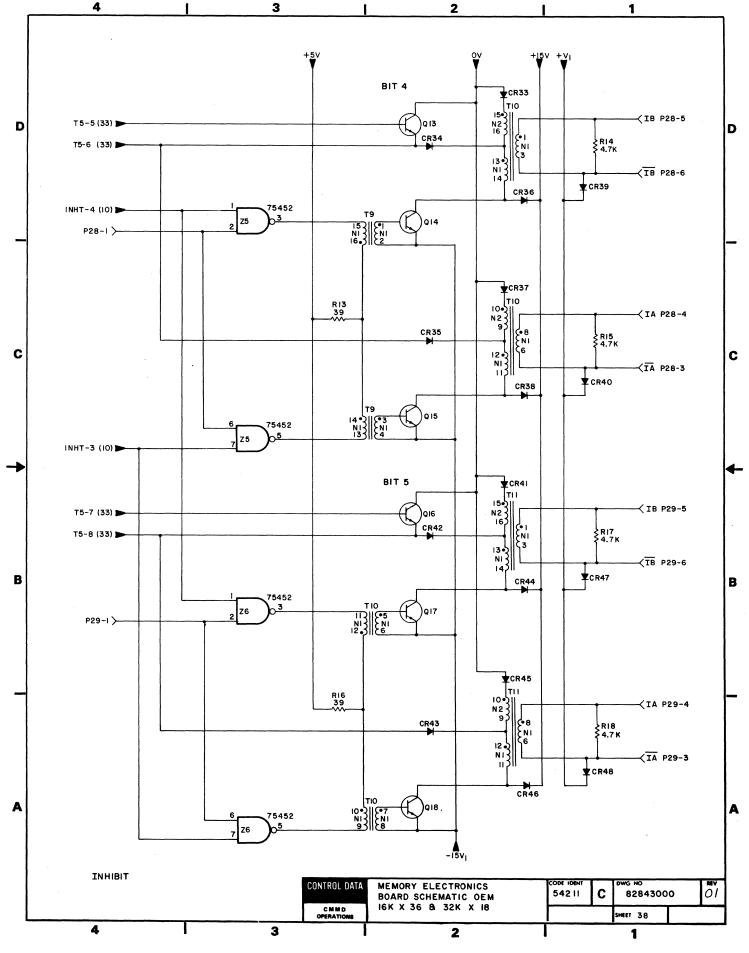


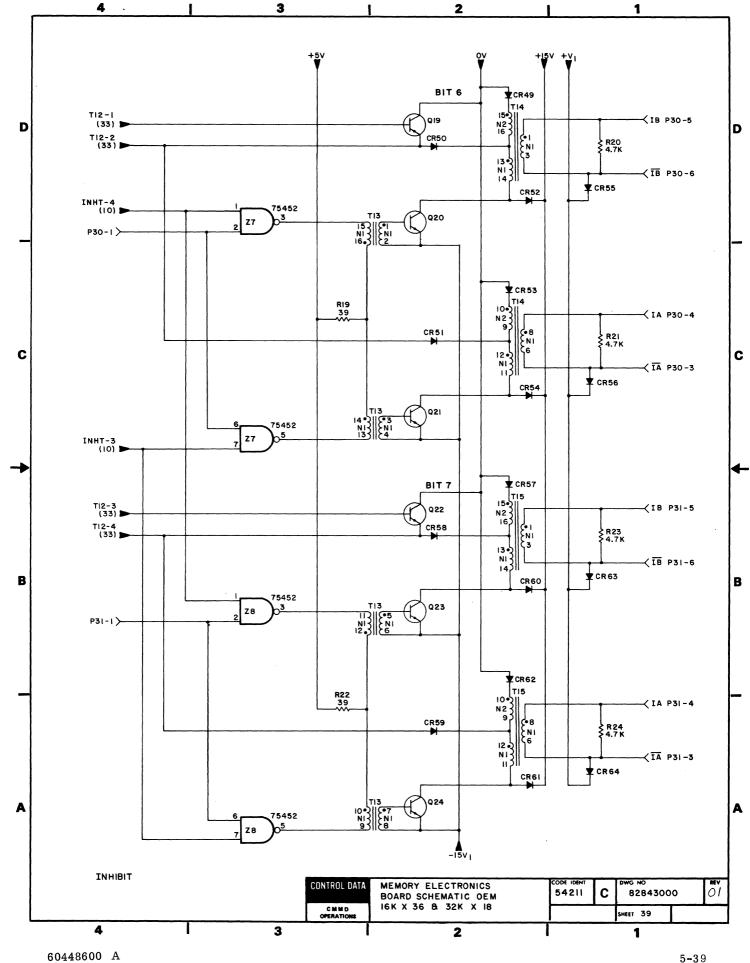


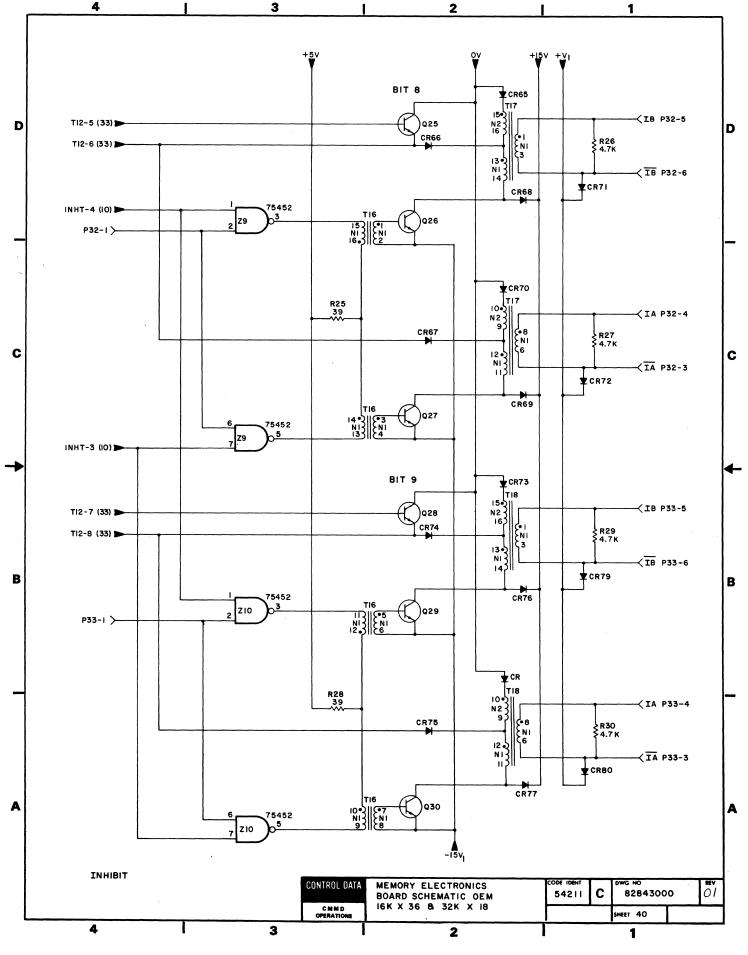


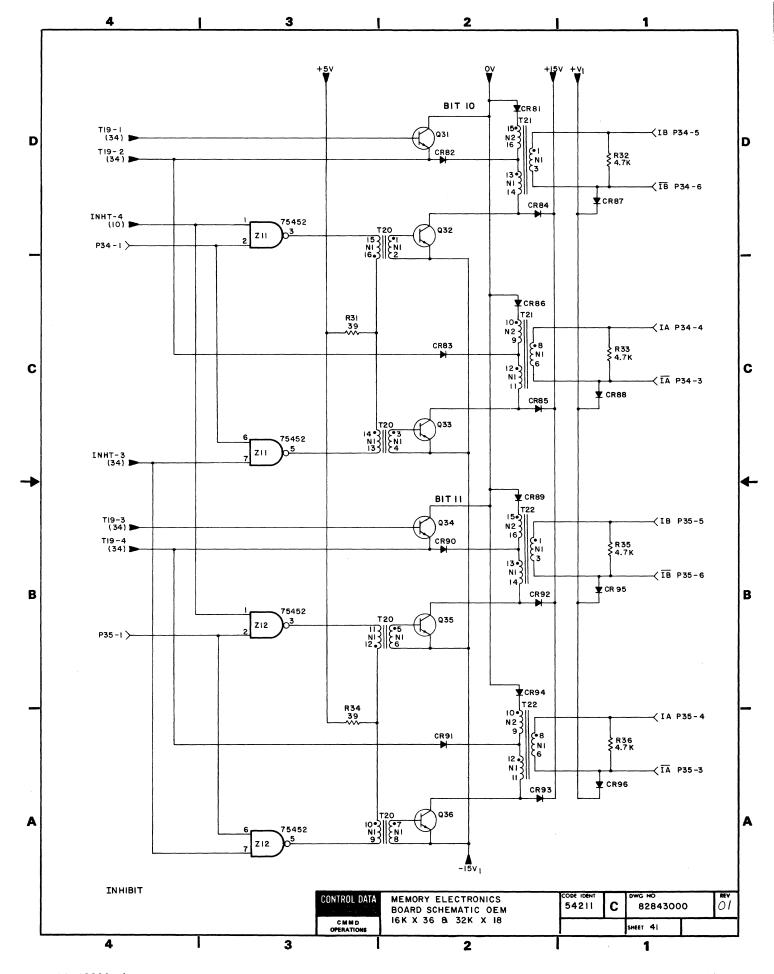


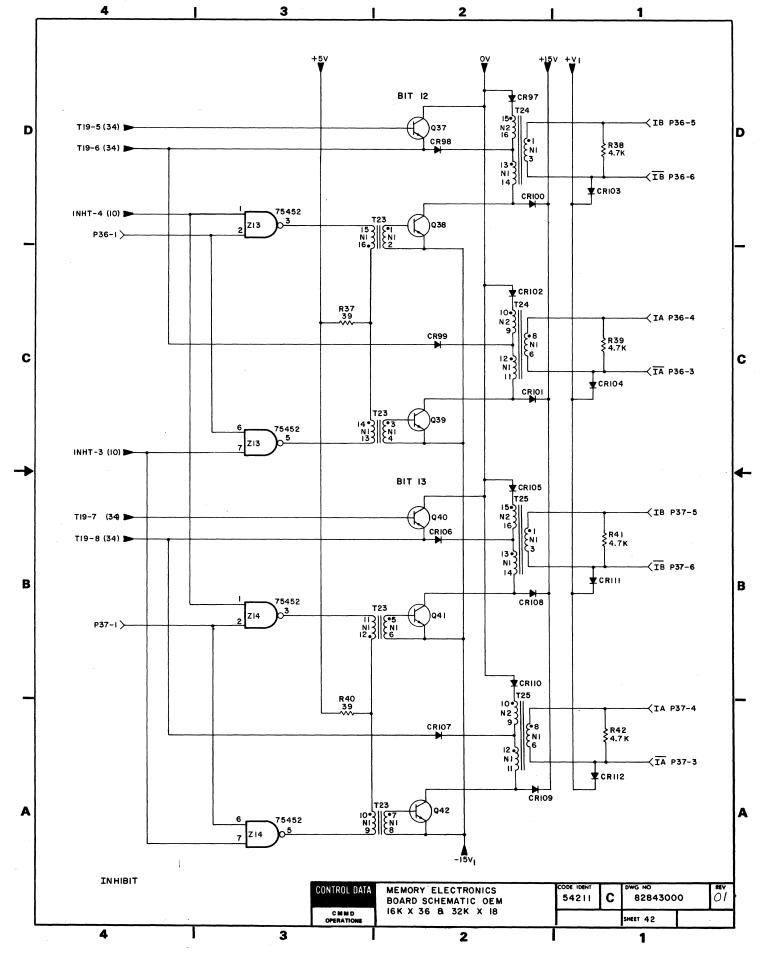


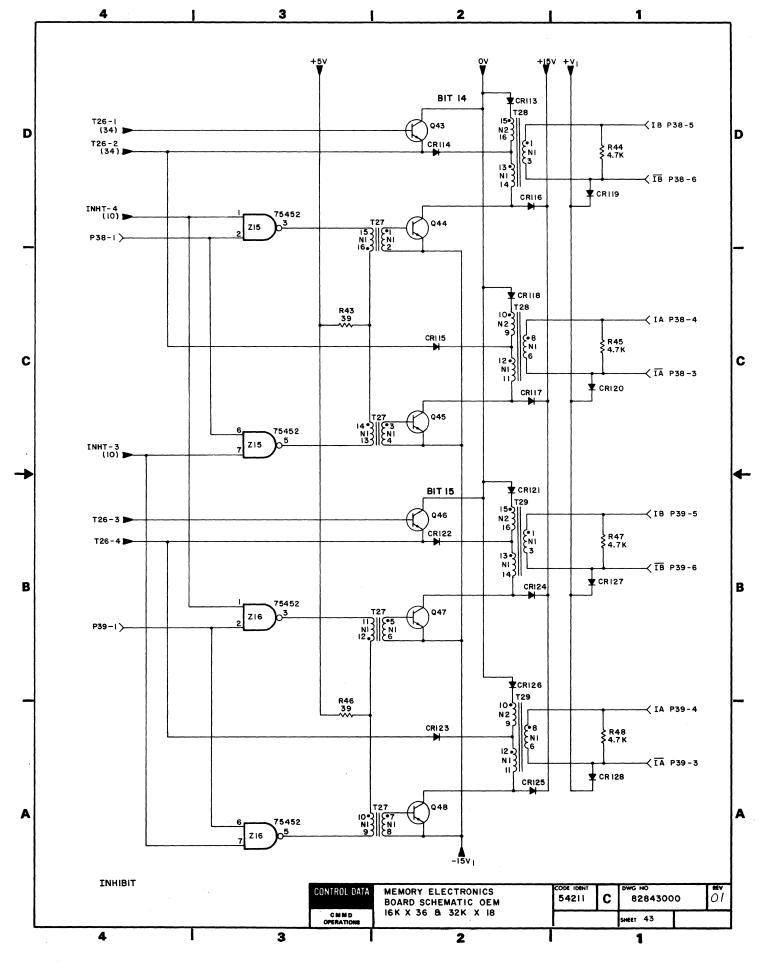


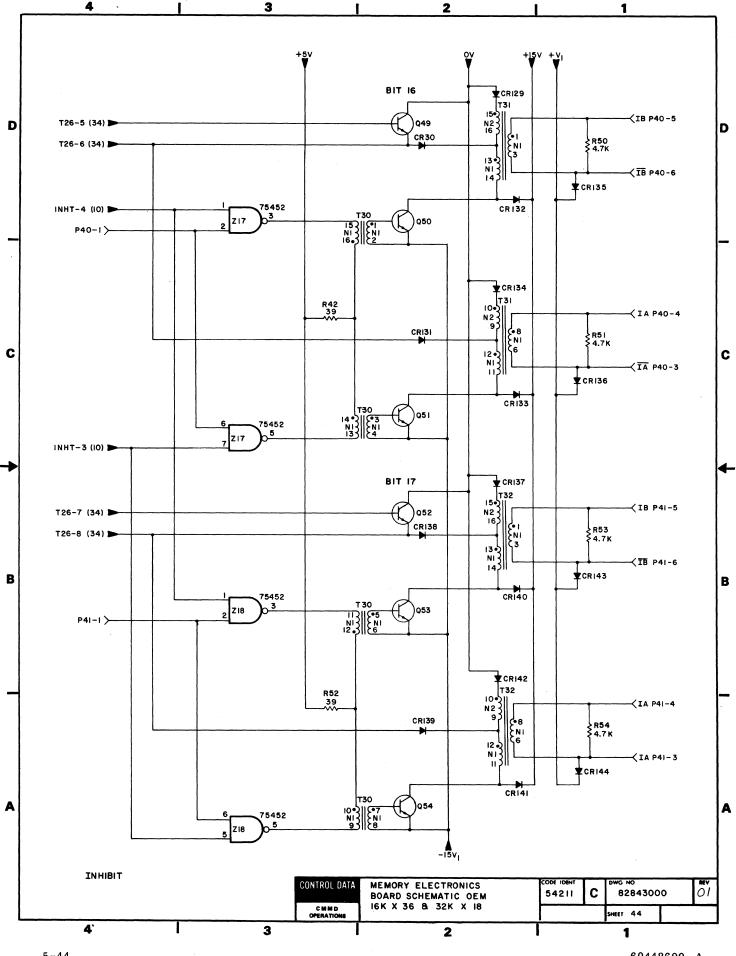


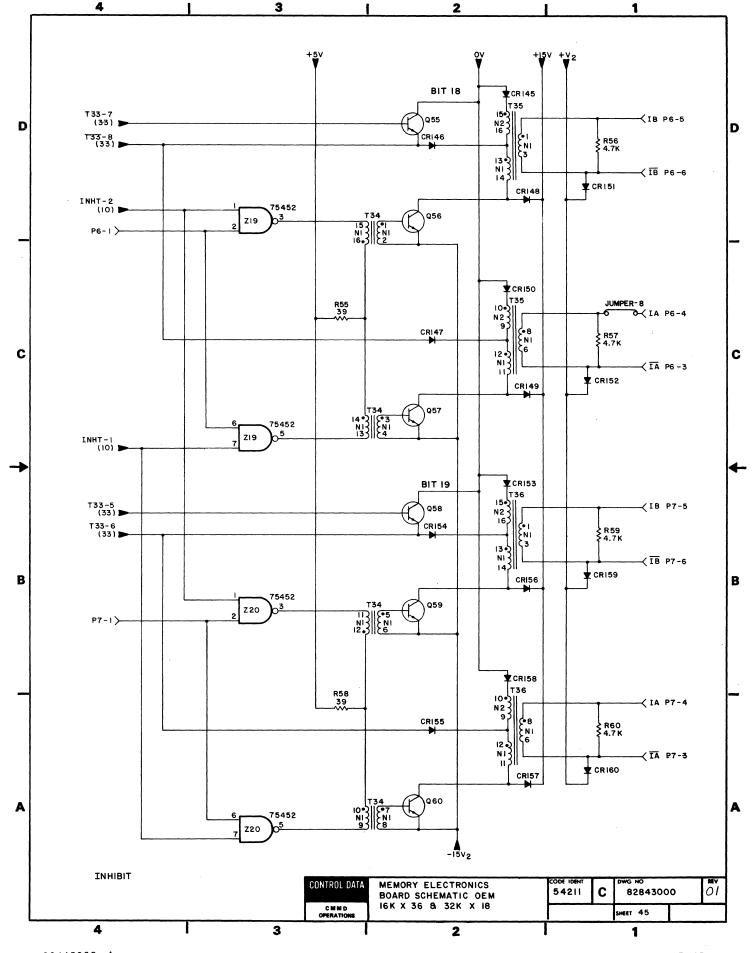


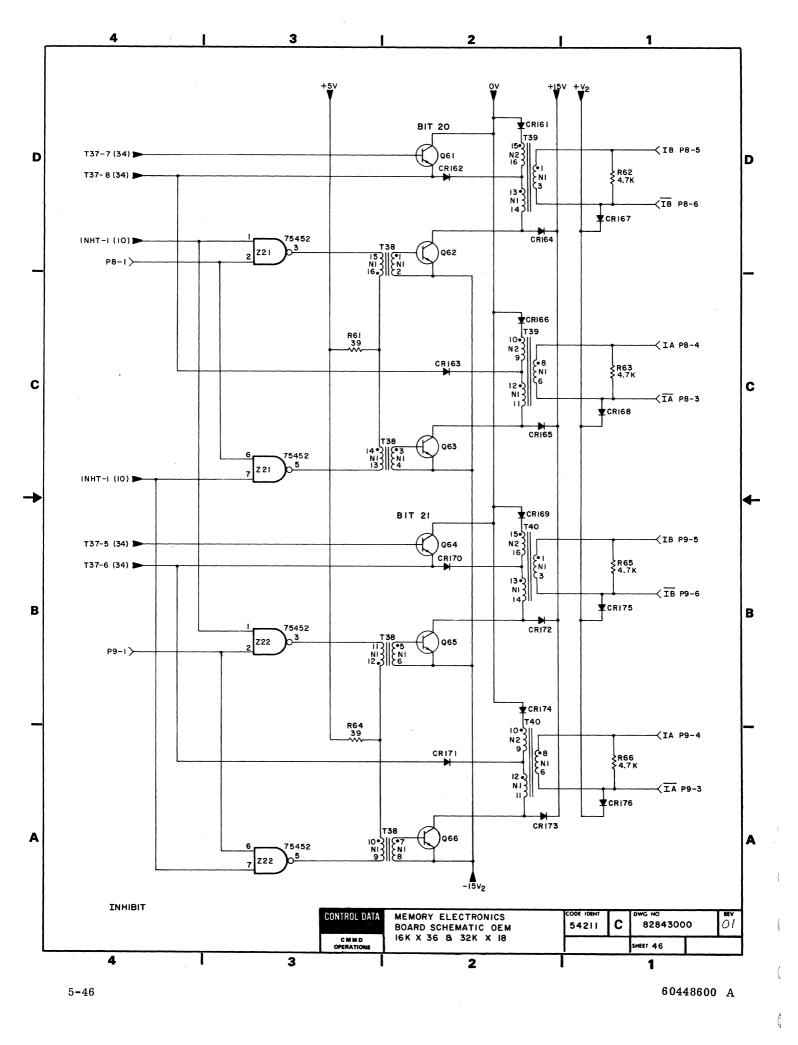


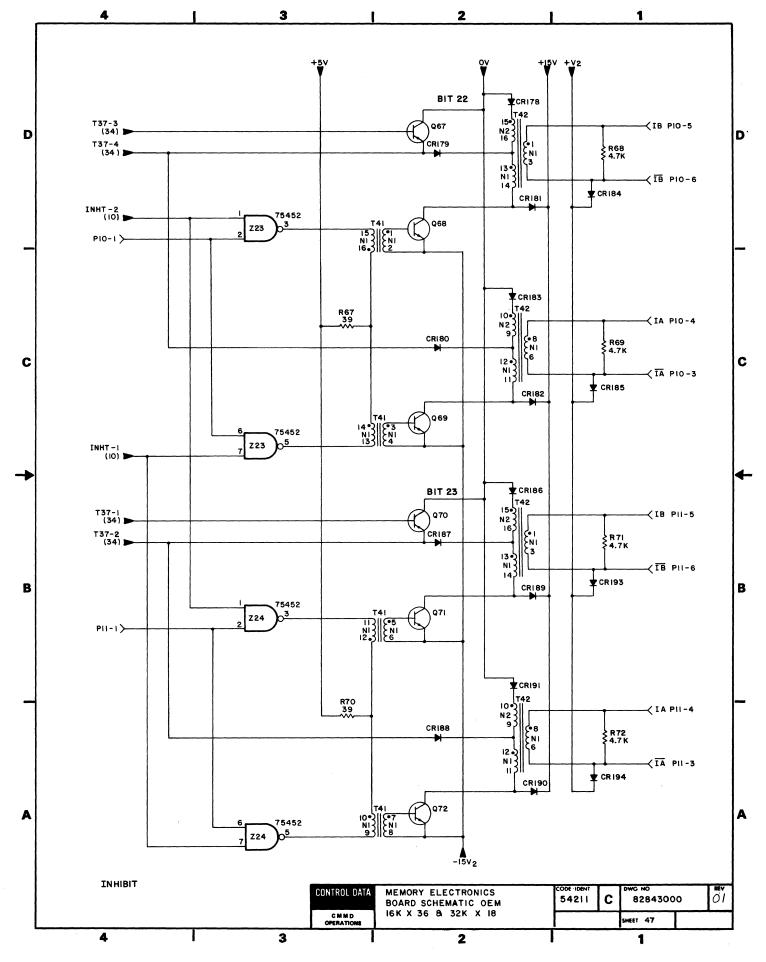


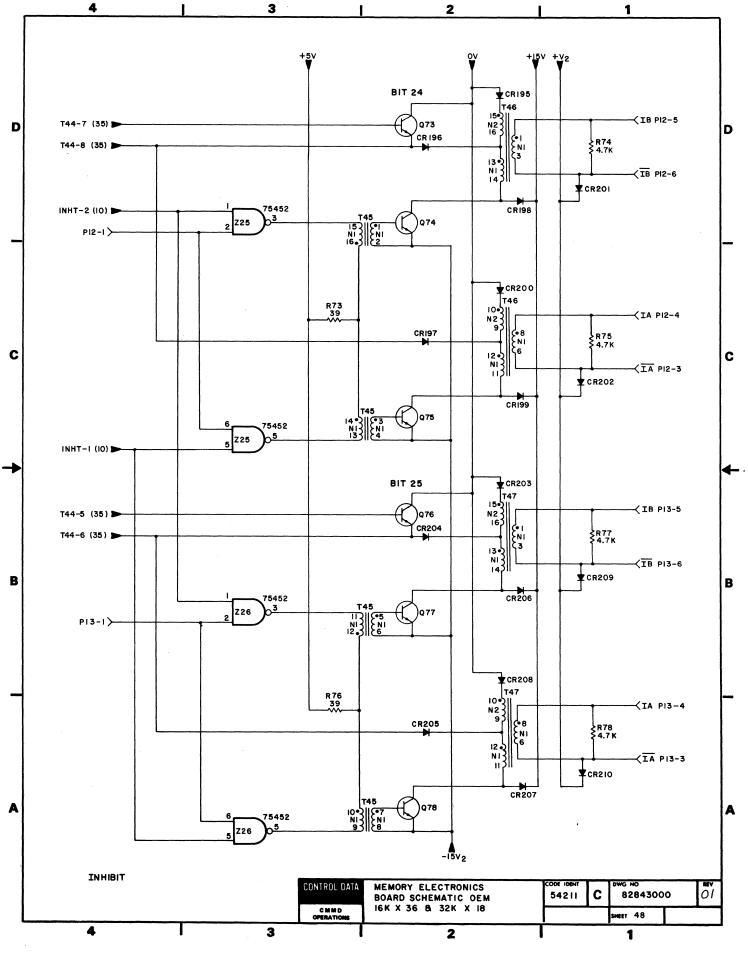


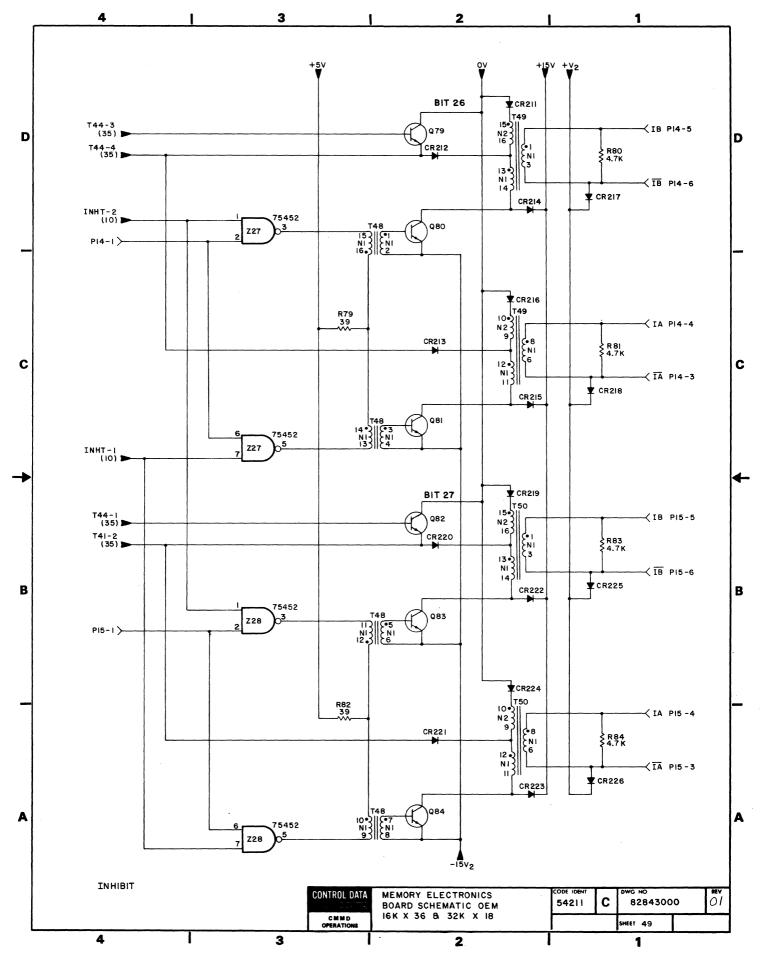


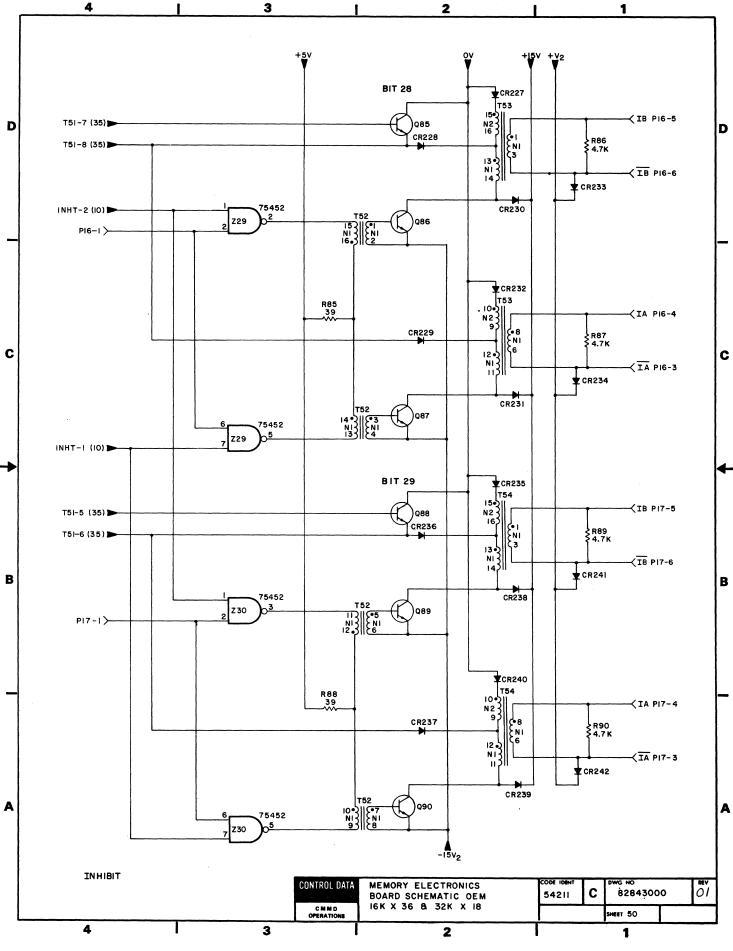


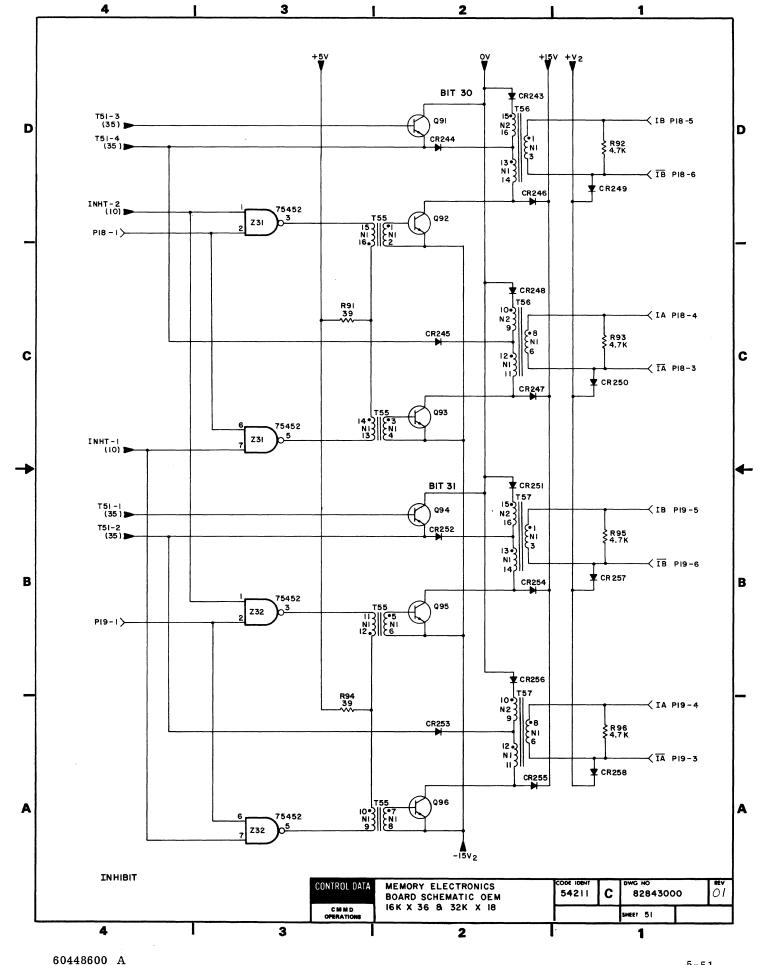


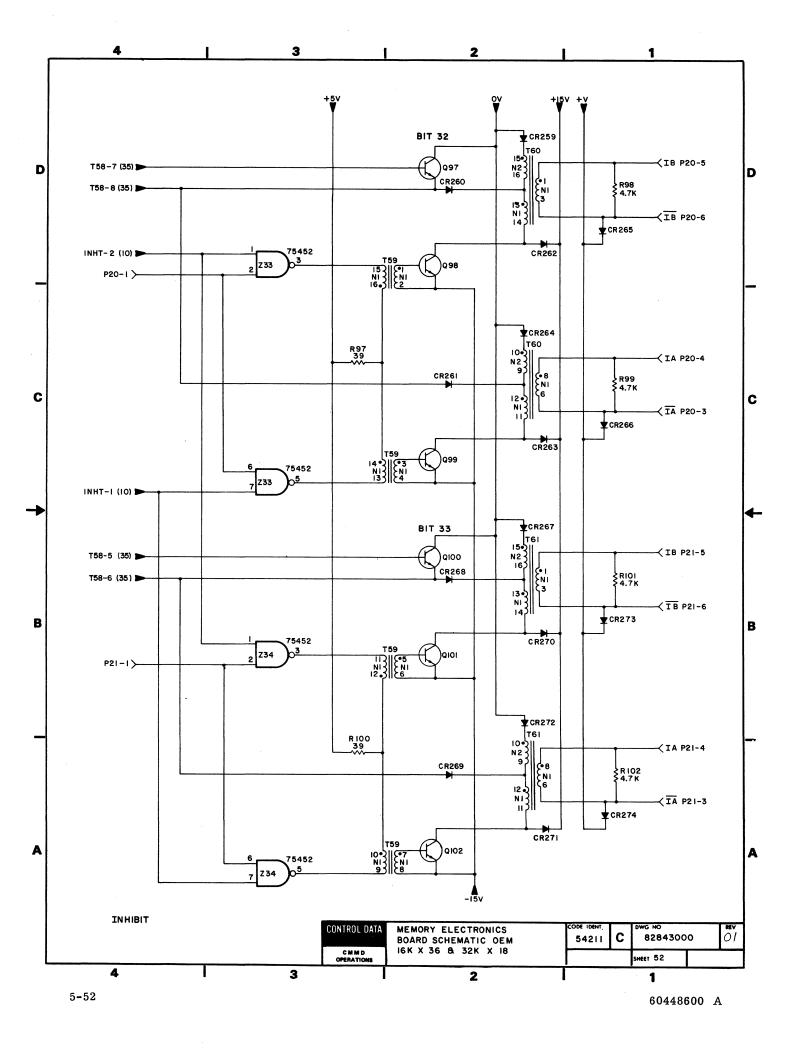


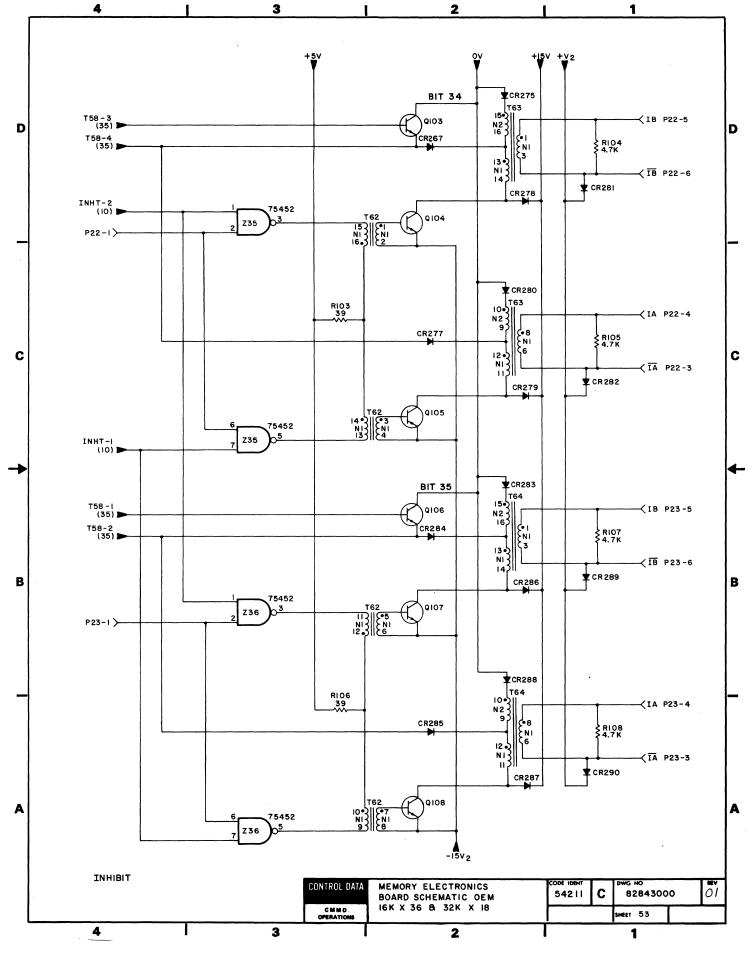




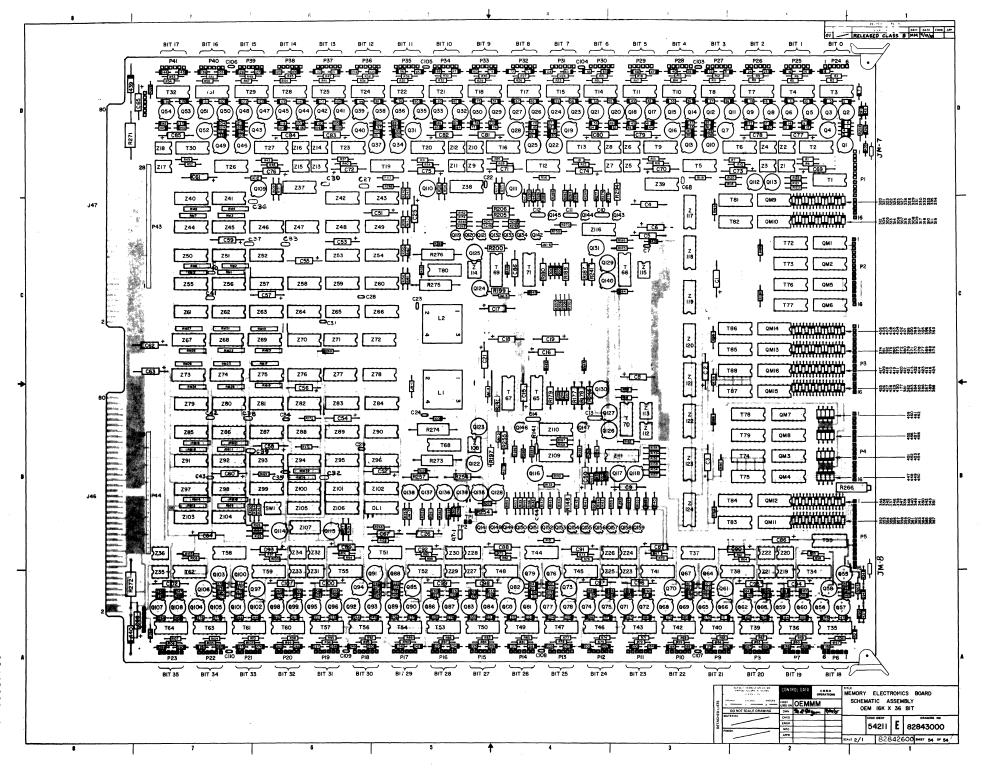




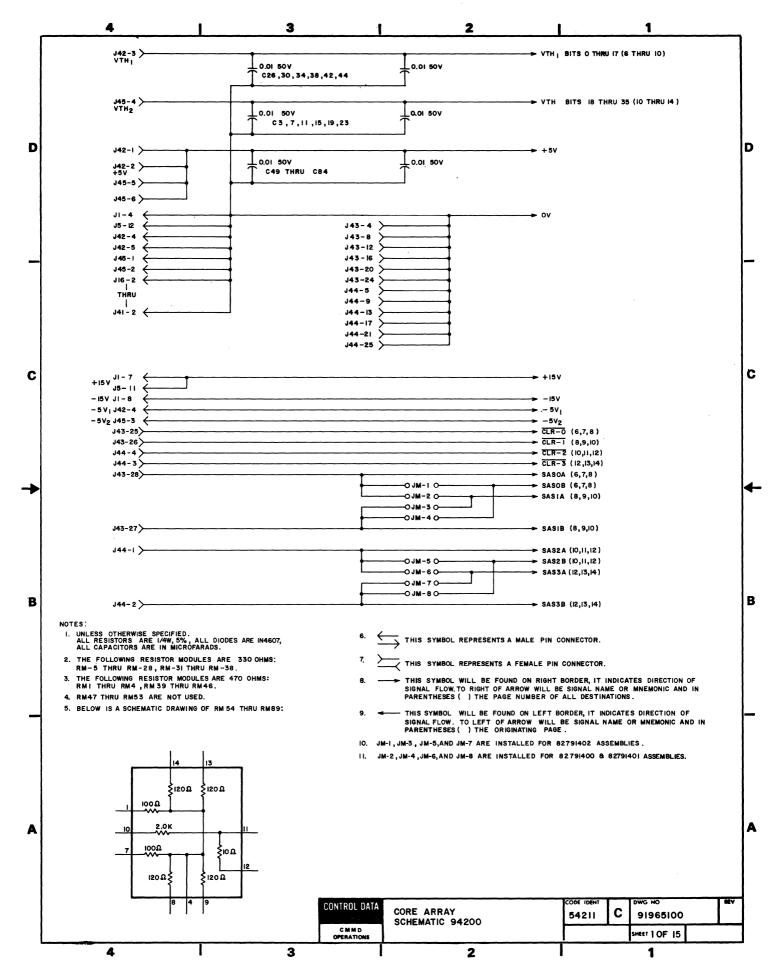


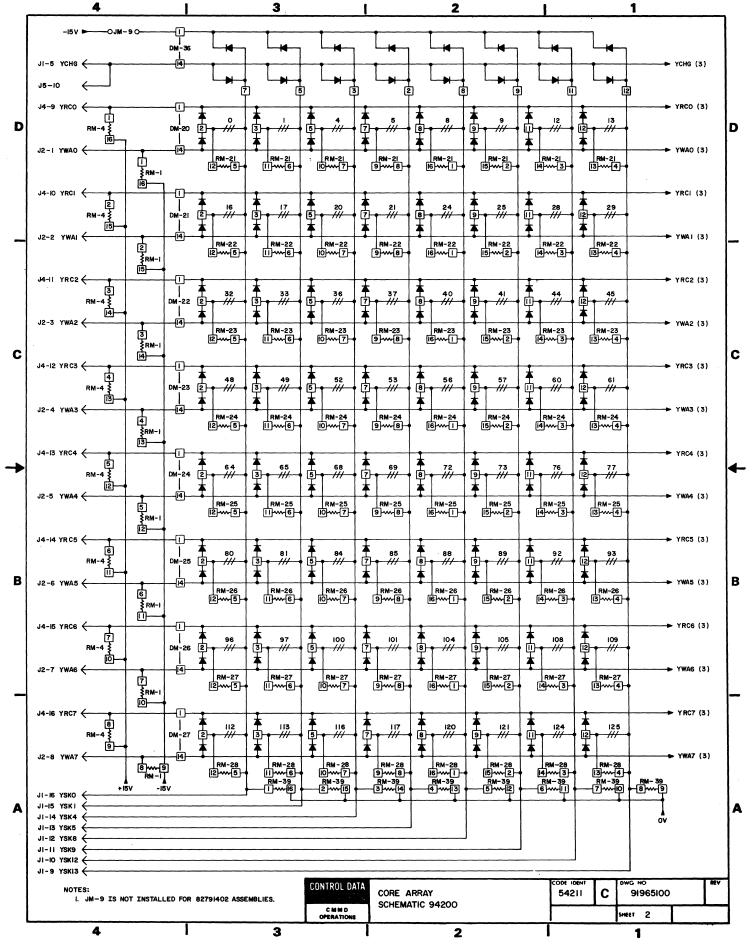


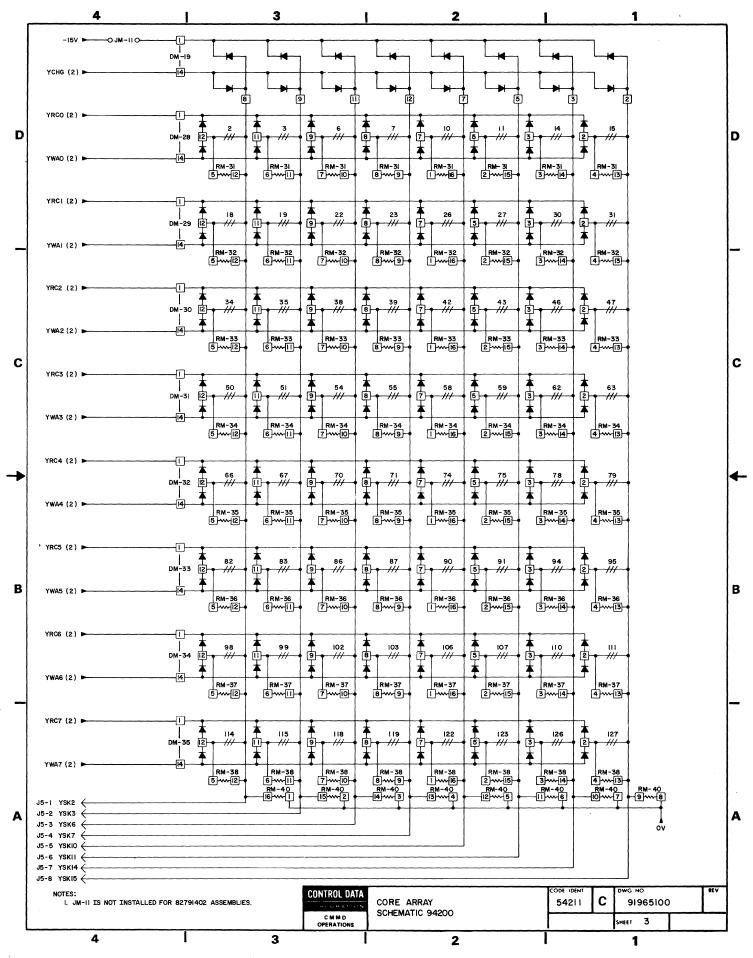


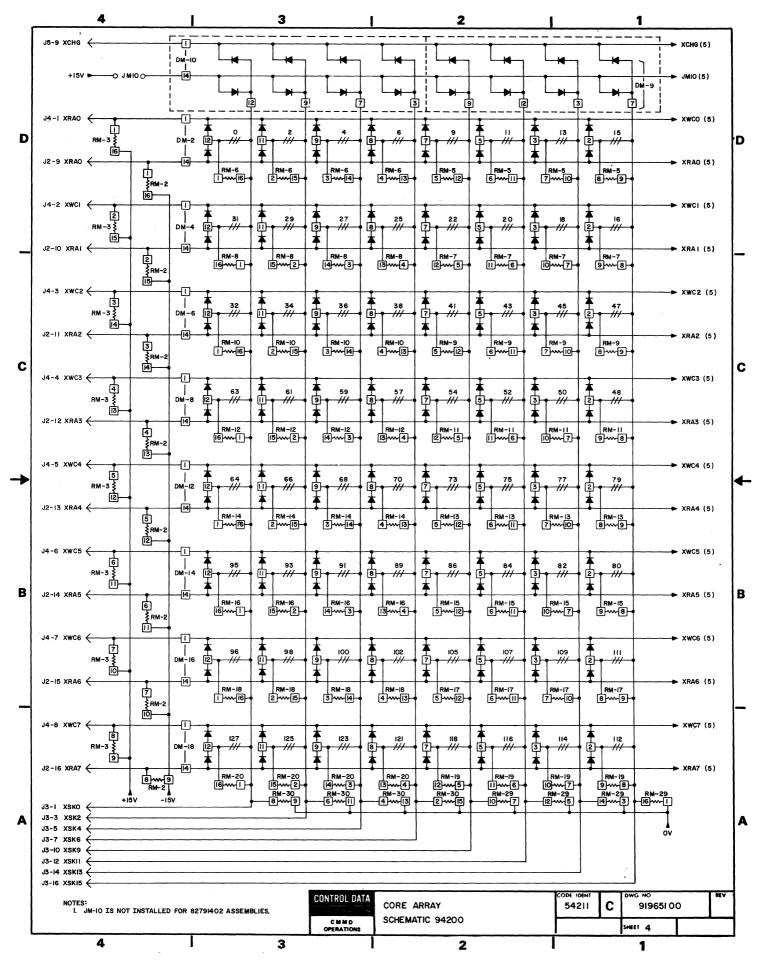


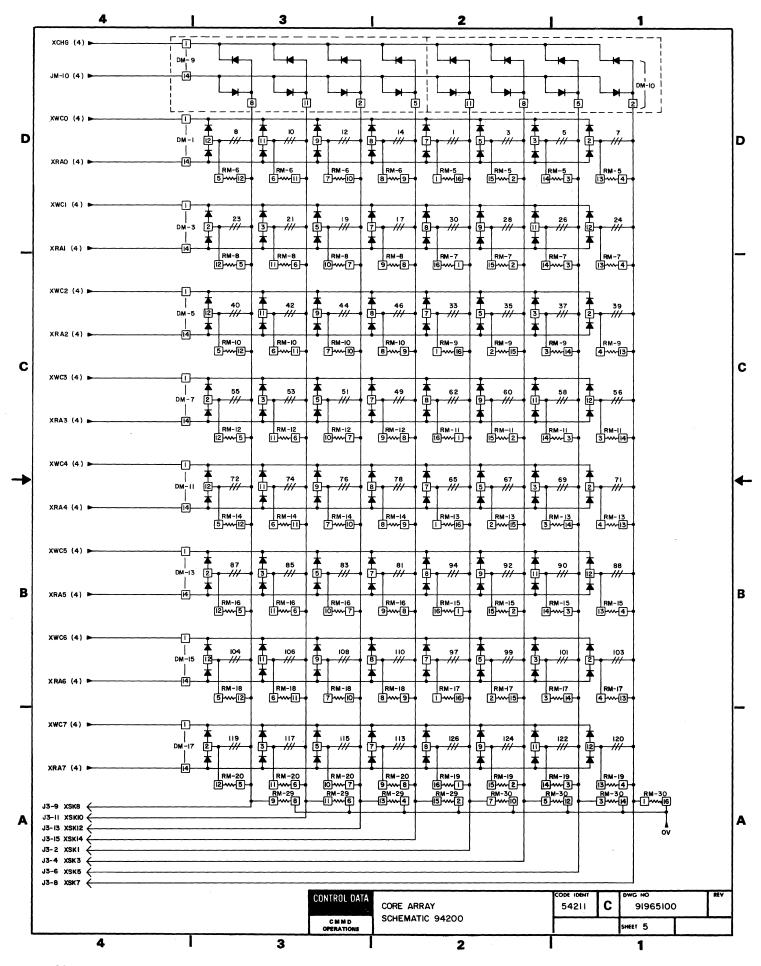
60448600 A

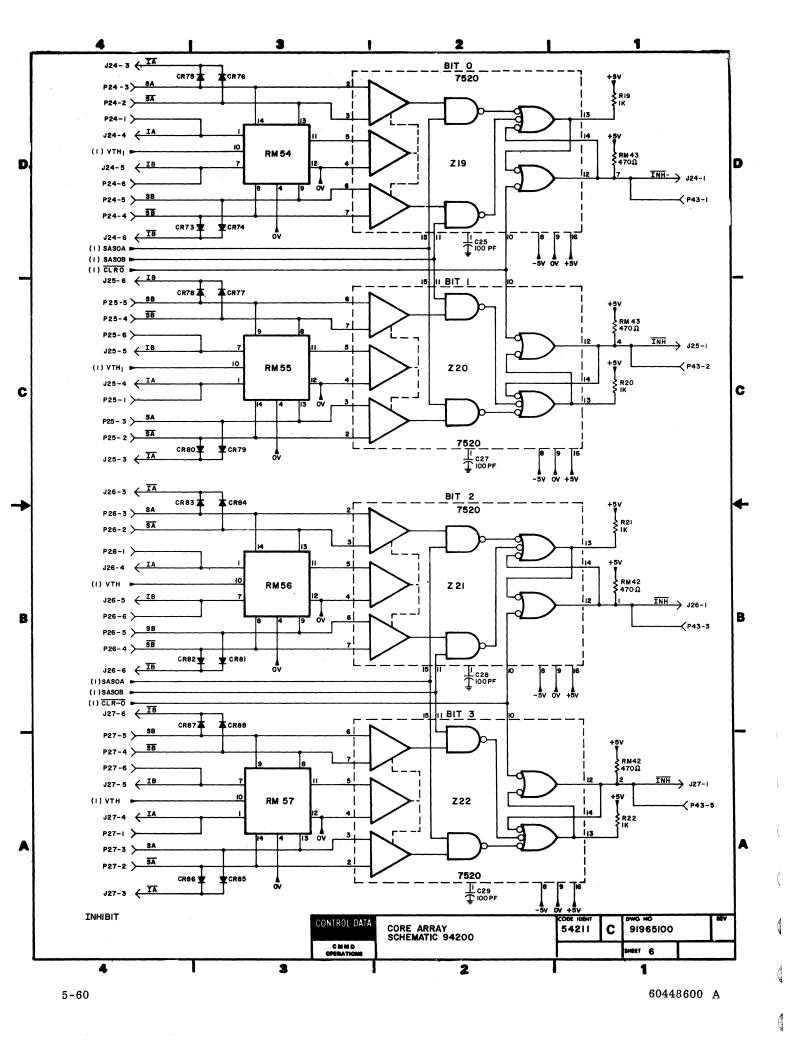


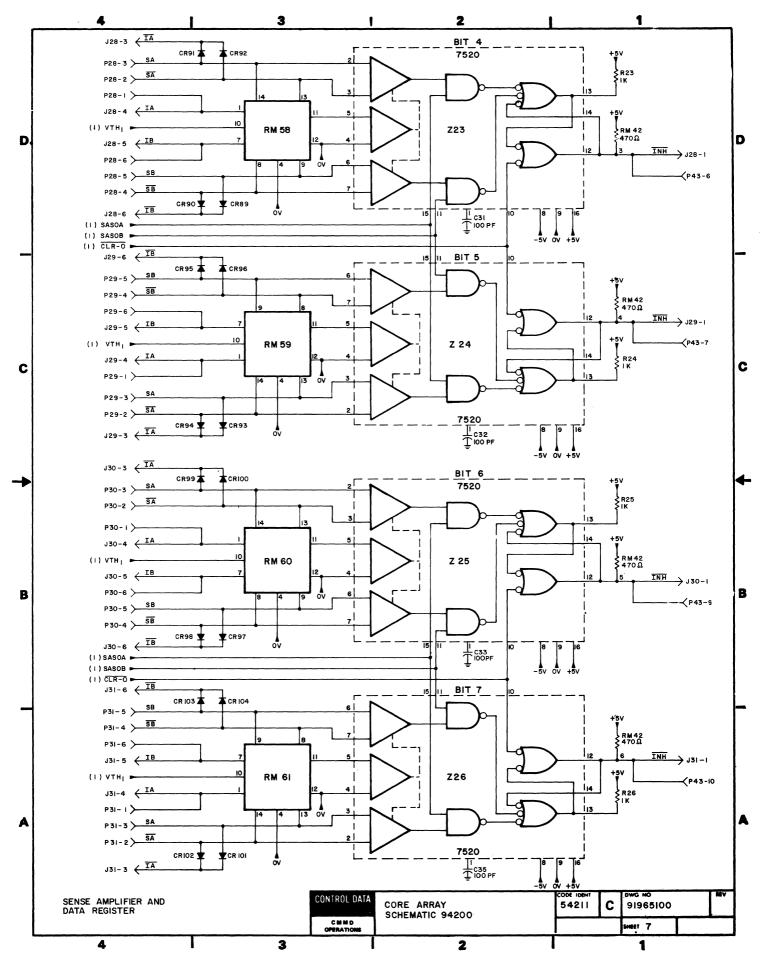


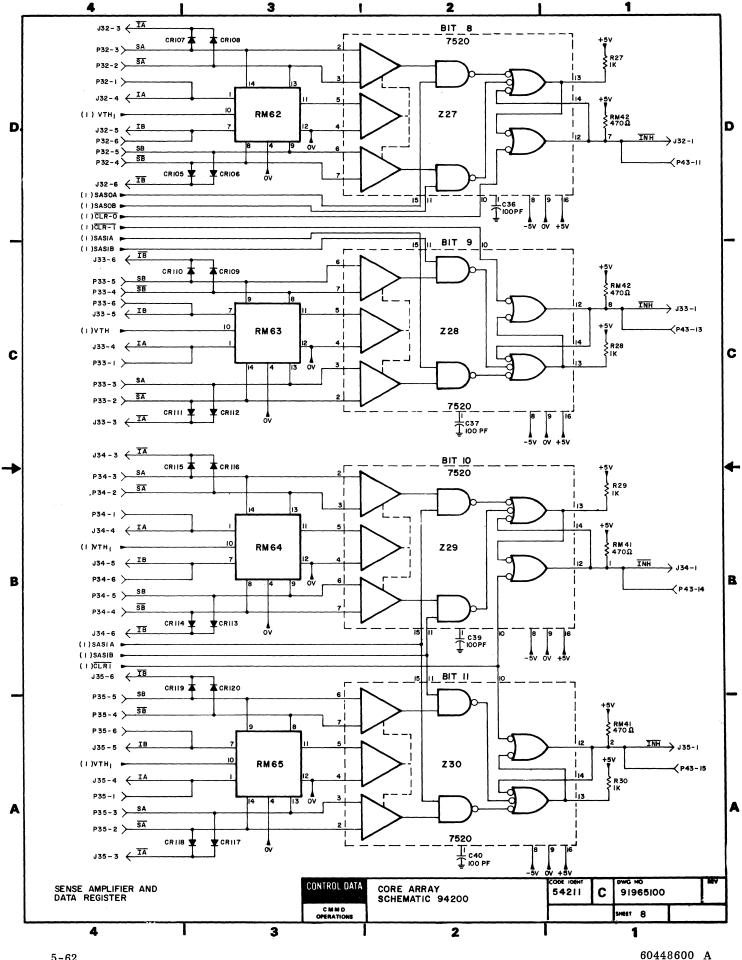


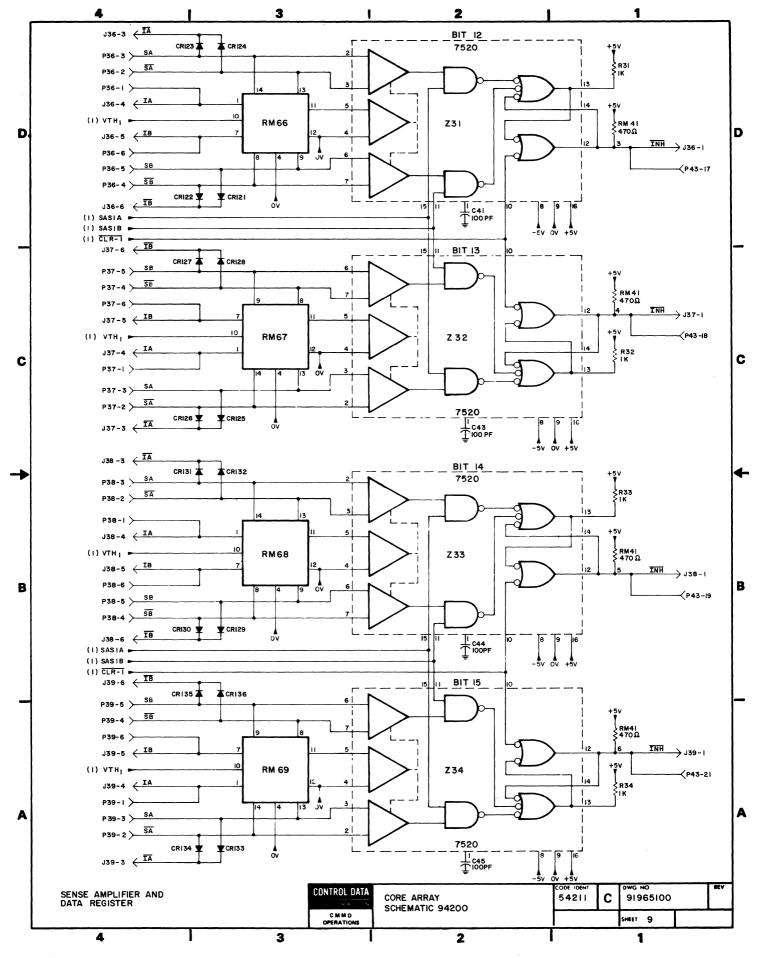


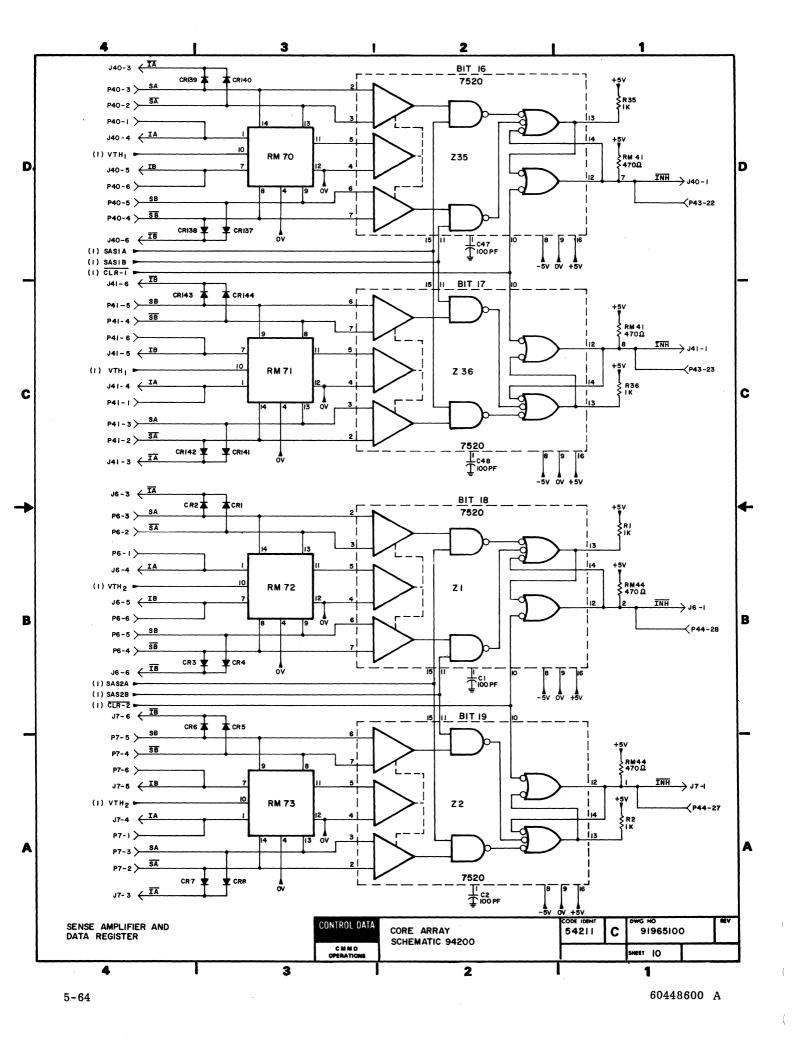


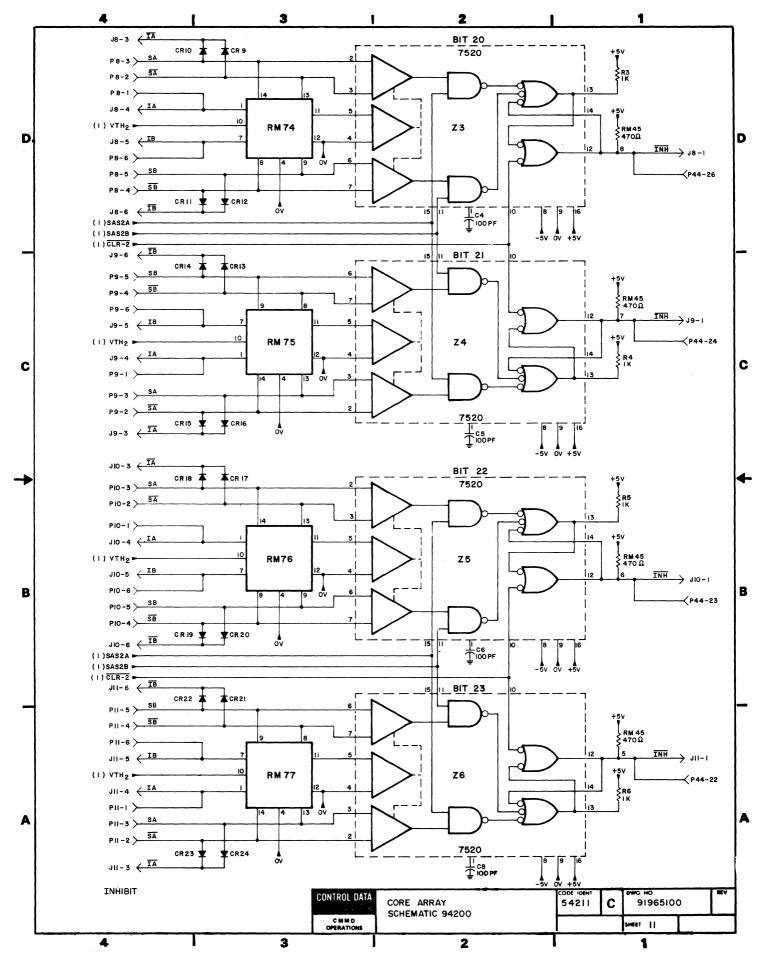


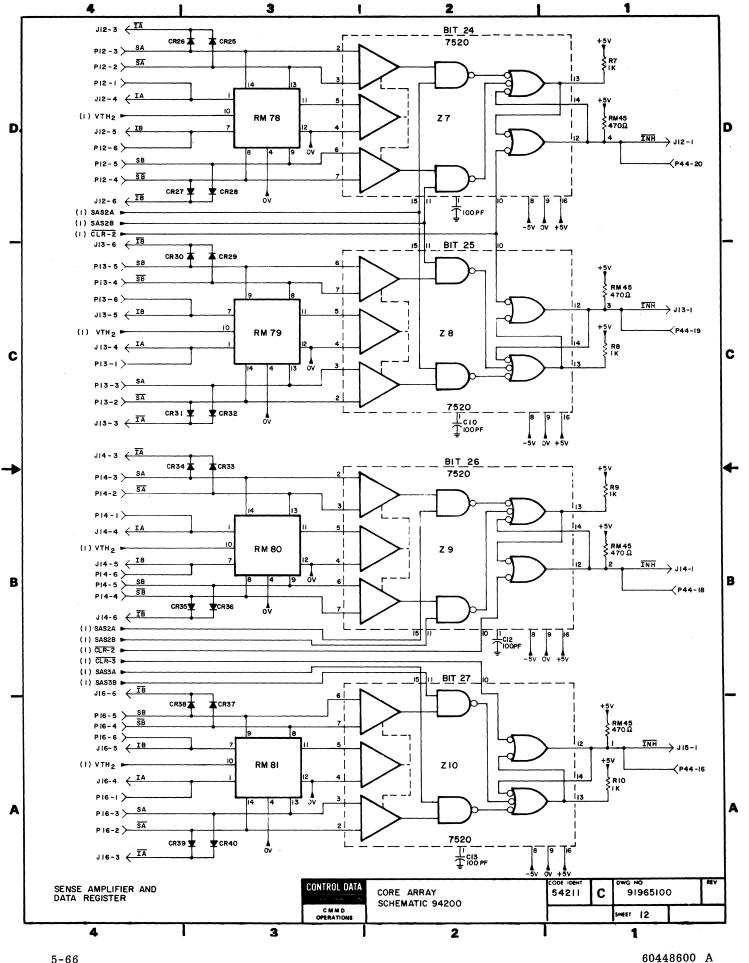


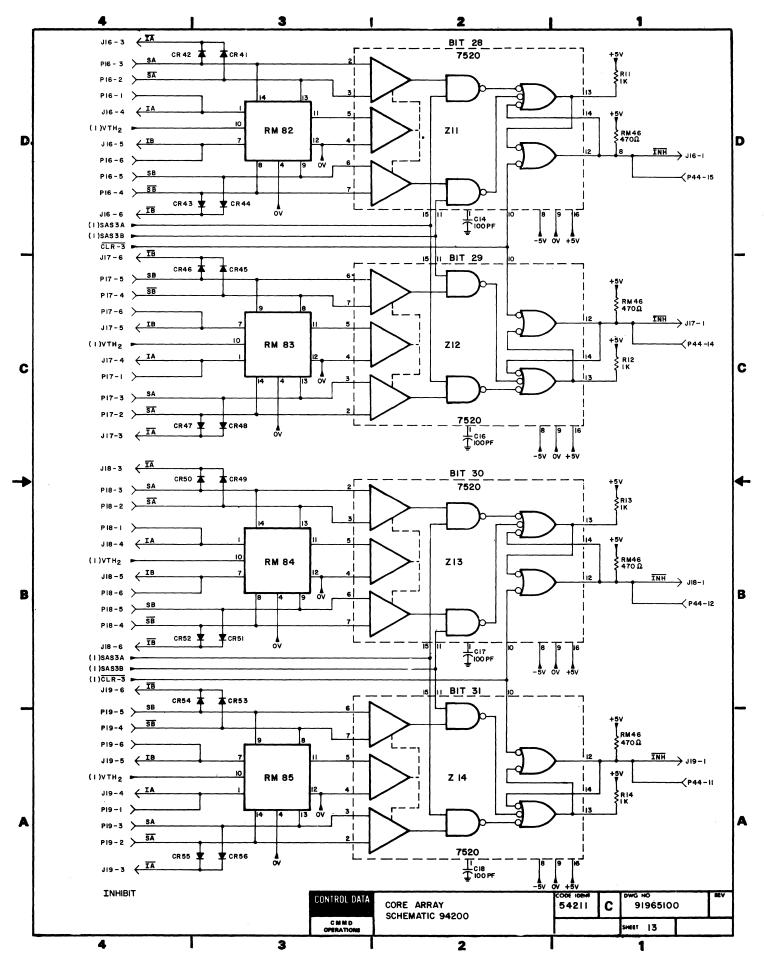


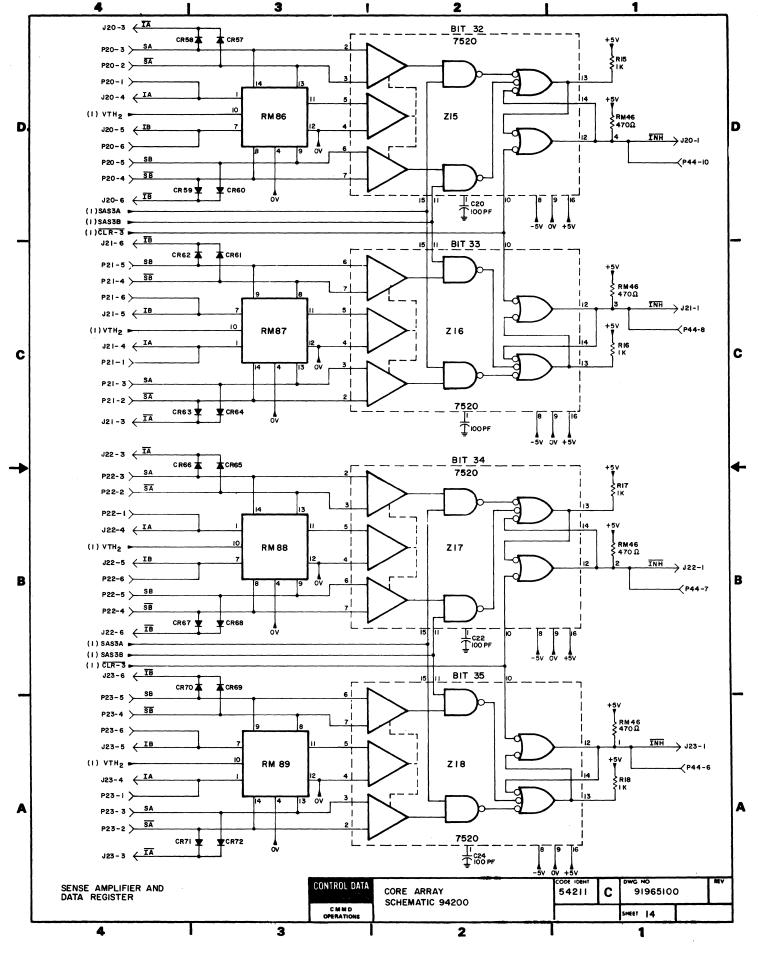


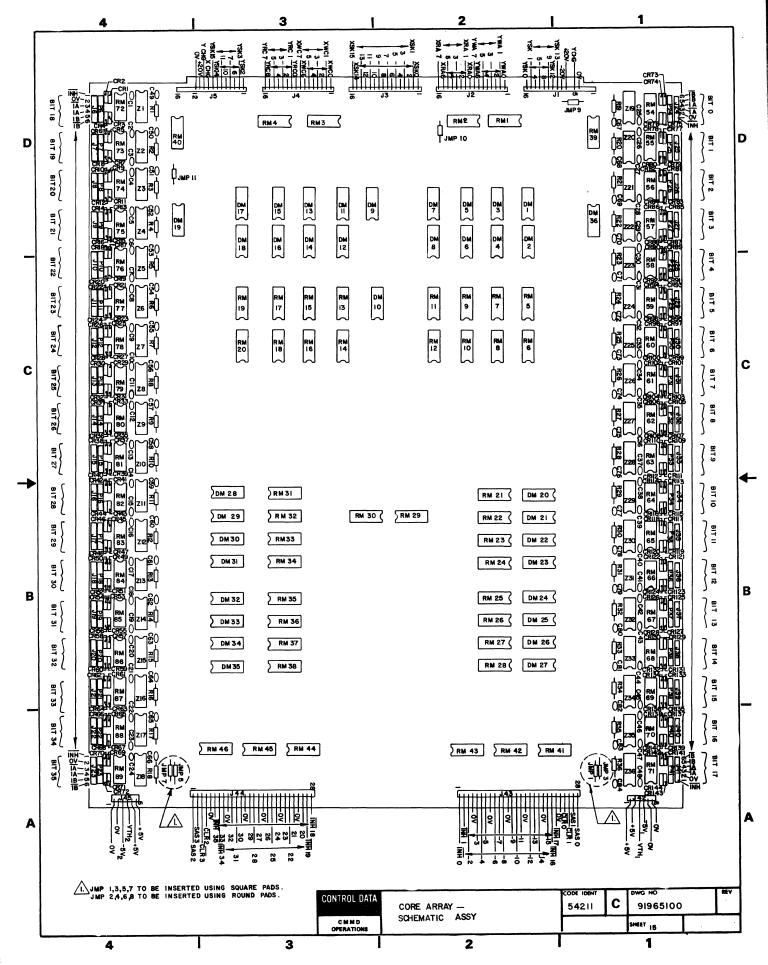












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				36 BIT						۳ .	of	Ь	<u> </u>	82842	F00	05
FIND	PART			QU.	ANTITY R	EQUIRED				UNIT		NOM	ENCLATU	IRE	SPECIFICAT	IONS,
NO.	IDENTIFICATION	00	נס							MEAS		OR D	ESCRIPT	ION	NOTES, OR MA	TERIAL
ı.	82842700	1										MEMORY EL BCP DETAI		NICZ BD.		
	000.000		-		1			1				HEADER - S		НT	<u> </u>	
2	82797000	2	2									1-28, "BE	RG" L	5274-3		
3	82813400	308	308									RECEPTACL				
								I				EJECTOR				
4	85856600	2	2		+-+							"SCANBE" WIRE, 28			<u> </u>	
5	18653610	A/R	A/R									TEFLON ST) WHITE		
Ь																
7	82843000		_									MEMORY EL SCHEMATIO		NICZ BD.		
												LBE47NZ			Z40-41-44-4	5-50-51
8	P5037500	50	50					 				INTERGRAT	ED CI	RCUIT	55,56,61,62	
															85,86,91,92 103,104	
_	5025W 00											SN74S00J			Z42,46,48,6	4,65,81
9	50254600	8	8		+-+			├──┼				INTERGRAT SN74504J	FD CTI	KCOTI	88,95 Z37,38,39,6	ו מים מוו
10	15109200	9	9				İ	1 1				INTERGRAT	ED CTE	CUTT	194,107,111	6103104
	1010100	† -			+-+							SN74SD5J	LV CII	(COI)	177101111	
11	15117100	3	3					1 1	l			INTERGRAT	ED CI	RCUIT	Z109-110-11	Ь
					T							LBOZPTNZ				
75	15150900	5	5		\perp							INTERGRAT	ED CIF	RCUIT	Z52-57-58-5	9,63
		١.			1 1	l			1			2N742101				
13	50254700	4	4		+-+							INTERGRAT	ED CI	RCUIT	<u> 253-82-87-1</u> 290-100	U2
1,4	15116400	2	2									SN74SllJ INTERGRAT	ED CTE	CUTT	עטערטו צ	
_ _		-	<u> </u>		+			 				ZN74ZZOJ	<u> </u>		<u> </u>	
15	50254900	3	3									INTERGRAT	ED CIR	RCUIT	Z93,96,101	
												L55247NZ		······································		
16	15127300	4	4		\bot							INTERGRAT	ED CIR	RCUIT	Z43-49-54-6	0
		_										SN74S40J		.		
17	50254800	3	3		+							INTERGRAT	ED CI	RCUIT	Z70 - 76 - 106	
1 n	15117000	_	2			1				1		SN82S41 INTERGRAT	בה כדי	PCUTT	Z99-105	
7.8	15117900	_2		 	++			 		+		INTERGRAT	EN CTL	COTI	L 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1	
19	15109700	ı	ı									INTERGRAT	ED CI	RCUIT	Z 8 9	

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		ARD M 1	COMP	THEND	ASSEM	IBLY				SHE	ET č	of	Ь	PL	828421	P00	02
FIND NO.	PART IDENTIFICATION				QUANTITY		RED	T			UNIT OF MEAS			ENCLATU		SPECIFICA NOTES, OR M	
NO.	IDENTIFICATION	00	01								MEAS			ESCRIFI	ON	NOTES, OR MA	
20	17186100	8	8										SN74145J INTERGRAT		RCUIT	Z117 - 124	
57	15117400	7	7										SN74S157J INTERGRAT		RCUIT	Z47-67-68-6 73-74-75	.9
22	15138800	4	4										SN74S174J INTERGRAT		RCUIT	 Z71, 72, 71	7, 78
23	15113000	41	41										SN75452 INTERGRAT	ED CIF		Z1-36	
24	82801100	16	16										420-9031 OTZIZNAST			QMI-16	
25	82796700	2	2										610-9035 INDUCTOR	TMI		L1,2	
2F	82796600	2	2										500-9084 MRORZNART	ER TI	11	T68,80	
27	95907500	70	70										500-1031 TRANSFORM	ER TI	II	T1-5-12-19- 44-51-58	26,33,37
28	82796500												500-1033 MRORZNART		NI	72-6-9-13-1 27-30-34-38	
																48,52,55,5° 67,69,70,78	1,62,66,
													11.			81-88	
29	82796400	38	38										500-1093 M9 <u>072NA9T</u>	ER TI	II	T3-4-7-8-10 15-17-18-21	,,22,24,
																25,28,29,31 36,39,40,42	1431461
																47-49-50-53 57-60-61-63	
																71	
30	82830900	ı	l.									1	PECOPOCA DELAY LIN	E TM3		DLl	
37	82788000	1.5	1.5										SAPENZ OTZIZNART	R		137,128,13	1
32	82787900	119	119									- [2N3725 OTZIZNANT	R		#1-108,122- 131,139,140	1
33	82808300	25	25										PJESNS OTZIZNANT	R		@119-120-12 @134-@141-1	

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CON	RUL DATA	EMORY ELECTRONICS OARD COMPONENT ASSEMBLY EM 16K x 36 BIT QUANTITY REQUIR				C	ODE IDENT	 ет 3	o f	Ь	PL	DOCUMENT N		D2	
FIND NO.	PART IDENTIFICATION	00	01	QU	ANTITY	REQUIR	RED		 UNIT OF MEAS		1	ENCLATU ESCRIPTI		SPECIFICA NOTES, OR MA	· · · · · · · · · · · · · · · · · · ·
34	50240106	1	1								IN751A DIODE ZEI	NER 5.	ΓΛ	CR438	
35	50240108	2	2						 		SENI SENI	NER L.	2 V	CR295-437	
36	16797605	2	2								DIODE ZE		LV lW	CR439-440	1171
37	82788100	460	460						 		IN4607 N	Ul	NITRODE	CR1-294-29	
38	82797300	31	, ∃l,								CAPACITO	V 20%		703-770-55 703-770-55	7-44-68-
39	82799501	5	5								CAPACITO	00V 2	%	C10-C14	
40	24504353	27	<u>ē</u> ?								CAPACITO			69-72-90-9	3
41	24504383	42	42								LSuf 2		/ .	C6-15-17-1 61-67-73-8	· T -
42	24500001	3	3								RESISTOR	/4W 5	%	R251-252-2	53
43	24500025	7.0	70								RESISTOR		γ.	R111-114-1:	
-											RESISTOR			135-138 R147-148-1	uB 152
44	24500027	11	77						 		33 ~ 1.		%	154-246-25	0,258
45	24500029	36	36								RESISTOR	/4W 5	/.	R1,4,7,10, 22,25,28,3 40,43,45,3	1,34,37, 9,52,55,
														58,61,64,6 76,79,82,8 94,97,100,	5-88-91
46	24500033	75	75								RESISTOR	/4 W 5	%	R181-184-10	
47	24500035				4						RESISTOR	/4W 5	γ.	R185-1	
48	24500039	7	7								RESISTOR	/40/ 5	% .	R141,207,21 210, R262,	
49	24500045	J	<u>ا</u> ا						 		RESISTOR		%	R146-R244	
50	24500047	3	3								RESISTOR		%	R155-286-2	95

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CONT	NUL DATA BO	ARD	COMP	CTRON PONENT 36 BI	AZZE	MBLY		CODE IDE	EN I	SHEE	ΕT	4 of	. P	PL	DOCUMENT NO		REV.
IND NO.	PART IDENTIFICATION				TITMAU	Y REQU	IRED	Γ		·	UNIT OF MEAS			MENCLATI DESCRIPT		SPECIFICA NOTES, OR MA	-
51	24500051	7P 00	7P 07										NOTZIZ3N L DEE	/4 W 5	i%	R109,112,1 121,124,12 136,150,15	7-130-13
52													RESISTOR			289,293 R110,113,1	71 770
53	24500055	23	23			-				-				/4W 5	i2	122, 125,1 134,137,16 165,168,17	28,131, 0,161,
_													RESISTOR			269,270,27 267,291 R139,140,1	7,280,28
54	24500063	70	סנ	_		+	-							/4W 5	iz.	163-166-16	
55	24500069	. 2	_ 2		-	+			+	-+			RESISTOR		i%	R143-R159 R145-151-1	
5Ь	24500071	75	75			-				+			2.2K 1	/40/ 5	i Z	164,169,17 263-265,26	
57	24500079	73											RESISTOR 4.7K 1	/4W 5	i%	R2-3-4-6-8 14-15-17-1 24-26-27-2	8,20,21.
																35:36:38:3 44:45:47:4 53:54:56:5	8,50,51, 7,59,60,
_				_		-	-									62-63-65-6 71-72-74-7 80-81-83-8	5
																89,90,92,9 98,99,101, 105,107,10	102-104.
58													RESISTOR				
59	24500083	ı	ľ			-	ļ						F-9K 7	/4W 5	ሂ	R281	
	24500139	2	2			-							RESISTOR 100 1 RESISTOR	/2W 5	iz.	R146, R294	
L 7.	24500147	ا ج	-							1					i%	R179-180	

CONT		AKD	COMP	CTRONIC A TNBNO B BIT	ZZEME	BLY	CODE	IDENT	SHE	ET	5 of	Ь	PL	DOCUMENT N		REV.
FIND NO.	PART IDENTIFICATION			QU.	ANTITY	REQUIRE	D	1		UNIT OF MEAS			ENCLATU		SPECIFICATION NOTES, OR MA	•
		00	01													
P5	24500150	ĉ	2								1		r/5M	5%	R205120L	
63	24500159	2	2										L/2W	5%	R241-245	
64	24500163	ŀ	7										r\5M	5%	R255	· · · · · · · · · · · · · · · · · · ·
Ь5	24500165	<u>l</u>	<u>ı</u>										L/2W	5%	R254	
66	24500171	4	4		-							RESISTOR E•2K RESISTOR	r\5M	5%	R177-178-18	7-188
Ь7	68583315	2	2									RESISTOR RESISTOR	L/BW	1%	R201-202	
68	<u>68583384</u>	2	<u> </u>									RESISTOR RESISTOR	L/8W	1%	R259,260	
69	68583329 68583329	_1	7		-								L/BW	1%	RZLL	
70	<u> 68583344</u>	1_	1		 			-					L/8W	1%	RZ85	
71	6858335Z		_3_		-							L.ELK] RESISTOR	L/8W	1%	R278-288-29	12
72	68583358 68583358	_1						-				RESISTOR RESISTOR	L/8W	1%	R283	
73	82831003		7		-		·	-				RESISTOR	3М	1%	RZSL	
74	85831051	<u>l</u>	<u>l</u>		 							L2 RESISTOR	3₩	1%	R257	
75	82831019	Ь	Ь					-				38	5W	3%	R271-276	
76	82799400	_1	<u> </u>					-				POTENTION RESISTOR	TETER	500	RZEE	
77	24500133	4	4				-						L/2W	5%	R197,198,19	
78	91938428	-	15						·			RESISTOR	MODUL	E 470	15-17-19-21 27-29	11231251
79	91938426	-	15									RESISTOR	MODUL	E 390	RM-2-4-6-8- 14-16-18-20 26-28-30	

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FIND NO.	PART IDENTIFICATION	00	01		QUA	NTITY	REQUI	UNIT OF MEAS						I	ENCLATU DESCRIPTI		SPECIFICATIONS, NOTES, OR MATERIAL	
80	23235200	25												TRANSIST	OR PAD	TO-18		
81	82815600	134	134											TRANSIST	OR PAD	T0-5		
82	91921500	8	8											CIRCUIT	JUMPER		JM-1-8	
å3	82800700	r	ı											THERMIST	ER 100	25°C	RT-1	
84	91931601	l	l											ZWITCH 4	TIZOG	ION	ZM-J	
85	91931701	ı	ı											COVER RECEPTACI	F MAD	דד ת	FOR SW-1	
86	82813401	2	2											"AMP INC	" 858L	5-2LP	TP-1, TP-2	
87		2	2														R179, R184	
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FIND NO.	PART IDENTIFICATION			QU	ANTITY	REQUIF	RED		T		OF MEAS			ENCLATU ESCRIPT		SPECIFICA NOTES, OR MA	
7	82792200	ŀ											PCB DETA	IL			
5	24500063	36											RESISTOR	1. OK	i		
3	82797200	36			-								CAPACITO	R 100F		27-29-31-3	2-24-25
4	82797300	48											CAPACITO	R Oluf	50V 20%	39-41,43-4 (3,7,11,15 30,34,38,4	1-19-23-26.
5	82780802	36											DIODE MO	DULES		DW7-3P	
Ь	82796300	32											RESISTOR	MODUL	.LEE 23.	RM5-28-31-	-38
7	82780700	14			-								RESISTOR	MODUL	.ES 470 -AL	RM1-4-29-3	10 - 39-46
8	82788100	144							_	_			DIODE I	N4607		CR1-144	
9	82834300	36							-				RECEPTAC HEADER	STRAIC			
75	82797000	9 56											1-28 BER RECEPTAC AMPING 8	LE MOI	DII		
16	82795500	REF			-				_	_			CORE ARR	AY TES	ST SPEC		
19	15127500	36			-	-							INTEGRAT	ED CIF	RCUIT	Z1-Z3F	
20	82800900	36			-								RESISTOR	NETWO	RK	RM54-89	
55	82795400	l.			-								TARTZBUZ	Ε			
23	82795200	J.											CORE COV	ER			
24	82795300	REF											WIRING D	IAGRAN	1		
25	91965100	REF											SCHEMATI	:c			
27	24524418	<u> </u>											MAG WIRE	•			

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CONT	ONTROL DATA CORE ARRAY BOARD COMPONENT ASSEMBLY OFM 16K X 36								CODE IDENT			EET	2 OF	F2 PL		DOCUMENT NO. 82791402		REV.
FIND NO.	PART IDENTIFICATION	QUANTITY REQUI			RED				UNIT OF MEAS		NOMENCLATURE OR DESCRIPTION		SPECIFICATIONS, NOTES, OR MATERIAL					
28	82822400	589,	824											CORE 750-LAMTA				
29	24524420	_												MAG WIRE	•			
30	24524441	-												MAG WIRE	•			Alle Marie and the second of the second of
31	24524417	- -												MAG WIRE	•			
32	7944050P	-												A DHESIVE	•			
33	82785000	-												WAX F-1	15			
35	82834400	10												SCREW NY	LON			
36	82834200	59												TERMINAL	•			
37	82807200	14					ļ							STAND OF	<u>F</u>			
ae	82807300	75						,						STAND OF	F -12!	iLG		
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																		<u> </u>
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Mnemonic	Description
AD00-17	Address inputs 00 through 17
B0-B3	Byte inputs 0 through 3
B Hold	Byte hold
BCT	Byte control timing
CI	Cycle initiate
CLR 0-3	Clear 0 through 3
CPM	Clock pulses for memory
DA	Data available
DI 00-36	Data in 00 through 36
DIT	Data in timing
DO 00-36	Data out 00 through 36
DOT	Data out timing
DOS 0-3	Data out strobe
DS	Data save
EC	End of cycle
ER	End of read
INH 1-4	Inhibit timing 1 through 4
INHR	Inhibit rise time
LDT	Late data in timing
MA 00-17	Memory address 00 through 17
MB	Memory busy
MB 0-3	Memory byte 0 through 3
MRMW	Memory read modify write
MWW	Memory word write
QT 1-24	Q clock timing 1 through 24
RCLR	Read clear
RMW	Read modify write
RST	Read start time
SAS 0-3	Sense amplifier strobe 0 through 3
V-TH	Voltage threshold
WCLR	Write clear
WDT	Write data timing
WE 0-3	Write enable 0 through 3
WI	Write initiate
WINH	Write inhibit
WST	Write start time
WW	Word write
XRC	X read current
XRDT	X read timing
XWC	X write current
XSKT	X sink timing
YRC	Y read current
YRDT	Y read timing
YWC	Y write current
YSKT	Y sink timing

60448600 A A-1

	Con	nector J46		Connector J47					
Pin No.	Signal	Pin No.	Signal	Pin No.	Signal	Pin No.	Signal		
1	+5	41	0V	1	+15	41	0V		
2	+5V	42	0V	2	+15V	42	0V		
3	+5	43	DI25	3	0V	43	D006		
4	+5	44	D025	4	0V	44	DI06		
5	Reset	45	$\overline{ ext{WI}}$	5	AD05	45	DI11		
6	$\overline{ ext{LDT}}$	46	$\overline{\text{CI}}$	6	AD09	46	D011		
7	-15V	47	DI22	7	AD10	47	ov		
8	-15V	48	D022	8	AD06	48	ov		
9	+15	49	0V	9	AD11	49	DI10		
10	+15	50	ov	10	AD08	50	D010		
11†		51	DI23	11	AD07	51	DI13		
12†		52	D023	12	AD04	52	D013		
13	D026	53	DI20	13	AD02	53	\mathbf{ov}		
14	D126	54	D020	14	AD01	54	ov		
15	D035	55	D018	15	AD03	55	DI12		
16	DI35	5 6	DI18	16	AD00	5 6	D012		
17	0V	57	D019	17	$\overline{ ext{CD0}}$	57	D014		
18	0V	58	DI19	18	$\overline{ ext{ER}}$	58	16K/32K† 1		
19	DI34	59	DI24	19	ov	59	DI14		
20	D034	60	D024	20	0V	60	0V		
21	D033	61	DI21	21	D100	61	D015		
22	DI33	62	D021	22	D000	62	DI15		
23	0 V	63	EC	23	DI01	63	D016		
24	0V	64	$\frac{\overline{DA}}{\overline{DA}}$	24	D001	64	DI16		
25	D032	65	B0	25	D002	65	0V		
26	DI32	66	$\frac{\mathbf{B}}{\mathbf{B}}$	26	DI02	66	0V		
27	D030	67	AD16	27	D007	67	D017		
28	DI30	68	$\overline{\mathrm{B2}}$	28	DI07	68	DI17		
29	0V	69	AD12	29	D109	69	Spare		
30	0V	70	$\overline{\mathbf{w}}$	30	D009	70	Spare		
31	DI31	71	AD13	31	DI03	71	+15V		
32	D031	72	AD15	32	D003	72	+15V		
33	D029	73	$\overline{\mathrm{B1}}$	33	DI05	73	-15V		
34	DI29	74	AD14	34	D005	74	-15V		
35	0V	75	AD17	35	0V	75	Data Save		
36	0V	76	B3	36	0V	76	Spare		
37	D028	77	BCT†††	37	DI04	77	+5V		
38	DI28	78	$\frac{201}{\text{RMW}}$	38	D004	78	+5V		
39	D027	79	-15	39	DI08	79	+5V		
40	DI27	80	-15	40	D008	80	+5		

[†]Used if external current control desired.

††Pin is open for 16K by 36 bit operation, wired to ground for 32K by 18 bit operation.

††Pin is open for BCT at WI time in RMW mode, wired to ground for BWT at t₀ in RMW mode.

Refer to byte control timing in text.

COMMENT SHEET

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